A Complete Bibliography of Publications in *Technometrics* for the decade 1970–1979

Nelson H. F. Beebe
University of Utah
Department of Mathematics, 110 LCB
155 S 1400 E RM 233
Salt Lake City, UT 84112-0090
USA

Tel: +1 801 581 5254
FAX: +1 801 581 4148

E-mail: `beebe@math.utah.edu`, `beebe@acm.org`,
`beebe@computer.org` (Internet)
WWW URL: `https://www.math.utah.edu/~beebe/`

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0.5 [Lad77]. 18 [Joh73a]. 2 [BN72]. 2^m [SC71]. 2^n [Joh79]. 2^{n-k} [Joh79]. 2×2 [MDM77]. 3 [Lin79]. 3^n [Hok74]. ^{4} [Dic74]. ^{5} [Dic74]. ^{n} [TW70]. A [Bad70, Bor72]. α [AS73, McC78a]. $A \subset B$ [Bad70, Bor72]. B [Bad70, Bor72]. β [AS73, GPU76]. C_P [Mal73, Ano73i, Ken71]. D [GK77a, Luc78, Mit74a, Mit74b, MB78a, MB78b, NGM70, SD75]. F [DW72, DW73, HH77, J.79u, Joh73b, Obe77, Pap72, PW72, HB71]. k [HP73, Ode71, WK71, Zei73]. $\log Y$ [Scl72]. m [FM77, HP73]. $m \leq 6$ [SC71]. N [Shu71, Gre70b, Sap73]. $n = 92$ [Wat70a]. O [MHL74]. p [Dun78a, FM77, For72, Lad77, MC72]. $P(Y < X)$ [KKS76]. $P[Y < X]$ [WK77]. $\Pr(Y < X)$ [Dow73]. $\Pr\{Y < X\}$ [JTS75, Ton74, Ton75]. R^2 [DH74]. s [Bha73, Lik74]. s^n [AT79]. σ^2 [JMM78]. t [AS73, KP79, Ros75c, SI70, TC72, YM74]. T^2 [BJN71]. T_M^2 [JH79]. V [SC71]. W [GH79, HH73, HL76, Ste78, Tho75]. X [Scl72]. Y [Scl72]. $|X'X|$ [Ano71a, Ano72e, Ano73h, BD71, Dyk71, Eva79].

References

Alldredge:1974:MLE

[AA74] J. Richard Alldredge and David W. Armstrong. Maximum likelihood estimation for the multinomial distribution using geometric progamming. *Technometrics*, 16(4):585–587, November 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267611`.

Al-Bayyati:1971:RTD

[AB71] H. A. Al-Bayyati. A rule of thumb for determining a sample size in comparing two proportions. *Technometrics*, 13(3):675–677, August 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267178`.

Anderssen:1974:TSA

[AB74] R. S. Anderssen and Peter Bloomfield. A time series approach to numerical differentiation. *Technometrics*, 16(1):69–75, February 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267494`.

Abraham:1979:SIF

[AB79] Bovas Abraham and George E. P. Box. Sampling interval and feedback control. *Technometrics*, 21(1):1–8, February 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268575`.

Al-Bayyati:1972:DSE

[ABA72] H. A. Al-Bayyati and J. C. Arnold. On double-stage estimation in simple linear regression using prior knowledge. *Technometrics*, 14(2):405–414, May 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267431`.

Addelman:1972:BRB

[Add72] Sidney Addelman. Book review: *Statistical Design and Analysis of Experiments* by Peter W. M. John. *Technometrics*, 14(1):234–235,

February 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266937`.

Addelman:1979:BRB

[Add79] Sidney Addelman. Book review: *Statistics for Experimenters* by G. E. P. Box; W. G. Hunter; J. S. Hunter. *Technometrics*, 21(3):387–388, August 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267766`.

Armstrong:1976:BBS

[AF76] R. D. Armstrong and E. L. Frome. A branch-and-bound solution of a restricted least squares problem. *Technometrics*, 18(4):447–450, November 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268660`.

Aitkin:1974:SIC

[Ait74] Murray A. Aitkin. Simultaneous inference and the choice of variable subsets in multiple regression. *Technometrics*, 16(2):221–227, May 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267942`.

Ashour:1977:SCI

[AJ77] S. K. Ashour and P. W. Jones. Shortest confidence intervals for the shape parameter of a Weibull distribution based on two adjacent failure times. *Technometrics*, 19(2):201–203, May 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268630`.

Antle:1971:NCM

[AK71] Charles E. Antle and Lawrence A. Klimko. A note on a conjecture of Mantel concerning quadratic programming. *Technometrics*, 13(2):425–427, May 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266803`.

Alam:1971:SMP

[Ala71] Khursheed Alam. On selecting the most probable category. *Technometrics*, 13(4):843–850, November 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266959`.

AGC:1972:AR

[Ale72] Alexander Grant & Co. Auditors' report. *Technometrics*, 14(2):??, May 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267446`.

Allen:1971:MSE

[All71] David M. Allen. Mean square error of prediction as a criterion for selecting variables. *Technometrics*, 13(3):469–475, August 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267161`.

Allen:1974:RBV

[All74] David M. Allen. The relationship between variable selection and data augmentation and a method for prediction. *Technometrics*, 16(1):125–127, February 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267500`.

Angers:1979:NPI

[AM79] Claude Angers and Georges McLaughlin. A note on prediction intervals for large future samples. *Technometrics*, 21(3):383–385, August 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267765`.

Anderson:1970:BRB

[And70] Virgil L. Anderson. Book review: *Evolutionary Operation: A Method for Increasing Industrial Productivity* by George E. P. Box; Norman R. Draper. *Technometrics*, 12(1):172–173, February 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267365`.

Andrew:1973:SEI

[And73] A. L. Andrew. Solution of equations involving centrosymmetric matrices. *Technometrics*, 15(2):405–407, May 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266998`.

Andrews:1974:RMM

[And74] D. F. Andrews. A robust method for multiple linear regression. *Technometrics*, 16(4):523–531, November 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267603`.

Andrew:1975:BRB

[And75] A. L. Andrew. Book review: *Two-Point Boundary Value Problems: Shooting Methods* by Sanford M. Roberts; Jerome S. Shipman. *Technometrics*, 17(2):277–278, May 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268370`.

Anderson:1976:LE

[And76] O. D. Anderson. Letter to the Editor. *Technometrics*, 18(2):245, May 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267541`. See errata [Ano77f].

Anderson:1977:LE

[And77] O. D. Anderson. Letter to the Editor. *Technometrics*, 19(2):223, May 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268645`.

Angers:1974:GME

[Ang74] Claude Angers. A graphical method to evaluate sample sizes for the multinomial distribution. *Technometrics*, 16(3):469–471, August 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267680`.

Anonymous:1970:APP

[Ano70a] Anonymous. Abstracts of papers presented at SPES Session of the 129th Annual Meeting of the American Statistical Association. *Technometrics*, 12(1):191–206, February 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267376`.

Anonymous:1970:BMa

[Ano70b] Anonymous. Back matter. *Technometrics*, 12(1):??, February 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267377`.

Anonymous:1970:BMb

[Ano70c] Anonymous. Back matter. *Technometrics*, 12(2):438, May 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267255`.

Anonymous:1970:BMc

[Ano70d] Anonymous. Back matter. *Technometrics*, 12(3):725–726, August 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267227`.

Anonymous:1970:BMd

[Ano70e] Anonymous. Back matter. *Technometrics*, 12(4):939–940, November 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267345`.

Anonymous:1970:EMH

[Ano70f] Anonymous. Errata to Margolin, Harter, Good, Hoerl and Sen. *Technometrics*, 12(3):721–724, August 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267226`. See [HK70a].

Anonymous:1970:FMa

[Ano70g] Anonymous. Front matter. *Technometrics*, 12(1):181–190, February 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267346`.

Anonymous:1970:FMb

[Ano70h] Anonymous. Front matter. *Technometrics*, 12(2):421–422, May 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267228`.

Anonymous:1970:FMc

[Ano70i] Anonymous. Front matter. *Technometrics*, 12(3):??, August 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267194`.

Anonymous:1970:FMd

[Ano70j] Anonymous. Front matter. *Technometrics*, 12(4):i–ii, November 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267317`.

Anonymous:1970:SNBa

[Ano70k] Anonymous. Summaries of new books. *Technometrics*, 12(1):183–186, February 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267374`.

Anonymous:1970:SNBb

[Ano70l] Anonymous. Summaries of new books. *Technometrics*, 12(2):427–431, May 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267252`.

Anonymous:1970:SNBc

[Ano70m] Anonymous. Summaries of new books. *Technometrics*, 12(3):715–718, August 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267224`.

Anonymous:1970:SNBd

[Ano70n] Anonymous. Summaries of new books. *Technometrics*, 12(4):933–936, November 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267343`.

Anonymous:1970:VI

[Ano70o] Anonymous. Volume information. *Technometrics*, 12(4):941–944, November 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267316`.

Anonymous:1971:AAE

[Ano71a] Anonymous. Addendum: The augmentation of experimental data to maximize $|X'X|$. *Technometrics*, 13(4):927, November 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266979`.

Anonymous:1971:BMa

[Ano71b] Anonymous. Back matter. *Technometrics*, 13(1):219–220, February 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267098`.

Anonymous:1971:BMb

[Ano71c] Anonymous. Back matter. *Technometrics*, 13(2):??, May 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266817`.

Anonymous:1971:BMc

[Ano71d] Anonymous. Back matter. *Technometrics*, 13(3):??, August 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267193`.

Anonymous:1971:BMd

[Ano71e] Anonymous. Back matter. *Technometrics*, 13(4):929–938, November 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266980`.

Anonymous:1971:BRB

[Ano71f] Anonymous. Book review: *Abridged Tables for Use of Examination Candidates* by The Institute of Statisticians. *Technometrics*, 13(1):213–214, February 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267095`.

Anonymous:1971:EKS

[Ano71g] Anonymous. Errata to Kumar and Schatzoff. *Technometrics*, 13(3):712, August 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267192`. See [KP71].

Anonymous:1971:FMa

[Ano71h] Anonymous. Front matter. *Technometrics*, 13(1):215, February 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267071`.

Anonymous:1971:FMb

[Ano71i] Anonymous. Front matter. *Technometrics*, 13(2):459–460, May 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266784`.

Anonymous:1971:FMc

[Ano71j] Anonymous. Front matter. *Technometrics*, 13(3):??, August 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267159`.

Anonymous:1971:FMd

[Ano71k] Anonymous. Front matter. *Technometrics*, 13(4):??, November 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266947`.

Anonymous:1971:VI

[Ano71l] Anonymous. Volume information. *Technometrics*, 13(4):933–937, November 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266946`.

Anonymous:1972:BMa

[Ano72a] Anonymous. Back matter. *Technometrics*, 14(1):246, February 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266945`.

Anonymous:1972:BMb

[Ano72b] Anonymous. Back matter. *Technometrics*, 14(2):??, May 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267447`.

Anonymous:1972:BMc

[Ano72c] Anonymous. Back matter. *Technometrics*, 14(3):811, August 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267315`.

Anonymous:1972:BMd

[Ano72d] Anonymous. Back matter. *Technometrics*, 14(4):988–990, November 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267158`.

Anonymous:1972:CFD

[Ano72e] Anonymous. Corrigendum: “Factorial Designs, the $|X'X|$ Criterion, and Some Related Matters”. *Technometrics*, 14(2):511, May 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267445`. See [BD71].

Anonymous:1972:CLF

[Ano72f] Anonymous. Corrigendum: “On Lack of Fit”. *Technometrics*, 14(1):245, February 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266944`. See [DH71].

Anonymous:1972:CDS

[Ano72g] Anonymous. Corrigendum: “On the Determination of Single Sampling Attribute Plans Based upon a Linear Cost Model and a Prior Distribution”. *Technometrics*, 14(4):987, November 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267157`. See [Gue71b].

Anonymous:1972:FMa

[Ano72h] Anonymous. Front matter. *Technometrics*, 14(1):239–240, February 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266912`.

Anonymous:1972:FMb

[Ano72i] Anonymous. Front matter. *Technometrics*, 14(2):509–510, May 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267417`.

Anonymous:1972:FMc

[Ano72j] Anonymous. Front matter. *Technometrics*, 14(3):??, August 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267280`.

Anonymous:1972:FMd

[Ano72k] Anonymous. Front matter. *Technometrics*, 14(4):??, November 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267130`.

Anonymous:1972:VI

[Ano72l] Anonymous. Volume information. *Technometrics*, 14(4):991–994, November 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267129`.

Anonymous:1973:ABR

[Ano73a] Anonymous. Annotated bibliography on robustness studies of statistical procedures. *Technometrics*, 15(2):424, May 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267008`.

Anonymous:1973:BMa

[Ano73b] Anonymous. Back matter. *Technometrics*, 15(1):??, February 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266848`.

Anonymous:1973:BMb

[Ano73c] Anonymous. Back matter. *Technometrics*, 15(2):433–436, May 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267015`.

Anonymous:1973:BMc

[Ano73d] Anonymous. Back matter. *Technometrics*, 15(3):658, August 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266882`.

Anonymous:1973:BMd

[Ano73e] Anonymous. Back matter. *Technometrics*, 15(4):953–960, November 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267416`.

Anonymous:1973:CSI

[Ano73f] Anonymous. Corrigenda: "Small Incomplete Factorial Experiment Designs for Two- and Three-Level Factors". *Technometrics*, 15(4):951, November 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267415`. See [Web71].

Anonymous:1973:CES

[Ano73g] Anonymous. Corrigendum: "Extension of Sample Sizes and Percentage Points for Significance Tests of Outlying Observations". *Technometrics*, 15(2):429, May 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267012`. See [GB72].

Anonymous:1973:CFD

[Ano73h] Anonymous. Corrigendum: "Factorial Designs, the $|X'X|$ Criterion and Some Related Matters". *Technometrics*, 15(2):430, May 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267013`. See [BD71].

Anonymous:1973:ENS

[Ano73i] Anonymous. Erratum: A note on the C_p statistic. *Technometrics*, 15(3):657, August 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266881`. See [Ken71].

Anonymous:1973:ESM

[Ano73j] Anonymous. Erratum: "A Stochastic Model of Microscale Air Pollution from Highway Traffic". *Technometrics*, 15(4):949, November 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267414`. See [Mar73].

Anonymous:1973:EML

[Ano73k] Anonymous. Erratum: "Maximum-Likelihood Estimation of the Parameters of Gamma and Weibull Populations from Complete and from Censored Samples". *Technometrics*, 15(2):431, May 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267014`. See [Coh65].

Anonymous:1973:FMa

[Ano73l] Anonymous. Front matter. *Technometrics*, 15(1):205–206, February 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266818`.

Anonymous:1973:FMb

[Ano73m] Anonymous. Front matter. *Technometrics*, 15(2):??, May 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266981`.

Anonymous:1973:FMc

[Ano73n] Anonymous. Front matter. *Technometrics*, 15(3):??, August 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266849`.

Anonymous:1973:FMd

[Ano73o] Anonymous. Front matter. *Technometrics*, 15(4):659, November 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267379`.

Anonymous:1973:VI

[Ano73p] Anonymous. Volume information. *Technometrics*, 15(4):955–959, November 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267378`.

Anonymous:1974:BMa

[Ano74a] Anonymous. Back matter. *Technometrics*, 16(1):143–144, February 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267514`.

Anonymous:1974:BMb

[Ano74b] Anonymous. Back matter. *Technometrics*, 16(2):??, May 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267967`.

Anonymous:1974:BMc

[Ano74c] Anonymous. Back matter. *Technometrics*, 16(3):??, August 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267690`.

Anonymous:1974:BMd

[Ano74d] Anonymous. Back matter. *Technometrics*, 16(4):643–648, November 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267630`.

Anonymous:1974:BRB

[Ano74e] Anonymous. Book review: *Cyclic Designs* by J. A. John; F. W. Wolock; H. A. David. *Technometrics*, 16(1):138, February 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267506`.

Anonymous:1974:CTS

[Ano74f] Anonymous. Corrigendum: "Testing for a Single Outlier in Simple Linear Regression". *Technometrics*, 16(2):331, May 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267965`. See [TMB73].

Anonymous:1974:FSA

[Ano74g] Anonymous. Financial statements and auditors' report. *Technometrics*, 16(2):??, May 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267966`.

Anonymous:1974:FMa

[Ano74h] Anonymous. Front matter. *Technometrics*, 16(1):??, February 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267484`.

Anonymous:1974:FMb

[Ano74i] Anonymous. Front matter. *Technometrics*, 16(2):333, May 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267934`.

Anonymous:1974:FMc

[Ano74j] Anonymous. Front matter. *Technometrics*, 16(3):??, August 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267662`.

Anonymous:1974:FMd

[Ano74k] Anonymous. Front matter. *Technometrics*, 16(4):??, November 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267598`.

Anonymous:1974:VI

[Ano74l] Anonymous. Volume information. *Technometrics*, 16(4):639–647, November 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267597`.

Anonymous:1975:BMa

[Ano75a] Anonymous. Back matter. *Technometrics*, 17(1):??, February 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268025`.

Anonymous:1975:BMb

[Ano75b] Anonymous. Back matter. *Technometrics*, 17(2):283–285, May 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268374`.

Anonymous:1975:BMc

[Ano75c] Anonymous. Back matter. *Technometrics*, 17(3):396, August 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268095`.

Anonymous:1975:BMd

[Ano75d] Anonymous. Back matter. *Technometrics*, 17(4):521, November 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268451`.

Anonymous:1975:CPP

[Ano75e] Anonymous. Corrigendum: "The Probability Plot Correlation Coefficient Test for Normality". *Technometrics*, 17(4):520, November 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268450`. See [Fil75].

Anonymous:1975:EHW

[Ano75f] Anonymous. Errata to Hamdan and Watts. *Technometrics*, 17 (1):147, February 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268024`. See [Ham74, WB74].

Anonymous:1975:FMa

[Ano75g] Anonymous. Front matter. *Technometrics*, 17(1):??, February 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267992`.

Anonymous:1975:FMb

[Ano75h] Anonymous. Front matter. *Technometrics*, 17(2):??, May 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268344`.

Anonymous:1975:FMc

[Ano75i] Anonymous. Front matter. *Technometrics*, 17(3):??, August 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268061`.

Anonymous:1975:FMd

[Ano75j] Anonymous. Front matter. *Technometrics*, 17(4):397–398, November 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268425`.

Anonymous:1975:PR

[Ano75k] Anonymous. Publications received. *Technometrics*, 17(4):516, November 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268448`.

Anonymous:1975:VI

[Ano75l] Anonymous. Volume information. *Technometrics*, 17(4):517–523, November 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268424`.

Anonymous:1975:VT

[Ano75m] Anonymous. A vote of thanks. *Technometrics*, 17(1):??, February 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267993`.

Anonymous:1976:BMa

[Ano76a] Anonymous. Back matter. *Technometrics*, 18(1):126, February 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267933`.

Anonymous:1976:BMb

[Ano76b] Anonymous. Back matter. *Technometrics*, 18(2):247–248, May 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267543`.

Anonymous:1976:BMc

[Ano76c] Anonymous. Back matter. *Technometrics*, 18(3):366, August 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268755`.

Anonymous:1976:BMd

[Ano76d] Anonymous. Back matter. *Technometrics*, 18(4):506, November 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268674`.

Anonymous:1976:EED

[Ano76e] Anonymous. Erratum: "Experimental Designs for Quadratic Models in Constrained Mixture Spaces". *Technometrics*, 18(2):246, May 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267542`. See [Sne75b].

Anonymous:1976:EPS

[Ano76f] Anonymous. Erratum: "Progress in Statistics". *Technometrics*, 18(3):364, August 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268753`. See [J75e].

Anonymous:1976:FMa

[Ano76g] Anonymous. Front matter. *Technometrics*, 18(1):??, February 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267909`.

Anonymous:1976:FMb

[Ano76h] Anonymous. Front matter. *Technometrics*, 18(2):??, May 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267515`.

Anonymous:1976:FMc

[Ano76i] Anonymous. Front matter. *Technometrics*, 18(3):??, August 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268733`.

Anonymous:1976:FMd

[Ano76j] Anonymous. Front matter. *Technometrics*, 18(4):369–370, November 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268649`.

Anonymous:1976:PRa

[Ano76k] Anonymous. Publications received. *Technometrics*, 18(1):122–123, February 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267930`.

Anonymous:1976:PRb

[Ano76l] Anonymous. Publications received. *Technometrics*, 18(2):244, May 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267540`.

Anonymous:1976:PRc

[Ano76m] Anonymous. Publications received. *Technometrics*, 18(3):364, August 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268752`.

Anonymous:1976:PRd

[Ano76n] Anonymous. Publications received. *Technometrics*, 18(4):503, November 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268672`.

Anonymous:1976:VI

[Ano76o] Anonymous. Volume information. *Technometrics*, 18(4):507–508, November 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268648`.

Anonymous:1977:ACO

[Ano77a] Anonymous. Addendum and corrigendum to Odoroff and Ehrenfeld. *Technometrics*, 19(4):520, November 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267905`. See [Odo77, Ehr77].

Anonymous:1977:BMa

[Ano77b] Anonymous. Back matter. *Technometrics*, 19(1):107–108, February 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268274`.

Anonymous:1977:BMb

[Ano77c] Anonymous. Back matter. *Technometrics*, 19(2):225–226, May 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268647`.

Anonymous:1977:BMc

[Ano77d] Anonymous. Back matter. *Technometrics*, 19(3):352, August 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267718`.

Anonymous:1977:BMd

[Ano77e] Anonymous. Back matter. *Technometrics*, 19(4):523–525, November 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267908`.

Anonymous:1977:ERA

[Ano77f] Anonymous. Errata to Roquemore and Anderson. *Technometrics*, 19(1):106, February 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268273`. See [Roq76, And76].

Anonymous:1977:ELE

[Ano77g] Anonymous. Erratum: Letter to the Editor. *Technometrics*, 19(4):522, November 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267907`.

Anonymous:1977:EOC

[Ano77h] Anonymous. Erratum: "Optimal Choice of the Sampling Interval for Discrete Process Control". *Technometrics*, 19(2):224, May 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268646`. See [Mac76].

Anonymous:1977:FMa

[Ano77i] Anonymous. Front matter. *Technometrics*, 19(1):??, February 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268247`.

Anonymous:1977:FMb

[Ano77j] Anonymous. Front matter. *Technometrics*, 19(2):??, May 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268619`.

Anonymous:1977:FMc

[Ano77k] Anonymous. Front matter. *Technometrics*, 19(3):??, August 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267691`.

Anonymous:1977:FMd

[Ano77l] Anonymous. Front matter. *Technometrics*, 19(4):??, November 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267875`.

Anonymous:1977:PRa

[Ano77m] Anonymous. Publications received. *Technometrics*, 19(1):104, February 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268271`.

Anonymous:1977:PRb

[Ano77n] Anonymous. Publications received. *Technometrics*, 19(2):221, May 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268643`.

Anonymous:1977:PRc

[Ano77o] Anonymous. Publications received. *Technometrics*, 19(3):347, August 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267716`.

Anonymous:1977:PRd

[Ano77p] Anonymous. Publications received. *Technometrics*, 19(4):520–521, November 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267906`.

Anonymous:1977:VI

[Ano77q] Anonymous. Volume information. *Technometrics*, 19(4):526–527, November 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267874`.

Anonymous:1978:BMa

[Ano78a] Anonymous. Back matter. *Technometrics*, 20(1):108, February 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268177`.

Anonymous:1978:BMb

[Ano78b] Anonymous. Back matter. *Technometrics*, 20(2):220, May 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268732`.

Anonymous:1978:BMc

[Ano78c] Anonymous. Back matter. *Technometrics*, 20(3):??, August 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268151`.

Anonymous:1978:BMd

[Ano78d] Anonymous. Back matter. *Technometrics*, 20(4):505, November 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267661`.

Anonymous:1978:EWB

[Ano78e] Anonymous. Errata to Wolfe, Bose and Bradu. *Technometrics*, 20(2): 219, May 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268731`. See [Wol77a, BCK61, BG78].

Anonymous:1978:FMa

[Ano78f] Anonymous. Front matter. *Technometrics*, 20(1):??, February 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268152`.

Anonymous:1978:FMb

[Ano78g] Anonymous. Front matter. *Technometrics*, 20(2):i–iii, May 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268700`.

Anonymous:1978:FMc

[Ano78h] Anonymous. Front matter. *Technometrics*, 20(3):??, August 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268127`.

Anonymous:1978:FMd

[Ano78i] Anonymous. Front matter. *Technometrics*, 20(4):353–354, November 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267632`.

Anonymous:1978:FMe

[Ano78j] Anonymous. Front matter. *Technometrics*, 20(4):??, November 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267570`.

Anonymous:1978:PRa

[Ano78k] Anonymous. Publications received. *Technometrics*, 20(1):107, February 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268176`.

Anonymous:1978:PRb

[Ano78l] Anonymous. Publications received. *Technometrics*, 20(2):217, May 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268729`.

Anonymous:1978:PRc

[Ano78m] Anonymous. Publications received. *Technometrics*, 20(3):323, August 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268150`.

Anonymous:1978:PRd

[Ano78n] Anonymous. Publications received. *Technometrics*, 20(4):504, November 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267660`.

Anonymous:1978:VIa

[Ano78o] Anonymous. Volume information. *Technometrics*, 20(4):506–508, November 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267631`.

Anonymous:1978:VIb

[Ano78p] Anonymous. Volume information. *Technometrics*, 20(4):509–629, November 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267569`.

Anonymous:1979:BMa

[Ano79a] Anonymous. Back matter. *Technometrics*, 21(1):140, February 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268601`.

Anonymous:1979:BMb

[Ano79b] Anonymous. Back matter. *Technometrics*, 21(2):276, May 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268538`.

Anonymous:1979:BMc

[Ano79c] Anonymous. Back matter. *Technometrics*, 21(3):??, August 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267782`.

Anonymous:1979:BMd

[Ano79d] Anonymous. Back matter. *Technometrics*, 21(4):588–594, November 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268311`.

Anonymous:1979:CMB

[Ano79e] Anonymous. Corrigenda to Muse and Bishop. *Technometrics*, 21(1):139, February 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268600`. See [MA78, Bis78].

Anonymous:1979:CSO

[Ano79f] Anonymous. Corrigenda to Sprott and Odoroff. *Technometrics*, 21 (2):275, May 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268537`. See [Spr78, Odo78].

Anonymous:1979:CSG

[Ano79g] Anonymous. Corrigendum: "Some Grubbs-Type Statistics for the Detection of Several Outliers". *Technometrics*, 21(3):396, August 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267781`. See [TM72].

Anonymous:1979:FMa

[Ano79h] Anonymous. Front matter. *Technometrics*, 21(1):??, February 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268574`.

Anonymous:1979:FMb

[Ano79i] Anonymous. Front matter. *Technometrics*, 21(2):??, May 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268510`.

Anonymous:1979:FMc

[Ano79j] Anonymous. Front matter. *Technometrics*, 21(3):??, August 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267747`.

Anonymous:1979:FMd

[Ano79k] Anonymous. Front matter. *Technometrics*, 21(4):i–vi, November 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268276`.

Anonymous:1979:PRa

[Ano79l] Anonymous. Publications received. *Technometrics*, 21(1):136–137, February 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268598`.

Anonymous:1979:PRb

[Ano79m] Anonymous. Publications received. *Technometrics*, 21(2):274, May 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268535`.

Anonymous:1979:PRc

[Ano79n] Anonymous. Publications received. *Technometrics*, 21(3):394, August 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267779`.

Anonymous:1979:PRd

[Ano79o] Anonymous. Publications received. *Technometrics*, 21(4):586, November 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268309`.

Anonymous:1979:VI

[Ano79p] Anonymous. Volume information. *Technometrics*, 21(4):590–593, November 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268275`.

Anonymous:1980:CGJ

[Ano80a] Anonymous. Corrigenda to Gabriel, Jackson and Davis. *Technometrics*, 22(1):136, February 1980. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268407`. See [GZ79, Jac80, Dav79b].

Anonymous:1980:CLW

[Ano80b] Anonymous. Corrigenda to Leone, White, Narula and Narula. *Technometrics*, 22(3):452, August 1980. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268342`. See [LNN61, WG79].

Anonymous:1980:CNS

[Ano80c] Anonymous. Corrigendum: "Nonparametric Selection Procedures Applied to State Traffic Fatality Rates". *Technometrics*, 22(2):285, May 1980. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268482`. See [McD79].

Anonymous:1984:CUR

[Ano84] Anonymous. Corrigendum: "The Use of the Rank Transform in Regression". *Technometrics*, 26(4):419, November 1984. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1269514`. See [IC79].

Antle:1977:DED

[Ant77] Charles E. Antle. Discussion of: "Experimental Design for Sensitivity Testing: The Weibull Model". *Technometrics*, 19(4):413, November 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267880`. See [MHC77].

Azen:1973:MLE

[AR73] S. P. Azen and A. H. Reed. Maximum likelihood estimation of correlation between variates having equal coefficients of variation. *Technometrics*, 15(3):457–462, August 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266851`.

Anderson:1979:LDB

[AR79] J. A. Anderson and S. C. Richardson. Logistic discrimination and bias correction in maximum likelihood estimation. *Technomet-*

rics, 21(1):71–78, February 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268582`.

Aroian:1976:ADM

[Aro76] Leo A. Aroian. Applications of the direct method in sequential analysis. *Technometrics*, 18(3):301–306, August 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268739`.

Alexander:1973:TST

[AS73] Robert Alexander and Ronald Suich. A truncated sequential t-test for general α and β. *Technometrics*, 15(1):79–86, February 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266826`.

Alam:1973:PRE

[AT73] Khursheed Alam and James R. Thompson. A problem of ranking and estimation with Poisson processes. *Technometrics*, 15(4):801–808, November 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267390`.

Anderson:1979:NMR

[AT79] Donald A. Anderson and Ann M. Thomas. Near minimal resolution IV designs for the s^n factorial experiment. *Technometrics*, 21(3):331–336, August 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267755`.

Austin:1973:CCC

[Aus73] John A. Austin, Jr. Control chart constants for largest and smallest in sampling from a normal distribution using the generalized Burr distribution. *Technometrics*, 15(4):931–933, November 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267403`.

Adriaanse:1970:SRG

[AvdL70] R. P. Adriaanse and P. van der Laan. Some remarks on a general class of Markov processes with discrete time parameter and dependent increments. *Technometrics*, 12(4):851–866, November 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267330`.

Bobis:1970:AED

[BA70] A. H. Bobis and L. Bryce Andersen. An approach for economic discrimination between alternative chemical syntheses. *Technometrics*, 12(3):439–455, August 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267195`.

Billmann:1972:SIC

[BAB72] Barry R. Billmann, Charles E. Antle, and Lee J. Bain. Statistical inference from censored Weibull samples. *Technometrics*, 14 (4):831–840, November 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267132`.

Badenius:1970:QPW

[Bad70] Duncan Badenius. Query 3: In probability, why does $A \subset B$ mean, "A Implies B"? *Technometrics*, 12(3):707–708, August 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267218`.

Bagga:1970:SRS

[Bag70] P. C. Bagga. Sequencing with random service times. *Technometrics*, 12(2):327–334, May 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267237`.

Bain:1972:IBC

[Bai72] Lee J. Bain. Inferences based on censored sampling from the Weibull or extreme-value distribution. *Technometrics*, 14(3):693–702, August 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267297`.

Bain:1973:ROM

[Bai73] Lee J. Bain. Results for one or more independent censored samples from the Weibull or extreme-value distribution. *Technometrics*, 15(2):279–288, May 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266988`.

Bailey:1974:NUD

[Bai74a] William A. Bailey. A note on the use of discrete convolutions. *Technometrics*, 16(3):473–475, August 1974. CODEN TCMTA2. ISSN

0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267681`.

Bain:1974:ALF

[Bai74b] Lee J. Bain. Analysis for the linear failure-rate life-testing distribution. *Technometrics*, 16(4):551–559, November 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267607`.

Baker:1974:BRB

[Bak74] Charles R. Baker. Book review: *The Analysis of Feedback Systems* by Jan C. Willems. *Technometrics*, 16(1):141–142, February 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267511`.

Banerjee:1973:BRB

[Ban73] K. S. Banerjee. Book review: *Generalized Inverse of Matrices and Its Applications* by C. Radhakrishna Rao; Sujit Kumar Mitra. *Technometrics*, 15(1):197, February 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266840`.

Barnett:1972:BSL

[Bar72] V. D. Barnett. A Bayesian sequential life test. *Technometrics*, 14(2):453–468, May 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267435`.

Banerjee:1979:BRI

[BB79] Asit K. Banerjee and G. K. Bhattacharyya. Bayesian results for the inverse Gaussian distribution with an application. *Technometrics*, 21(2):247–251, May 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268523`.

Banerjee:1971:CRR

[BC71] K. S. Banerjee and R. N. Carr. A comment on ridge regression. Biased estimation for non-orthogonal problems. *Technometrics*, 13 (4):895–898, November 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266967`.

Beckman:1979:LE

[BC79a] R. J. Beckman and R. D. Cook. Letter to the Editor. *Technometrics*, 21(4):587, November 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268310`.

Beckman:1979:TTP

[BC79b] R. J. Beckman and R. D. Cook. Testing for two-phase regressions. *Technometrics*, 21(1):65–69, February 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268581`.

Bose:1961:MCS

[BCK61] R. C. Bose, I. M. Chakravarti, and D. E. Knuth. On methods of constructing sets of mutually orthogonal Latin squares using a computer. II. *Technometrics*, 3(1):111–117, February 1961. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266482`. See errata [Ano78e, BCK78].

Bose:1978:EMC

[BCK78] R. C. Bose, I. M. Chakravarti, and D. E. Knuth. Errata: "On methods of constructing sets of mutually orthogonal Latin squares using a computer. II" (Technometrics **3** (1961), 111–117). *Technometrics*, 20 (2):219, 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). See [BCK61].

Box:1971:FDC

[BD71] M. J. Box and N. R. Draper. Factorial designs, the $|X'X|$ criterion, and some related matters. *Technometrics*, 13(4):731–742, November 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266950`. See corrigenda [Ano72e, Ano73h].

Barham:1972:ALS

[BD72a] R. H. Barham and Wanzer Drane. An algorithm for least squares estimation of nonlinear parameters when some of the parameters are linear. *Technometrics*, 14(3):757–766, August 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267303`.

Behnken:1972:RTV

[BD72b] Donald W. Behnken and Norman R. Draper. Residuals and their variance patterns. *Technometrics*, 14(1):101–111, February 1972. CO-

DEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266922`.

Barr:1973:KST

[BD73] Donald R. Barr and Teddy Davidson. A Kolmogorov-Smirnov test for censored samples. *Technometrics*, 15(4):739–757, November 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267385`.

Box:1974:MPS

[BD74] Michael J. Box and Norman R. Draper. On minimum-point second-order designs. *Technometrics*, 16(4):613–616, November 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267614`.

Bishop:1978:EAV

[BD78] Thomas A. Bishop and Edward J. Dudewicz. Exact analysis of variance with unequal variances: Test procedures and tables. *Technometrics*, 20(4):419–430, November 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267642`.

Box:1970:MVM

[BDH70] Michael J. Box, Norman R. Draper, and William G. Hunter. Missing values in multiresponse nonlinear model fitting. *Technometrics*, 12(3):613–620, August 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267206`.

Bain:1973:IET

[BE73] Lee J. Bain and Max Engelhardt. Interval estimation for the two-parameter double exponential distribution. *Technometrics*, 15 (4):875–887, November 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267397`.

Beale:1970:NPV

[Bea70] E. M. L. Beale. Note on procedures for variable selection in multiple regression. *Technometrics*, 12(4):909–914, November 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267335`.

Beck:1974:PEC

[Bec74] J. V. Beck. Parameter estimation with cumulative errors. *Technometrics*, 16(1):85–92, February 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267496`.

Bedall:1974:BRB

[Bed74] Fritz K. Bedall. Book review: *Statistische Auswertungsmethoden* by Lothar Sachs. *Technometrics*, 16(1):141, February 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267510`.

Behboodian:1970:MMT

[Beh70] Javad Behboodian. On the modes of a mixture of two normal distributions. *Technometrics*, 12(1):131–139, February 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267357`.

Behboodian:1972:DSS

[Beh72] Javad Behboodian. On the distribution of a symmetric statistic from a mixed population. *Technometrics*, 14(4):919–923, November 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267140`.

Bell:1970:BRB

[Bel70] C. B. Bell. Book review: *Distribution-Free Statistical Tests* by James V. Bradley. *Technometrics*, 12(4):929, November 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267340`.

Bender:1976:BRB

[Ben76] Filmore E. Bender. Book review: *Cost of Living Index Numbers: Practice, Precision and Theory* by Kali S. Banerjee. *Technometrics*, 18(2):243–244, May 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267538`.

Berger:1972:YOF

[Ber72a] Paul D. Berger. On Yates' order in fractional factorial designs. *Technometrics*, 14(4):971–972, November 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267146`.

Berman:1972:BRB

[Ber72b] Simeon M. Berman. Book review: *On Regular Variation and Its Application to the Weak Convergence of Sample Extremes* by L. de Haan. *Technometrics*, 14(1):236–237, February 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266940`.

Berry:1973:BRB

[Ber73] Brian J. L. Berry. Book review: *Explorations in Mathematical Anthropology* by Paul Kay. *Technometrics*, 15(1):201–202, February 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266844`.

Berk:1978:CSR

[Ber78] Kenneth N. Berk. Comparing subset regression procedures. *Technometrics*, 20(1):1–6, February 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268153`.

Brown:1972:SMS

[BF72] G. H. Brown and N. I. Fisher. Subsampling a mixture of sampled material. *Technometrics*, 14(3):663–668, August 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267294`.

Brown:1974:SSB

[BF74] Morton B. Brown and Alan B. Forsythe. The small sample behavior of some statistics which test the equality of several means. *Technometrics*, 16(1):129–132, February 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267501`.

Best:1974:IGA

[BG74] D. J. Best and P. G. Gipps. An improved gamma approximation to the negative binomial. *Technometrics*, 16(4):621–624, November 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267616`.

Bradu:1978:BDT

[BG78] Dan Bradu and K. Ruben Gabriel. The biplot as a diagnostic tool for models of two-way tables. *Technometrics*, 20(1):47–68, February

1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268161`. See errata [Ano78e].

Blumenthal:1973:TRB

[BGH73] S. Blumenthal, J. A. Greenwood, and L. Herbach. The transient reliability behavior of series systems or superimposed renewal processes. *Technometrics*, 15(2):255–269, May 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266986`.

Ball:1970:SII

[BH70] Geoffrey H. Ball and David J. Hall. Some implications of interactive graphic computer systems for data analysis and statistics. *Technometrics*, 12(1):17–31, February 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267348`.

Bulgren:1973:DST

[BH73] William G. Bulgren and John E. Hewett. Double sample tests for hypotheses about the mean of an exponential distribution. *Technometrics*, 15(1):187–190, February 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266836`.

Box:1974:CIV

[BH74] George E. P. Box and William J. Hill. Correcting inhomogeneity of variance with power transformation weighting. *Technometrics*, 16(3):385–389, August 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267668`.

Bradley:1977:ODT

[BH77] Ralph A. Bradley and A. Hedayat. Optimal designs for two noninteractive treatments. *Technometrics*, 19(1):53–57, February 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268254`.

Bauer:1978:UMQ

[BH78] Peter Bauer and Peter Hackl. The use of MOSUMS for quality control. *Technometrics*, 20(4):431–436, November 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267643`.

Bhapkar:1972:BRB

[Bha72] Vasant Bhapkar. Book review: *Practical Nonparametric Statistics* by W. J. Conover. *Technometrics*, 14(4):977–979, November 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267149`.

Bhat:1973:RIC

[Bha73] U. Narayan Bhat. Reliability of an independent component, s-spare system with exponential life times and general repair times. *Technometrics*, 15(3):529–539, August 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266858`.

Box:1973:SPA

[BHME73] G. E. P. Box, W. G. Hunter, J. F. MacGregor, and J. Erjavec. Some problems associated with the analysis of multiresponse data. *Technometrics*, 15(1):33–51, February 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266823`.

Binns:1974:ANB

[Bin74a] M. R. Binns. Approximating the negative bionomial via the positive binomial. *Technometrics*, 16(2):323–324, May 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267956`.

Binns:1974:DSP

[Bin74b] M. R. Binns. A double sampling procedure to control the variance in net weight acceptance sampling. *Technometrics*, 16(4):539–543, November 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267605`.

Bishir:1972:BRB

[Bis72a] John Bishir. Book review: *Physical Concepts of Probability* by J. A. McFadden. *Technometrics*, 14(4):977, November 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267148`.

Bishop:1972:BRB

[Bis72b] Albert Bishop. Book review: *Mathematical Methods of Optimal Control* by V. G. Boltyanskii; K. N. Trirogoff. *Technometrics*, 14(4):981–983, November 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267153`.

Bishop:1978:NSR

[Bis78] Thomas A. Bishop. A note on Schafer and Rutemiller's complete ranking procedure. *Technometrics*, 20(4):495–496, November 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267651`. See corrigenda [Ano79e] and [SR75].

Bishop:1979:SRS

[Bis79] Thomas A. Bishop. Some results on simultaneous inference for analysis of variance with unequal variances. *Technometrics*, 21(3):337–340, August 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267756`.

Basson:1970:LE

[BJ70a] Rodney P. Basson and Jay W. Johnson. Letters to the Editor. *Technometrics*, 12(1):187–188, February 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267375`.

Bellmore:1970:IES

[BJ70b] M. Bellmore and P. A. Jensen. An implicit enumeration scheme for proper cut generation. *Technometrics*, 12(4):775–788, November 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267324`.

Bagshaw:1975:ESC

[BJ75] Michael Bagshaw and Richard A. Johnson. The effect of serial correlation on the performance of CUSUM tests II. *Technometrics*, 17(1):73–80, February 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268003`.

Bhattacharyya:1971:CPS

[BJN71] G. K. Bhattacharyya, Richard A. Johnson, and Henry R. Neave. A comparative power study of the bivariate rank sum test and T^2. *Technometrics*, 13(1):191–198, February 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267086`.

Boardman:1970:ECE

[BK70a] Thomas J. Boardman and Peter J. Kendell. Estimation in compound exponential failure models. *Technometrics*, 12(4):891–900, November 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267333`.

Boardman:1970:TEA

[BK70b] Thomas J. Boardman and Peter J. Kendell. Tables of exact and approximate expected values of certain ratios and reciprocals of multinomial random variables useful in life testing. *Technometrics*, 12(4):901–908, November 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267334`.

Bowman:1974:PPP

[BK74] Kimiko O. Bowman and Marvin A. Kastenbaum. Potential pitfalls of portable power. *Technometrics*, 16(3):349–352, August 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267664`.

Barnett:1978:SPT

[BKRS78] A. Barnett, D. J. Kleitman, D. Rosenbaum, and B. Singer. A statistical procedure for testing nuclear powered cardiac pacemakers. *Technometrics*, 20(3):221–226, August 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268128`.

Basu:1971:DRT

[BL71] A. P. Basu and Robert H. Lochner. On the distribution of the ratio of two random variables having generalized life distributions. *Technometrics*, 13(2):281–287, May 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266790`.

Britt:1973:EPN

[BL73] H. I. Britt and R. H. Luecke. The estimation of parameters in nonlinear, implicit models. *Technometrics*, 15(2):233–247, May 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266984`.

Beja:1974:ESA

[BL74a] Avraham Beja and Shaul P. Ladany. Efficient sampling by artificial attributes. *Technometrics*, 16(4):601–611, November 1974. CODEN

TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267613`.

Berger:1974:EWP

[BL74b] Roger W. Berger and Kenneth Lawrence. Estimating Weibull parameters by linear and nonlinear regression. *Technometrics*, 16 (4):617–619, November 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267615`.

Blackwell:1977:ESP

[Bla77] M. T. R. Blackwell. The effect of short production runs on CSP-1. *Technometrics*, 19(3):259–263, August 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267695`.

Bray:1973:TCA

[BLB73] D. F. Bray, D. A. Lyon, and I. W. Burr. Three class attributes plans in acceptance sampling. *Technometrics*, 15(3):575–585, August 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266864`.

Blight:1972:MEC

[Bli72] B. J. N. Blight. On the most economical choice of a life testing procedure for exponentially distributed data. *Technometrics*, 14(3):613–618, August 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267289`.

Box:1972:LE

[BM72] George E. P. Box and John F. MacGregor. Letter to the Editor. *Technometrics*, 14(4):985–986, November 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267156`.

Box:1974:ACL

[BM74] George E. P. Box and John F. MacGregor. The analysis of closed-loop dynamic-stochastic systems. *Technometrics*, 16(3):391–398, August 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267669`.

Box:1976:PEC

[BM76] George E. P. Box and John F. MacGregor. Parameter estimation with closed-loop operating data. *Technometrics*, 18(4):371–380, November

1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268651`. See discussion [Ell76].

Bruvold:1978:SSC

[BM78] Norman T. Bruvold and Richard A. Murphy. Sample sizes for comparison of proportions. *Technometrics*, 20(4):437–440, November 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267644`.

Beyer:1976:ESD

[BMH76] Jon N. Beyer, Albert H. Moore, and H. Leon Harter. Estimation of the standard deviation of the logistic distribution by the use of selected order statistics. *Technometrics*, 18(3):313–332, August 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268741`.

Breiman:1977:VKE

[BMP77] Leo Breiman, William Meisel, and Edward Purcell. Variable kernel estimates of multivariate densities. *Technometrics*, 19(2):135–144, May 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268623`.

Bechhofer:1972:OAO

[BN72] Robert E. Bechhofer and Dominique Jean-Marie Nocturne. Optimal allocation of observations when comparing several treatments with a control. II. 2-sided comparisons. *Technometrics*, 14(2):423–436, May 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267433`.

Boardman:1973:ECE

[Boa73] Thomas J. Boardman. Estimation in compound exponential failure models—when the data are grouped. *Technometrics*, 15(2):271–277, May 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266987`.

Boardman:1979:BRBa

[Boa79a] Eileen C. Boardman. Book reviews: *Statistics in the Real World* by Richard J. Larsen; Donna Fox Stroup; *A Programmed Text in Statistics: Books One-Four* by J. Hine; G. B. Wetherill; *Statistical Methods for Engineers and Scientists: A Students' Course Book* by A. C. Bajpai; I. M. Calus; J. A. Fairley; *Statistics: A Self-Teaching Guide* by Donald J. Koosis. *Technometrics*, 21(3):390–391, August 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267771`.

Boardman:1979:BRBb

[Boa79b] Thomas J. Boardman. Book review: *Prediction and Improved Estimation in Linear Models* by John Bibby; Helge Toutenburg. *Technometrics*, 21(4):582, November 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268300`.

Bodin:1970:ASR

[Bod70] Lawrence D. Bodin. Approximations to system reliability using a modular decomposition. *Technometrics*, 12(2):335–344, May 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267238`.

Bonis:1976:BRBa

[Bon76a] Austin J. Bonis. Book review: *Comparative Statistical Inference* by Vick Barnett. *Technometrics*, 18(1):119–120, February 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267925`.

Bonis:1976:BRBb

[Bon76b] Austin J. Bonis. Book review: *Gambling with Truth. An Essay on Induction and the Aims of Science* by Isaac Levi. *Technometrics*, 18 (2):240, May 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267533`.

Bonis:1977:BRB

[Bon77] Austin J. Bonis. Book review: *Scientific Strategies in Human Affairs: To Tell the Truth* by Irwin D. J. Bross. *Technometrics*, 19(1):102, February 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268264`.

Borges:1972:QAQ

[Bor72] Rudolf Borges. Query 1: Addition to query 3, In Probability, Why Does $A \subset B$ Mean, “A Implies B”? (Volume 13, No. 3, August 1970). *Technometrics*, 14(1):243, February 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266943`.

Bowerman:1977:BRB

[Bow77] Bruce L. Bowerman. Book review: *Probability and Mathematical Statistics* by Lester D. Taylor. *Technometrics*, 19(3):342, August 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267706`.

Bowerman:1978:BRB

[Bow78] Bruce Bowerman. Book review: *Introductory Statistics* by T. H. Wonnacott; R. J. Wonnacott. *Technometrics*, 20(4):502–503, November 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267655`.

Box:1970:IPE

[Box70a] M. J. Box. Improved parameter estimation. *Technometrics*, 12 (2):219–229, May 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267230`.

Box:1970:SEN

[Box70b] M. J. Box. Some experiences with a nonlinear experimental design criterion. *Technometrics*, 12(3):569–589, August 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267204`.

Box:1971:SED

[Box71] M. J. Box. Simplified experimental design. *Technometrics*, 13(1):19–31, February 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267073`.

Boyle:1974:BRB

[Boy74] Carolyn R. Boyle. Book review: *Statistical and Mathematical Aspects of Pollution Problems* by John W. Pratt. *Technometrics*, 16(4):636, November 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267627`.

Brown:1973:EML

[BR73] Gerald G. Brown and Herbert C. Rutemiller. The efficiencies of maximum likelihood and minimum variance unbiased estimators of fraction defective in the normal case. *Technometrics*, 15(4):849–855, November 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267394`.

Brown:1975:EMP

[BR75] G. H. Brown and D. S. Robson. The estimation of mixing proportions by double sample using bulk measurement. *Technometrics*, 17(1):119–126, February 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268009`.

Bakir:1979:NPP

[BR79] Saad T. Bakir and Marion R. Reynolds, Jr. A nonparametric procedure for process control based on within-group ranking. *Technometrics*, 21(2):175–183, May 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268514`.

Brillinger:1973:BRB

[Bri73a] David R. Brillinger. Book review: *Introduction to Random Differential Equations and Their Applications* by S. K. Srinivasan; R. Vasudevan. *Technometrics*, 15(2):421–422, May 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267004`.

Brillinger:1973:PSE

[Bri73b] David R. Brillinger. A power spectral estimate which is insensitive to transients. *Technometrics*, 15(3):559–562, August 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266861`.

Britney:1974:RCS

[Bri74] Robert R. Britney. The reliability of complex systems with dependent subsystem failures: An absorbing Markov chain model. *Technometrics*, 16(2):245–250, May 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267946`.

Brown:1977:CSR

[Bro77] P. J. Brown. Centering and scaling in ridge regression. *Technometrics*, 19(1):35–36, February 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268251`.

Brown:1979:OCL

[Bro79] G. H. Brown. An optimization criterion for linear inverse estimation. *Technometrics*, 21(4):575–579, November 1979. CODEN TCMTA2.

ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268298`.

Bryson:1971:GTP

[Bry71] Maurice C. Bryson. A Gibbs-type phenomenon in the failure rates of parallel systems. *Technometrics*, 13(3):692–695, August 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267182`.

Bryson:1974:HTD

[Bry74] Maurice C. Bryson. Heavy-tailed distributions: Properties and tests. *Technometrics*, 16(1):61–68, February 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267493`.

Barlow:1971:EAL

[BS71] Richard E. Barlow and Ernest M. Scheuer. Estimation from accelerated life tests. *Technometrics*, 13(1):145–159, February 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267082`. See remark [Rea71].

Bradley:1972:COL

[BS72] E. L. Bradley, Jr. and J. G. Saw. Choosing the optimum lot size for a reordering policy with instantaneous emergency deliveries. *Technometrics*, 14(4):931–934, November 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267142`.

Bryant:1979:CLM

[BS79] Clifford M. Bryant and Josef Schmee. Confidence limits on MTBF for sequential test plans of MIL-STD 781. *Technometrics*, 21(1):33–42, February 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268578`.

Bratcher:1971:BPP

[BSH71] T. L. Bratcher, W. R. Schucany, and H. H. Hunt. Bayesian prediction and population size assumptions. *Technometrics*, 13(3):678–681, August 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267179`.

Beaton:1974:FPS

[BT74] Albert E. Beaton and John W. Tukey. The fitting of power series, meaning polynomials, illustrated on band-spectroscopic data. *Tech-*

nometrics, 16(2):147–185, May 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267936`. See discussion [Mal74, Mar74].

Buck:1973:BRB

[Buc73] James R. Buck. Book review: *Work Design, a Systems Concept* by Gerald Nadler. *Technometrics*, 15(1):200–201, February 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266843`.

Burgerhout:1973:CPD

[Bur73] Th. J. Burgerhout. A class of probability distributions with application to aircraft flight path analysis. *Technometrics*, 15(2):365–378, May 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266995`.

Bush:1971:UEA

[Bus71] Norman Bush. Unmodeled error analysis on trajectory and orbital estimation. *Technometrics*, 13(2):303–314, May 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266792`.

Butcher:1978:TIM

[BWL78] Allan C. Butcher, Alan Winterbottom, and Harold Lampkin. Transformations improving maximum likelihood confidence intervals for system reliability. *Technometrics*, 20(4):467–473, November 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267647`.

Cameron:1977:BRB

[Cam77] J. M. Cameron. Book review: *Weighing Designs* by K. S. Baneriee. *Technometrics*, 19(2):219–220, May 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268639`.

Carter:1974:BRB

[Car74] Walter H. Carter, Jr. Book review: *Fundamental Concepts in the Design of Experiments* by Charles Hicks. *Technometrics*, 16(2):327–328, May 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267961`.

Carney:1977:BRB

[Car77a] Edward J. Carney. Book review: *Vital Statistics* by Michael Orkin; Richard Drogin. *Technometrics*, 19(2):218–219, May 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268637`.

Carroll:1977:BRB

[Car77b] Mavis B. Carroll. Book review: *Micro-Organisms in Foods 2: Sampling for Microbiological Analysis; Principles and Specific Applications* by *The International Commission on Microbiological Specifications for Foods*. *Technometrics*, 19(2):221, May 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268642`.

Castro:1976:BRB

[Cas76] Peter E. Castro. Book review: *Complex Variables for Scientists and Engineers* by John D. Paliouras. *Technometrics*, 18(2):244, May 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267539`.

Canfield:1975:SDT

[CB75] Ronald V. Canfield and Leon E. Borgman. Some distributions of time to failure for reliability applications. *Technometrics*, 17(2):263–268, May 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268360`.

Conover:1979:MDC

[CBI79] W. J. Conover, Thomas R. Bement, and Ronald L. Iman. On a method for detecting clusters of possible uranium deposits. *Technometrics*, 21(3):277–282, August 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267748`.

Chan:1971:STB

[CC71] Lai K. Chan and Smiley W. H. Cheng. On the Student's test based on sample percentiles from the normal, logistic and Cauchy distribution. *Technometrics*, 13(1):127–137, February 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267080`.

Chacko:1979:OME

[CDR79] Annie Chacko, A. Dey, and G. V. S. Ramakrishna. Orthogonal main-effect plans for asymmetrical factorials. *Technometrics*, 21(2):269–

270, May 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268528`.

Chhikara:1976:OTP

[CF76] Raj S. Chhikara and J. Leroy Folks. Optimum test procedures for the mean of first passage time distribution in Brownian motion with positive drift (inverse Gaussian distribution). *Technometrics*, 18(2):189–193, May 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267521`.

Chhikara:1977:IGD

[CF77] R. S. Chhikara and J. L. Folks. The inverse Gaussian distribution as a lifetime model. *Technometrics*, 19(4):461–468, November 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267886`.

Cleveland:1976:SRS

[CG76] William S. Cleveland and Roberta Guarino. Some robust statistical procedures and their application to air pollution data. *Technometrics*, 18(4):401–409, November 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268655`.

Chan:2007:MMC

[CGO07] Raymond H. Chan, Chen Greif, and Dianne P. O'Leary, editors. *Milestones in Matrix Computation: the Selected Works of Gene H. Golub with Commentaries*. Oxford University Press, Walton Street, Oxford OX2 6DP, UK, 2007. ISBN 0-19-920681-3. xi + 565 + 3 pp. LCCN QA188 .G67 2007. URL `http://www.loc.gov/catdir/enhancements/fy0737/2007276086-d.html`.

Church:1970:ERS

[CH70] J. D. Church and Bernard Harris. The estimation of reliability from stress-strength relationships. *Technometrics*, 12(1):49–54, February 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267350`.

Chase:1973:TET

[CH73a] Gerald R. Chase and John E. Hewett. On testing for equality of two availabilities. *Technometrics*, 15(4):889–896, November 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267398`.

Cohen:1973:EED

[CH73b] A. Clifford Cohen and Frederick Russell Helm. Estimation in the exponential distribution. *Technometrics*, 15(2):415–418, May 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267000`.

Cleroux:1974:ARA

[CH74] R. Cleroux and M. Hanscom. Age replacement with adjustment and depreciation costs and interest charges. *Technometrics*, 16(2):235–239, May 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267944`.

Chambers:1970:CSR

[Cha70a] J. M. Chambers. Computers in statistical research: Simulation and computer-aided mathematics. *Technometrics*, 12(1):1–15, February 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267347`.

Chapman:1970:MVC

[Cha70b] J. W. Chapman. Moments, variances, and covariances of sines and cosines of arguments which are subject to random error. *Technometrics*, 12(3):693–694, August 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267213`.

Chandler:1972:IPE

[Cha72] J. P. Chandler. On an iterative procedure for estimating functions when both variables are subject to error. *Technometrics*, 14(1):71–76, February 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266919`.

Chafee:1975:BRB

[Cha75a] Nathaniel Chafee. Book review: *Partial Differential Equations of Mathematical Physics* by Tyn Myint-U. *Technometrics*, 17(3):389, August 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268089`.

Chambers:1975:BRB

[Cha75b] John M. Chambers. Book review: *Nonlinear Parameter Estimation* by Yonathan Bard. *Technometrics*, 17(2):271–272, May 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268363`.

Chang:1979:CIE

[Cha79] Wei-Chien Chang. Confidence interval estimation and transformation of data in a mixture of two multivariate normal distributions with any given large dimension. *Technometrics*, 21(3):351–355, August 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267758`.

Chew:1971:BRB

[Che71] Milton C. Chew, Jr. Book review: *Distributions in Statistics: Continuous Univariate Distributions — 1 and 2* by N. L. Johnson; S. Kotz. *Technometrics*, 13(4):919–920, November 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266973`.

Chaddha:1971:ATS

[CHH$^+$71] R. L. Chaddha, W. W. Hardgrave, D. J. Hudson, M. Segal, and J. W. Suurballe. Allocation of total sample size when only the stratum means are of interest. *Technometrics*, 13(4):817–831, November 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266957`.

Chiu:1974:NPD

[Chi74] W. K. Chiu. A new prior distribution for attributes sampling. *Technometrics*, 16(1):93–102, February 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267497`.

Chiu:1975:EDA

[Chi75] W. K. Chiu. Economic design of attribute control charts. *Technometrics*, 17(1):81–87, February 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268004`.

Choi:1973:NST

[Cho73] S. C. Choi. On nonparametric sequential tests for independence. *Technometrics*, 15(3):625–629, August 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266868`.

Choi:1979:TST

[Cho79] S. C. Choi. Two-sample tests for compound distributions for homogeneity of mixing proportions. *Technometrics*, 21(3):361–365, August

1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267760`.

Consul:1973:GPD

[CJ73] P. C. Consul and G. C. Jain. A generalization of the Poisson distribution. *Technometrics*, 15(4):791–799, November 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267389`.

Cleveland:1975:GTE

[CK75] William S. Cleveland and Beat Kleiner. A graphical technique for enhancing scatterplots with moving statistics. *Technometrics*, 17(4):447–454, November 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268431`.

Cornell:1979:OCP

[CK79] John A. Cornell and Andre I. Khuri. Obtaining constant prediction variance on concentric triangles for ternary mixture systems. *Technometrics*, 21(2):147–157, May 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268512`.

Corneliussen:1970:STB

[CL70] Arvid Corneliussen and Daniel W. Ladd. On sequential tests of the binomial distribution. *Technometrics*, 12(3):635–646, August 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267209`. See addendum [CL71].

Corneliussen:1971:AST

[CL71] Arvid H. Corneliussen and Daniel W. Ladd. Addendum to “On Sequential Tests of the Binomial Distribution”. *Technometrics*, 13(1):205–210, February 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267090`. See [CL70].

Cleveland:1971:FTS

[Cle71] William S. Cleveland. Fitting time series models for prediction. *Technometrics*, 13(4):713–723, November 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266948`.

Cleveland:1972:BRB

[Cle72a] William S. Cleveland. Book review: *Multiple Time Series* by E. J. Hannan. *Technometrics*, 14(1):229–231, February 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266935`.

Cleveland:1972:IAT

[Cle72b] William S. Cleveland. The inverse autocorrelations of a time series and their applications. *Technometrics*, 14(2):277–293, May 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267420`. See discussion [Par72].

Connell:1971:CWT

[CM71] Terrence L. Connell and Piotr W. Mikulski. On comparison of waiting time versus counting technique in construction of confidence intervals for a parameter of a Poisson process. *Technometrics*, 13(3):699–703, August 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267184`.

Cohen:1977:PCS

[CN77] A. Clifford Cohen and Nicholas J. Norgaard. Progressively censored sampling in the three-parameter gamma distribution. *Technometrics*, 19(3):333–340, August 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267704`.

Cornell:1975:UGA

[CO75] John A. Cornell and Lyman Ott. The use of gradients to aid in the interpretation of mixture response surfaces. *Technometrics*, 17(4):409–424, November 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268427`. See discussion [Sne75a].

Cohen:1965:MLE

[Coh65] A. Clifford Cohen. Maximum likelihood estimation in the Weibull distribution based on complete and on censored samples. *Technometrics*, 7(4):579–588, November 1965. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266397`. See errata [Ano73k].

Cohen:1970:CAS

[Coh70] A. Clifford Cohen. Curtailed attribute sampling. *Technometrics*, 12(2):295–298, May 1970. CODEN TCMTA2. ISSN 0040-

1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267234`.

Cohen:1972:EPP

[Coh72] A. Clifford Cohen. Estimation in a Poisson process based on combinations of complete and truncated samples. *Technometrics*, 14 (4):841–846, November 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267133`.

Cohen:1973:RWD

[Coh73] A. Clifford Cohen. The reflected Weibull distribution. *Technometrics*, 15(4):867–873, November 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267396`.

Cohen:1975:MCS

[Coh75] A. Clifford Cohen. Multi-censored sampling in the three parameter Weibull distribution. *Technometrics*, 17(3):347–351, August 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268072`.

Cohen:1976:PCS

[Coh76] A. Clifford Cohen. Progressively censored sampling in the three parameter log-normal distribution. *Technometrics*, 18(1):99–103, February 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267922`.

Company:1970:AR

[Com70] Alexander Grant & Company. Auditor's report. *Technometrics*, 12(2):435–437, May 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267254`.

Company:1971:AR

[Com71] Alexander Grant & Company. Auditors' report. *Technometrics*, 13 (2):461, May 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266816`.

Conniffe:1970:NRR

[Con70] D. Conniffe. A note on the 'round robin' design. *Technometrics*, 12(3):695–696, August 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267214`.

Conover:1974:BRB

[Con74] W. J. Conover. Book review: *Statistical Methods for Rates and Proportions* by Joseph L. Fleiss. *Technometrics*, 16(2):326–327, May 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267960`.

Cooper:1972:BRB

[Coo72] Leon Cooper. Book review: *Notes on Linear Programming* by M. Sakarovitch. *Technometrics*, 14(1):237–238, February 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266941`.

Cook:1977:DIO

[Coo77] R. Dennis Cook. Detection of influential observation in linear regression. *Technometrics*, 19(1):15–18, February 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268249`.

Cornell:1971:BRB

[Cor71] John A. Cornell. Book review: *Introductory Mathematical Statistics: Principles and Methods* by Erwin Kreyszig. *Technometrics*, 13(4):922–925, November 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266977`.

Cornell:1973:EMR

[Cor73] John A. Cornell. Experiments with mixtures: A review. *Technometrics*, 15(3):437–455, August 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266850`.

Cornell:1975:SCD

[Cor75] John A. Cornell. Some comments on designs for Cox's mixture polynomial. *Technometrics*, 17(1):25–35, February 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267996`.

Cornell:1977:WVU

[Cor77] John A. Cornell. Weighted versus unweighted estimates using Scheffé's mixture model for symmetrical error variances patterns. *Technometrics*, 19(3):237–247, August 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267693`.

Cornell:1979:EMU

[Cor79] John A. Cornell. Experiments with mixtures: An update and bibliography. *Technometrics*, 21(1):95–106, February 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268585`.

Cleveland:1975:ECF

[CP75] William S. Cleveland and Emanuel Parzen. The estimation of coherence, frequency response, and envelope delay. *Technometrics*, 17(2):167–172, May 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268347`.

Chhikara:1979:NCM

[CR79] R. S. Chhikara and D. T. Register. A numerical classification method for partitioning of a large multidimensional mixed data set. *Technometrics*, 21(4):531–537, November 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268293`.

Crain:1974:BRB

[Cra74] Bradford R. Crain. Book review: *Approximating Countable Markov Chains*, Volume III by David Freedman. *Technometrics*, 16(4):635, November 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267624`.

Crocker:1971:CNJ

[Cro71] Douglas C. Crocker. Comment on a note by John J. Wiorkowski. *Technometrics*, 13(2):455, May 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266814`. See [Wio70].

Crocker:1978:BRB

[Cro78] Douglas C. Crocker. Book review: *A Short Course on Applied Regression Analysis* by Stanley L. Sclove. *Technometrics*, 20(2):215, May 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268727`.

Crump:1978:BRBa

[Cru78a] Phelps P. Crump. Book review: *Introduction to Statistics* by Robert Fried. *Technometrics*, 20(1):103–104, February 1978. CODEN

TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268166.

Crump:1978:BRBb

[Cru78b] Phelps P. Crump. Book review: *Statistics and Experimental Design in Engineering and the Physical Sciences* by Norman L. Johnson; Fred C. Leone. *Technometrics*, 20(3):319–320, August 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1268143.

Corbeil:1976:RML

[CS76] R. R. Corbeil and S. R. Searle. Restricted maximum likelihood (REML) estimation of variance components in the mixed model. *Technometrics*, 18(1):31–38, February 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1267913.

DAgostino:1971:ALE

[D'A71a] Ralph B. D'Agostino. An addendum to "linear estimation of the Weibull parameters". *Technometrics*, 13(2):428–429, May 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1266804.

DAgostino:1971:LEW

[D'A71b] Ralph B. D'Agostino. Linear estimation of the Weibull parameters. *Technometrics*, 13(1):171–182, February 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1267084.

Dumonceaux:1973:DBL

[DA73] Robert Dumonceaux and Charles E. Antle. Discrimination between the log-normal and the Weibull distributions. *Technometrics*, 15(4):923–926, November 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1267401.

Dumonceaux:1973:LRT

[DAH73] Robert Dumonceaux, Charles E. Antle, and Gerald Haas. Likelihood ratio test for discrimination between two models with unknown location and scale parameters. *Technometrics*, 15(1):19–27, February 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL http://www.jstor.org/stable/1266821. See discussion [Har73a].

Dalal:1977:BRB

[Dal77] Jayesh G. Dalal. Book review: *Statistics for Technology* by Christopher Chatfield. *Technometrics*, 19(3):342, August 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267707`.

Danziger:1970:PCL

[Dan70] L. Danziger. Planning censored life tests for estimation of the hazard rate of a Weibull distribution with prescribed precision. *Technometrics*, 12(2):408–412, May 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267246`.

Daniel:1978:PRT

[Dan78] Cuthbert Daniel. Patterns in residuals in the two-way layout. *Technometrics*, 20(4):385–395, November 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267638`.

David:1970:BRB

[Dav70] F. N. David. Book review: *Systems of Frequency Curves* by W. P. Elderton; N. L. Johnson. *Technometrics*, 12(1):173–174, February 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267366`.

Davis:1977:BRB

[Dav77] Henry T. Davis. Book review: *Statistical and Computational Methods in Data Analysis* by Siegmund Brandt. *Technometrics*, 19 (4):516–517, November 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267898`.

Davis:1979:CRS

[Dav79a] A. W. Davis. On certain ratio statistics in weather modification experiments. *Technometrics*, 21(3):283–289, August 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267749`.

Davis:1979:RMD

[Dav79b] William W. Davis. Robust methods for detection of shifts of the innovation variance of a time series. *Technometrics*, 21(3):313–320, August 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267753`. See [Ano80a].

DeGray:1970:SYS

[DeG70] R. J. DeGray. The sequential Youden square. *Technometrics*, 12(1):147–152, February 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267359`.

Draper:1971:BEB

[DG71] N. Draper and I. Guttman. Bayesian estimation of the binomial parameter. *Technometrics*, 13(3):667–673, August 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267177`.

Dahiya:1972:GFT

[DG72] Ram C. Dahiya and John Gurland. Goodness of fit tests for the gamma and exponential distributions. *Technometrics*, 14(3):791–801, August 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267306`.

Draper:1971:LF

[DH71] Norman R. Draper and Agnes M. Herzberg. On lack of fit. *Technometrics*, 13(2):231–241, May 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266786`. See corrigendum [Ano72f].

Diehr:1974:ADS

[DH74] George Diehr and Donald R. Hoflin. Approximating the distribution of the sample R^2 in best subset regressions. *Technometrics*, 16(2):317–320, May 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267954`.

Dickinson:1974:SRO

[Dic74] A. W. Dickinson. Some run orders requiring a minimum number of factor level changes for the 2^4 and 2^5 main effect plans. *Technometrics*, 16(1):31–37, February 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267489`.

Dillon:1971:BRB

[Dil71] Martin Dillon. Book review: *Style and Vocabulary: Numerical Studies* by C. B. Williams. *Technometrics*, 13(3):708–709, August 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267188`.

Draper:1970:NRT

[DL70] Norman R. Draper and Willard E. Lawrence. A note on residuals in two dimensions. *Technometrics*, 12(2):394–398, May 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267244`.

Denby:1977:TDD

[DM77] L. Denby and C. L. Mallows. Two diagnostic displays for robust regression analysis. *Technometrics*, 19(1):1–13, February 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268248`.

Dufour:1978:DRM

[DM78] R. Dufour and U. R. Maag. Distribution results for modified Kolmogorov–Smirnov statistics for truncated or censored samples. *Technometrics*, 20(1):29–32, February 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268157`.

Dolby:1970:SSA

[Dol70] James L. Dolby. Some statistical aspects of character recognition. *Technometrics*, 12(2):231–245, May 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267231`.

Doob:1972:BRB

[Doo72] J. L. Doob. Book review: *Markov Chains* by David Freedman. *Technometrics*, 14(2):503, May 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267441`.

Downton:1973:ENC

[Dow73] F. Downton. The estimation of $\Pr(Y < X)$ in the normal case. *Technometrics*, 15(3):551–558, August 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266860`.

Dey:1977:NOM

[DR77] A. Dey and G. V. S. Ramakrishna. A note on orthogonal main-effect plans. *Technometrics*, 19(4):511–512, November 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267894`.

Drane:1979:BRB

[Dra79] J. Wanzer Drane. Book review: *The Analysis of Cross-Classified Categorical Data* by Stephen E. Fienberg. *Technometrics*, 21(3):388, August 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267767`.

Draper:1977:DTF

[DS77a] Norman R. Draper and Ralph C. St. John. Designs in three and four components for mixtures models with inverse terms. *Technometrics*, 19(2):117–130, May 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268621`.

Draper:1977:MMI

[DS77b] Norman R. Draper and Ralph C. St. John. A mixtures model with inverse terms. *Technometrics*, 19(1):37–46, February 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268252`.

Doviak:1979:SSE

[DS79] M. J. Doviak and R. L. Scheaffer. A sequential scheme for estimating average quality in a mixed product production process. *Technometrics*, 21(4):549–554, November 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268295`.

Dubey:1973:PPT

[Dub73] Satya D. Dubey. On the performance of power of tests for the comparison of exponential distributions. *Technometrics*, 15(1):183–186, February 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266835`.

Dudewicz:1979:BRB

[Dud79] Edward J. Dudewicz. Book review: *Selecting and Ordering Populations: A New Statistical Methodology* by J. D. Gibbons; I. Olkin; M. Sobel. *Technometrics*, 21(4):582–583, November 1979. CODEN

TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268301`.

Dunn:1971:SEV

[Dun71] Olive Jean Dunn. Some expected values for probabilities of correct classification in discriminant analysis. *Technometrics*, 13(2):345–353, May 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266796`.

Dunn:1972:BRB

[Dun72] Olive Jean Dunn. Book review: *Nonparametric Methods in Multivariate Analysis* by M. L. Puri; P. K. Sen. *Technometrics*, 14(2):502–503, May 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267440`.

Dunsmore:1974:BPD

[Dun74] I. R. Dunsmore. The Bayesian predictive distribution in life testing models. *Technometrics*, 16(3):455–460, August 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267677`.

Dunn:1977:BRBa

[Dun77a] Douglas M. Dunn. Book review: *Forecasting and Time Series Analysis* by Douglas C. Montgomery; Lynwood A. Johnson. *Technometrics*, 19(3):344, August 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267711`.

Dunn:1977:BRBb

[Dun77b] Douglas M. Dunn. Book review: *Management Applications of Modern Control Theory* by A. Bensoussan; E. Gerald Hurst,; B. Naslund. *Technometrics*, 19(3):344–345, August 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267712`.

Duncan:1978:EDC

[Dun78a] Acheson J. Duncan. The economic design of p-charts to maintain current control of a process: Some numerical results. *Technometrics*, 20(3):235–243, August 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268131`.

Duncan:1978:ESJ

[Dun78b] George T. Duncan. An empirical study of jackknife-constructed confidence regions in nonlinear regression. *Technometrics*, 20(2):123–129, May 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268703`.

Dunsmore:1978:SAT

[Dun78c] Ian R. Dunsmore. Some approximations for tolerance factors for the two parameter exponential distribution. *Technometrics*, 20(3):317–318, August 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268141`.

Davis:1978:ACI

[DV78] A. W. Davis and L. G. Veitch. Approximate confidence intervals for nonlinear functions, with applications to a cloud-seeding experiment. *Technometrics*, 20(3):227–230, August 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268129`.

Draper:1979:RRJ

[DV79] Norman R. Draper and R. Craig Van Nostrand. Ridge regression and James-Stein estimation: review and comments. *Technometrics*, 21(4):451–466, November 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268284`.

Davenport:1972:TEP

[DW72] James M. Davenport and J. T. Webster. Type-I error and power of a test involving a Satterthwaite's approximate F-statistic. *Technometrics*, 14(3):555–569, August 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267284`.

Davenport:1973:CSA

[DW73] James M. Davenport and J. T. Webster. A comparison of some approximate F-tests. *Technometrics*, 15(4):779–789, November 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267388`.

Dyer:1970:NRS

[DY70] M. R. Dyer and D. H. Young. A note on the reliability of a system with spares which operates at discrete times. *Technomet-*

rics, 12(3):702–705, August 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267217`.

Dyer:1973:ESP

[Dye73] D. D. Dyer. Estimation of the scale parameter of the chi distribution based on sample quantiles. *Technometrics*, 15(3):489–496, August 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266854`.

Dyer:1974:BRB

[Dye74] Alan R. Dyer. Book review: *Introduction to Statistics* by Ronald E. Walpole. *Technometrics*, 16(4):633–634, November 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267620`.

Dykstra:1971:AED

[Dyk71] Otto Dykstra, Jr. The augmentation of experimental data to maximize $|X'X|$. *Technometrics*, 13(3):682–688, August 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267180`.

Dykstra:1976:BRB

[Dyk76] Otto Dykstra, Jr. Book review: *Statistics: An Introduction* by Harold J. Larson. *Technometrics*, 18(4):502, November 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268670`.

Easterling:1972:BRB

[Eas72] Robert G. Easterling. Book review: *Reliability Mathematics: Fundamentals; Practices; Procedures* by Bertram L. Amstadter. *Technometrics*, 14(1):232–234, February 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266936`.

Easterling:1976:GFP

[Eas76] Robert G. Easterling. Goodness of fit and parameter estimation. *Technometrics*, 18(1):1–9, February 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267910`.

Easterling:1978:DCI

[Eas78] Robert G. Easterling. Discussion of: “Confidence Interval Estimation for the Weibull and Extreme Value Distributions”. *Technometrics*, 20(4):365–368, November 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267634`. See [Law78].

Engelhardt:1973:SCC

[EB73] Max Engelhardt and Lee J. Bain. Some complete and censored sampling results for the Weibull or extreme-value distribution. *Technometrics*, 15(3):541–549, August 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266859`.

Engelhardt:1974:SRP

[EB74] Max Engelhardt and Lee J. Bain. Some results on point estimation for the two-parameter Weibull or extreme-value distribution. *Technometrics*, 16(1):49–56, February 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267491`.

Engelhardt:1975:TTP

[EB75] Max Engelhardt and Lee J. Bain. Tests of two-parameter exponentiality against three-parameter Weibull alternatives. *Technometrics*, 17(3):353–356, August 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268073`.

Engelhardt:1977:SSP

[EB77a] Max Engelhardt and Lee J. Bain. Simplified statistical procedures for the Weibull or extreme-value distribution. *Technometrics*, 19(3):323–331, August 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267703`.

Engelhardt:1977:UMP

[EB77b] Max Engelhardt and Lee J. Bain. Uniformly most powerful unbiased tests on the scale parameter of a gamma distribution with a nuisance shape parameter. *Technometrics*, 19(1):77–81, February 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268258`.

Engelhardt:1978:COU

[EB78a] Max Engelhardt and Lee J. Bain. Construction of optimal unbiased inference procedures for the parameters of the gamma distribution. *Technometrics*, 20(4):485–489, November 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267649`.

Engelhardt:1978:PIW

[EB78b] Max Engelhardt and Lee J. Bain. Prediction intervals for the Weibull process. *Technometrics*, 20(2):167–169, May 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268709`.

Engelhardt:1978:TLC

[EB78c] Max Engelhardt and Lee J. Bain. Tolerance limits and confidence limits on reliability for the two-parameter exponential distribution. *Technometrics*, 20(1):37–39, February 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268159`.

Engelhardt:1979:PLT

[EB79] Max Engelhardt and Lee J. Bain. Prediction limits and two-sample problems with complete or censored Weibull data. *Technometrics*, 21(2):233–237, May 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268521`.

Edelman:1974:TSN

[Ede74] David A. Edelman. Three-stage nested designs with composited samples. *Technometrics*, 16(3):409–417, August 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267671`.

Ehrenfeld:1972:GSS

[Ehr72] S. Ehrenfeld. On group sequential sampling. *Technometrics*, 14(1):167–174, February 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266928`.

Ehrenfeld:1977:BRB

[Ehr77] Sylrain Ehrenfeld. Book review: *Sequential Methods in Statistics* by G. B. Wetherill. *Technometrics*, 19(2):220, May 1977. CODEN

TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268640`. See addendum and corrigendum [Ano77a].

Elder:1974:DSL

[Eld74] Robert S. Elder. Double sampling for lot average. *Technometrics*, 16(3):435–439, August 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267674`.

Ellingsen:1976:DPE

[Ell76] Walter R. Ellingsen. Discussion of: “Parameter Estimation with Closed-Loop Operating Data”. *Technometrics*, 18(4):381–384, November 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268652`. See [BM76].

Ellerton:1978:REA

[Ell78] Roger R. W. Ellerton. Is the regression equation adequate?—a generalization. *Technometrics*, 20(3):313–315, August 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268140`.

Engelhardt:1975:SEP

[Eng75] Max Engelhardt. On simple estimation of the parameters of the Weibull or extreme-value distribution. *Technometrics*, 17(3):369–374, August 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268076`.

Enslein:1976:BRB

[Ens76] Kurt Enslein. Book review: *Cluster Analysis Algorithms for Classification of Objects and Data Reduction* by Helmuth Späth. *Technometrics*, 18(2):240–241, May 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267534`.

Enslein:1977:BRB

[Ens77] Kurt Enslein. Book review: *Einfuhrung in die Mathematische Statistik II, Anwendungen* by D. Rasch. *Technometrics*, 19(4):517, November 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267899`.

Enslein:1978:BRB

[Ens78] Kurt Enslein. Book review: *The Natural History of Chronic Bronchitis and Emphysema: An Eight Year Study of Early Chronic Obstructive Lung Disease in Working Men in London* by Charles Fletcher; Richard Peto; Cecily Tinker; Frank E. Speizer. *Technometrics*, 20(2):212–213, May 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268722`.

Easterling:1971:CCS

[EP71] R. G. Easterling and R. R. Prairie. Combining component and system information. *Technometrics*, 13(2):271–280, May 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266789`.

Ericson:1972:BRB

[Eri72] W. A. Ericson. Book review: *Introduction to Mathematical Statistics* by Paul G. Hoel. *Technometrics*, 14(3):807–809, August 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267313`.

Evans:1971:ANI

[Eva71] David H. Evans. An application of numerical integration techniques to statistical tolerancing, II: A note on the error. *Technometrics*, 13(2):315–324, May 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266793`.

Evans:1972:ANI

[Eva72] David H. Evans. An application of numerical integration techniques to statistical tolerancing, III: General distributions. *Technometrics*, 14(1):23–35, February 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266915`.

Evans:1979:CAE

[Eva79] James W. Evans. Computer augmentation of experimental designs to maximize $|X'X|$. *Technometrics*, 21(3):321–330, August 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267754`.

Falls:1970:EPC

[Fal70] Lee W. Falls. Estimation of parameters in compound Weibull distributions. *Technometrics*, 12(2):399–407, May 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267245`.

Farebrother:1975:MMS

[Far75] R. W. Farebrother. The minimum mean square error linear estimator and ridge regression. *Technometrics*, 17(1):127–128, February 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268010`.

Farebrother:1978:PRR

[Far78] R. W. Farebrother. Partitioned ridge regression. *Technometrics*, 20(2):121–122, May 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268702`.

Faulkenberry:1970:NTL

[Fau70] G. David Faulkenberry. A note on tolerance limits for a binomial distribution. *Technometrics*, 12(4):920–922, November 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267337`.

Folks:1975:IOC

[FB75] J. Leroy Folks and Richard H. Browne. On the interpretation of the observed confidence in certain reliability assessments. *Technometrics*, 17(3):287–290, August 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268062`.

Faulkenberry:1970:SST

[FD70] G. David Faulkenberry and James C. Daly. Sample size for tolerance limits on a normal distribution. *Technometrics*, 12(4):813–821, November 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267327`.

Feder:1974:BRB

[Fed74a] Paul I. Feder. Book review: *Probability and Statistics for Engineers and Scientists* by R. E. Walpole; R. H. Myers. *Technometrics*, 16(2):325, May 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267957`.

Feder:1974:GTS

[Fed74b] Paul I. Feder. Graphical techniques in statistical data analysis: Tools for extracting information from data. *Technometrics*, 16(2):287–299, May 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267951`.

Feder:1975:SRG

[Fed75] Paul I. Feder. Studentized range graph paper: A graphical tool for the comparison of treatment means. *Technometrics*, 17(2):181–188, May 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268350`.

Feder:1977:BRB

[Fed77] Paul I. Feder. Book review: *The Analysis of Categorical Data* by R. L. Plackett. *Technometrics*, 19(4):515–516, November 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267896`.

Fung:1979:DSC

[FH79] Conrad A. Fung and William G. Hunter. Discussion of: "Statistical Comparison of Multiple Analytic Procedures: Application to Clinical Chemistry". *Technometrics*, 21(4):411–416, November 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268279`. See [LSYF79].

Fienberg:1973:BRB

[Fie73] Stephen E. Fienberg. Book review: *Statistical Papers of George Udny Yule (1871–1951)* by Alan Stuart; Maurice G. Kendall; George Udny Yule. *Technometrics*, 15(3):647–648, August 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266873`.

Filliben:1975:PPC

[Fil75] James J. Filliben. The probability plot correlation coefficient test for normality. *Technometrics*, 17(1):111–117, February 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268008`. See corrigendum [Ano75e].

Fink:1975:BRB

[Fin75] James P. Fink. Book review: *Elementary Differential Equations* by Earl D. Rainville; Phillip E. Bedient. *Technometrics*, 17(2):278–279,

May 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268372`.

Finkelstein:1976:CBP

[Fin76] J. M. Finkelstein. Confidence bounds on the parameters of the Weibull process. *Technometrics*, 18(1):115–117, February 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267924`.

Frawley:1971:TLB

[FKRO71] W. H. Frawley, C. H. Kapadia, J. N. K. Rao, and D. B. Owen. Tolerance limits based on range and mean range. *Technometrics*, 13(3):651–656, August 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267175`.

Fleiss:1971:LE

[Fle71] Joseph L. Fleiss. Letter to the Editor. *Technometrics*, 13(1):217, February 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267097`.

Flehinger:1976:BRB

[Fle76] B. J. Flehinger. Book review: *Sequential Medical Trials* by P. Armitage. *Technometrics*, 18(3):362, August 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268748`.

Feder:1971:AVM

[FM71] P. I. Feder and Reiji Mezaki. An application of variational methods to experimental design. *Technometrics*, 13(4):771–793, November 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266954`.

Fertig:1977:OSP

[FM77] Kenneth W. Fertig and Nancy R. Mann. One-sided prediction intervals for at least p out of m future observations from a normal population. *Technometrics*, 19(2):167–177, May 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268626`.

Forthofer:1971:BRB

[For71] Ron Forthofer. Book review: *Regression and Econometric Methods* by David S. Huang. *Technometrics*, 13(2):449, May 1971. CODEN

TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266807`.

Forsythe:1972:RES

[For72] Alan B. Forsythe. Robust estimation of straight line regression coefficients by minimizing p th power deviations. *Technometrics*, 14(1):159–166, February 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266927`.

Forthofer:1973:BRB

[For73] R. Forthofer. Book review: *Linear Programming and Related Techniques* by C. van de Panne. *Technometrics*, 15(3):653, August 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266878`.

Farewell:1977:SDS

[FP77] Vern T. Farewell and Ross L. Prentice. A study of distributional shape in life testing. *Technometrics*, 19(1):69–75, February 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268257`.

Fercho:1972:SSP

[FR72] W. W. Fercho and L. J. Ringer. Small sample power of some tests of the constant failure rate. *Technometrics*, 14(3):713–724, August 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267299`.

Frane:1977:NCT

[Fra77] James W. Frane. A note on checking tolerance in matrix inversion and regression. *Technometrics*, 19(4):513–514, November 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267895`.

Freeman:1973:BRBa

[Fre73a] Jean L. Freeman. Book review: *Selected Readings in Econometrics from Econometrica* by John W. Hooper; Marc Nerlove. *Technometrics*, 15(1):203, February 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266846`.

Freeman:1973:BRBb

[Fre73b] Jean L. Freeman. Book review: *Sixth Berkeley Symposium on Mathematical Statistics and Probability, Volume I* by Lucien Le Cam; Jerzy Neyman; Elizabeth L. Scott. *Technometrics*, 15(2):425–426, May 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267010`.

Freeman:1973:BRBc

[Fre73c] Jean L. Freeman. Book review: *Stochastic Point Processes: Statistical Analysis, Theory, and Applications* by Peter A. W. Lewis. *Technometrics*, 15(4):943–944, November 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267411`.

Freeman:1974:BRBb

[Fre74a] Daniel H. Freeman, Jr. Book review: *Distributions in Statistics: Continuous Multivariate Distributions* by Norman L. Johnson; Samuel Kotz. *Technometrics*, 16(4):636, November 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267626`.

Freeman:1974:BRBa

[Fre74b] Daniel H. Freeman, Jr. Book review: *Statistical Decomposition Analysis* by Henri Theil. *Technometrics*, 16(2):328, May 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267962`.

Freeman:1975:BRB

[Fre75] Daniel H. Freeman, Jr. Book review: *Regression Estimation from Grouped Observations* by Y. Haitovsky. *Technometrics*, 17(1):142, February 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268021`.

Fuchs:1978:TSL

[Fuc78] Camil Fuchs. On test sizes in linear models for transformed variables. *Technometrics*, 20(3):291–299, August 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268138`.

Furnival:1971:APR

[Fur71] George M. Furnival. All possible regressions with less computation. *Technometrics*, 13(2):403–408, May 1971. CODEN TCMTA2. ISSN

0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266801`.

Fraser:1972:BRS

[FW72] D. A. S. Fraser and J. S. Williams. On the *Technometrics* review of “The Structure of Inference”. *Technometrics*, 14(3):809–810, August 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267314`. See [Wil70].

Furnival:1974:RLB

[FW74] George M. Furnival and Robert W. Wilson, Jr. Regressions by leaps and bounds. *Technometrics*, 16(4):499–511, November 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267601`.

Gafarian:1978:CBM

[Gaf78] A. V. Gafarian. Confidence bands in multivariate polynomial regression. *Technometrics*, 20(2):141–149, May 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268705`.

Gart:1971:OCT

[Gar71] John J. Gart. On the ordering of contingency tables for significance tests. *Technometrics*, 13(4):910–911, November 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266971`.

Gardiner:1974:NE

[Gar74] Donald A. Gardiner. New Editor. *Technometrics*, 16(2):145, May 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267935`.

Grubbs:1972:ESS

[GB72] Frank E. Grubbs and Glenn Beck. Extension of sample sizes and percentage points for significance tests of outlying observations. *Technometrics*, 14(4):847–854, November 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267134`. See corrigendum [Ano73g].

Greenstreet:1974:PTE

[GC74] Richard L. Greenstreet and Robert J. Connor. Power of tests for equality of covariance matrices. *Technometrics*, 16(1):27–30, February 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267488`.

Gaver:1979:JEC

[GC79] Donald P. Gaver and Boyer B. Chu. Jackknife estimates of component and system availability. *Technometrics*, 21(4):443–450, November 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268283`.

Guttman:1978:CHU

[GDF78] Irwin Guttman, Rudolf Dutter, and Peter R. Freeman. Care and handling of univariate outliers in the general linear model to detect spuriosity—a Bayesian approach. *Technometrics*, 20(2):187–193, May 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268712`.

Gentleman:1977:BRB

[Gen77] Jane F. Gentleman. Book review: *Data Reduction. Analysing and Interpreting Statistical Data* by A. S. C. Ehrenberg. *Technometrics*, 19(4):516, November 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267897`.

George:1972:BRB

[Geo72] Stephen L. George. Book review: *A First Course in Statistics* by F. N. David. *Technometrics*, 14(4):983–984, November 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267155`.

Gerig:1975:BRB

[Ger75] Thomas M. Gerig. Book review: *Multivariate Analysis: Techniques for Educational and Psychological Research* by Maurice M. Tatsuoka. *Technometrics*, 17(1):141–142, February 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268020`.

Gnanadesikan:1970:SPM

[GG70a] Mrudulla Gnanadesikan and S. S. Gupta. A selection procedure for multivariate normal distributions in terms of the generalized variances. *Technometrics*, 12(1):103–117, February 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267355`.

Goldsmith:1970:ACD

[GG70b] Charles H. Goldsmith and David W. Gaylor. Three stage nested designs for estimating variance components. *Technometrics*, 12(3):487–498, August 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267198`. ASQC Chemical Division Technical Conference 1968 Prize Winning Paper.

Gaver:1970:CCS

[GH70] Donald P. Gaver, Jr. and David G. Hoel. Comparison of certain small-sample Poisson probability estimates. *Technometrics*, 12(4):835–850, November 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267329`.

Guenther:1975:LE

[GH75] William C. Guenther and M. A. Hamdan. Letters to the Editor: "An improved gamma approximation to the negative binomial" (Technometrics **16** (1974), 621–624) by D. J. Best and P. G. Gipps and "A simple approximation to the negative binomial (and regular binomial)" (ibid. **14** (1972), no. 2, 385–389) by W. C. Guenther. *Technometrics*, 17(4):518–519, November 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268449`.

Goodnight:1979:SAT

[GH79] J. H. Goodnight and W. J. Hemmerle. A simplified algorithm for the W transformation in variance component estimation. *Technometrics*, 21(2):265–267, May 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268527`.

Golub:1979:GCV

[GHW79] Gene H. Golub, Michael T. Heath, and Grace Wahba. Generalized cross-validation as a method for choosing a good ridge parameter. *Technometrics*, 21(2):215–223, May 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268518`. Cited in Åke Björck's bibliography on least squares, which is available at `ftp://math.liu.se/pub/references`. Reprinted in [CGO07].

Gibbons:1974:BRB

[Gib74] Jean D. Gibbons. Book review: *Nonparametric Statistical Methods* by M. Hollander; D. A. Wolfe. *Technometrics*, 16(3):477–478, August 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267682`.

Giesbrecht:1974:BRB

[Gie74] Francis Giesbrecht. Book review: *GPSS Primer* by Stanley Greenberg. *Technometrics*, 16(1):142, February 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267512`.

Gillings:1974:BRB

[Gil74] Dennis Gillings. Book review: *Introduction to Stochastic Processes* by Paul G. Hoel; Sidney C. Port; Charles J. Stone. *Technometrics*, 16(1):137–138, February 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267505`.

Galil:1977:CBD

[GK77a] Z. Galil and J. Kiefer. Comparison of Box–Draper and D-optimum designs for experiments with mixtures. *Technometrics*, 19(4):441–444, November 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267883`.

Galil:1977:CSD

[GK77b] Z. Galil and J. Kiefer. Comparison of simplex designs for quadratic mixture models. *Technometrics*, 19(4):445–453, November 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267884`.

Gentle:1975:DSB

[GKS75] James E. Gentle, Ralph L. Kodell, and Patricia L. Smith. On the distribution of the Studentized bivariate range. *Technometrics*, 17(4):501–505, November 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268439`.

Glenn:1977:BRB

[Gle77] William A. Glenn. Book review: *Statistics in Research* by Bernard Ostle; Richard W. Mensing. *Technometrics*, 19(1):103, February 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268266`.

Gleason:1978:BRB

[Gle78] Terry C. Gleason. Book review: *Survey and Opinion Research: Procedures for Processing and Analysis* by John A. Sonquist; William C. Dunkelberg. *Technometrics*, 20(4):502, November 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267654`.

Goldman:1974:RPP

[GLV74] Aaron S. Goldman, Homer D. Lewis, and William M. Visscher. Random packing of particles: Simulation with a one dimensional parking model. *Technometrics*, 16(2):301–309, May 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267952`.

Gunst:1979:SCE

[GM79] Richard F. Gunst and Robert L. Mason. Some considerations in the evaluation of alternate prediction equations. *Technometrics*, 21(1):55–63, February 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268580`.

Griffiths:1975:LE

[GMD$^+$75] David Griffiths, Alan Miller, Norman R. Draper, Michael J. Box, and Edward R. Jones. Letters to the Editor. *Technometrics*, 17(2):281–282, May 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268373`.

Goldsmith:1974:BRB

[Gol74] C. H. Goldsmith. Book review: *Probability and Statistical Inference* by J. K. Wani. *Technometrics*, 16(1):140–141, February 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267509`.

Good:1970:ICM

[Goo70] I. J. Good. The inverse of a centrosymmetric matrix. *Technometrics*, 12(4):925–928, November 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267339`.

Goodman:1971:AMC

[Goo71] Leo A. Goodman. The analysis of multidimensional contingency tables: Stepwise procedures and direct estimation methods for building models for multiple classifications. *Technometrics*, 13(1):33–61, February 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267074`.

Good:1975:BRB

[Goo75] I. J. Good. Book review: *An Introduction to Bayesian Inference in Econometrics* by Arnold Zellner. *Technometrics*, 17(1):137–138, February 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268014`. See amendment [Goo76].

Good:1976:ARA

[Goo76] I. J. Good. Amendment to review of Arnold Zellner's *An Introduction to Bayesian Inference in Econometrics*. *Technometrics*, 18(1):123, February 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267931`. See [Goo75].

Gorman:1976:BRB

[Gor76] John W. Gorman. Book review: *Optimal Subset Selection-Multiple Regression, Interdependence and Optimal Network Algorithms* by D. E. Boyce; A. Farhi; R. Weischedel. *Technometrics*, 18(2):239–240, May 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267530`.

Gould:1973:BRB

[Gou73] A. Lawrence Gould. Book review: *Probit Analysis* by D. J. Finney. *Technometrics*, 15(1):197–199, February 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266841`.

Gower:1972:BRB

[Gow72] J. C. Gower. Book review: *Generalized Inverse Matrices* by T. L. Boullion; P. L. Odell. *Technometrics*, 14(3):806–807, August 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267311`.

Guttman:1973:LSE

[GPS73] Irwin Guttman, Victor Pereyra, and Hugo D. Scolnik. Least squares estimation for a class of non-linear models. *Technometrics*, 15(2):209–218, May 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266982`.

Guenther:1976:OSC

[GPU76] William C. Guenther, S. A. Patil, and V. R. R. Uppuluri. One-sided β-content tolerance factors for the two-parameter exponential distribution. *Technometrics*, 18(3):333–340, August 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268742`.

Graff:1972:GTP

[GR72] Lois E. Graff and Robert Roeloffs. Group testing in the presence of test error; an extension of the Dorfman procedure. *Technometrics*, 14(1):113–122, February 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266923`.

Grandage:1972:BRB

[Gra72] A. Grandage. Book review: *Introductory Engineering Statistics* by Irwin Guttman; S. S. Wilks; J. Stuart Hunter. *Technometrics*, 14(4):979, November 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267150`.

Greenberg:1970:ALP

[Gre70a] Harvey J. Greenberg. An application of a Lagrangian penalty function to obtain optimal redundancy. *Technometrics*, 12(3):545–552, August 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267201`.

Greenberg:1970:FOS

[Gre70b] Irwin Greenberg. The first occurrence of n successes in N trials. *Technometrics*, 12(3):627–634, August 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267208`.

Green:1971:TDR

[Gre71] J. R. Green. Testing departure from a regression, without using replication. *Technometrics*, 13(3):609–615, August 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267172`.

Gridgeman:1970:CTM

[Gri70] N. T. Gridgeman. A comparison of two methods of analysis of mixtures of normal distributions. *Technometrics*, 12(4):823–833, November 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267328`.

Griffeath:1972:CSD

[Gri72] David S. Griffeath. Computer solution of the discrete maximum entropy problem. *Technometrics*, 14(4):891–897, November 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267137`.

Grizzle:1973:BRB

[Gri73] James E. Grizzle. Book review: *Analysis and Design of Certain Quantitative Multiresponse Experiments* by S. N. Roy; R. Gnanadesikan; J. N. Srivastava. *Technometrics*, 15(1):196–197, February 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266839`.

Griffiths:1979:SIC

[Gri79] David Griffiths. Structural identifiability for compartmental models. *Technometrics*, 21(2):257–259, May 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268525`.

Gross:1971:AES

[Gro71a] Alan J. Gross. The application of exponential smoothing to reliability assessment. *Technometrics*, 13(4):877–883, November 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266964`.

Gross:1971:MPM

[Gro71b] Alan J. Gross. Monotonicity properties of the moments of truncated gamma and Weibull density functions. *Technometrics*, 13(4):851–857, November 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266960`.

Grosh:1972:BSA

[Gro72] Doris Lloyd Grosh. A Bayes sampling allocation scheme for stratified finite populations with hyperbinomial prior distributions. *Technometrics*, 14(3):599–612, August 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267288`.

Groeneveld:1977:BRB

[Gro77] Richard A. Groeneveld. Book review: *Introduction to Statistics and Computer Programming* by Carl F. Kossack; Claudia I. Henschke. *Technometrics*, 19(3):341–342, August 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267705`.

Grubbs:1971:BRB

[Gru71a] F. E. Grubbs. Book review: *Order Statistics* by Herbert A. David. *Technometrics*, 13(3):706–708, August 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267186`.

Grubbs:1971:AFBa

[Gru71b] Frank E. Grubbs. Approximate fiducial bounds for the reliability of a series system for which each component has an exponential time-to-fail distribution. *Technometrics*, 13(4):865–871, November 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266962`.

Grubbs:1971:AFBb

[Gru71c] Frank E. Grubbs. Approximate fiducial bounds on reliability for the two parameter negative exponential distribution. *Technometrics*, 13(4):873–876, November 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266963`.

Grubbs:1973:DNF

[Gru73a] Frank E. Grubbs. Determination of number of failures to control risks of erroneous judgments in exponential life testing. *Technometrics*, 15(1):191–193, February 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266837`.

Grubbs:1973:EMP

[Gru73b] Frank E. Grubbs. Errors of measurement, precision, accuracy and the statistical comparison of measuring instruments. *Technometrics*, 15(1):53–66, February 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266824`.

Guttman:1971:IRD

[GS71] Irwin Guttman and Dennis E. Smith. Investigation of rules for dealing with outliers in small samples from the normal distribution II: Estimation of the variance. *Technometrics*, 13(1):101–111, February 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267078`.

Gualtierotti:1971:BRB

[Gua71] Antonio F. Gualtierotti. Book review: *Gestion de la Qualité: Aspects Économiques et Techniques (Management of Quality: Economical and Theoretical Features)* by L. Larrieu. *Technometrics*, 13(2): 452, May 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266811`.

Guenther:1971:ASN

[Gue71a] William C. Guenther. The average sample number for truncated double sample attribute plans. *Technometrics*, 13(4):811–816, November 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266956`.

Guenther:1971:DSS

[Gue71b] William C. Guenther. On the determination of single sampling attribute plans based upon a linear cost model and a prior distribution. *Technometrics*, 13(3):483–498, August 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267163`. See corrigendum [Ano72g].

Guenther:1972:SAN

[Gue72] William C. Guenther. A simple approximation to the negative binomial (and regular binomial). *Technometrics*, 14(2):385–389, May 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267429`.

Guenther:1974:SSF

[Gue74] William C. Guenther. Sample size formulas for some binomial type problems. *Technometrics*, 16(3):465–467, August 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267679`.

Guenther:1977:EMO

[Gue77] William C. Guenther. An easy method for obtaining percentage points of order statistics. *Technometrics*, 19(3):319–321, August

1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267702`.

Guttman:1973:CHU

[Gut73a] Irwin Guttman. Care and handling of univariate or multivariate outliners in detecting spuriosity: A Bayesian approach. *Technometrics*, 15(4):723–738, November 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267384`.

Guttman:1973:PPS

[Gut73b] Irwin Guttman. Premium and protection of several procedures for dealing with outliers when sample sizes are moderate to large. *Technometrics*, 15(2):385–404, May 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266997`.

Goel:1971:DRC

[GW71] Amrit L. Goel and S. M. Wu. Determination of A. R. L. and a contour nomogram for Cusum charts to control normal mean. *Technometrics*, 13(2):221–230, May 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266785`.

Gentleman:1975:DOT

[GW75] J. F. Gentleman and M. B. Wilk. Detecting outliers in a two-way table: I. Statistical behavior of residuals. *Technometrics*, 17(1):1–14, February 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267994`.

Gunst:1976:CLS

[GWM76] R. F. Gunst, J. T. Webster, and R. L. Mason. A comparison of least squares and latent root regression estimators. *Technometrics*, 18(1):75–83, February 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267919`.

Gabriel:1979:LRA

[GZ79] K. Ruben Gabriel and S. Zamir. Lower rank approximation of matrices by least squares with any choice of weights. *Technometrics*, 21(4):489–498, November 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268288`. See corrigenda [Ano80a].

Hackney:1978:BRB

[Hac78] Olga P. Hackney. Book review: *Elementary Probability and Statistical Reasoning* by Howard E. Reinhardt; Don O. Loftsgaarden. *Technometrics*, 20(4):503, November 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267657`.

Hackney:1979:BRB

[Hac79] Olga P. Hackney. Book review: *An Introduction to Probability Theory and Mathematical Statistics* by V. K. Rohatgi. *Technometrics*, 21(3):391, August 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267772`.

Hahn:1972:SPI

[Hah72] Gerald J. Hahn. Simultaneous prediction intervals for a regression model. *Technometrics*, 14(1):203–214, February 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266931`.

Hahn:1975:SPL

[Hah75] Gerald J. Hahn. A simultaneous prediction limit on the means of future samples from an exponential distribution. *Technometrics*, 17(3):341–345, August 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268071`.

Hahn:1977:PID

[Hah77] Gerald J. Hahn. A prediction interval on the difference between two future sample means and its application to a claim of product superiority. *Technometrics*, 19(2):131–134, May 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268622`.

Hahn:1979:BRB

[Hah79] Gerald J. Hahn. Book review: *Regression Analysis by Example* by S. Chatterjee; B. Price. *Technometrics*, 21(2):271–272, May 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268529`.

Halperin:1970:IEL

[Hal70] Max Halperin. On inverse estimation in linear regression. *Technometrics*, 12(4):727–736, November 1970. CODEN TCMTA2. ISSN

0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267319`.

Hald:1977:NDA

[Hal77a] Anders Hald. A note on the determination of attribute sampling plans of given strength. *Technometrics*, 19(2):211–212, May 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268632`.

Haller:1977:BRB

[Hal77b] H. Smith Haller. Book review: *An Introduction to Mathematical Statistics* by H. D. Brunk. *Technometrics*, 19(2):217–218, May 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268634`.

Hall:1979:MVV

[Hal79] James E. Hall. Minimum variance and VOQL sampling plans. *Technometrics*, 21(4):555–565, November 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268296`.

Hamdan:1970:LE

[Ham70] M. A. Hamdan. Letter to the Editor. *Technometrics*, 12(3):719, August 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267225`.

Hamdan:1972:ETB

[Ham72a] M. A. Hamdan. Estimation in the truncated bivariate Poisson distribution. *Technometrics*, 14(1):37–45, February 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266916`.

Hamdan:1972:CCE

[Ham72b] M. A. Hamdan. On a characterization by conditional expectations. *Technometrics*, 14(2):497–499, May 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267438`.

Hamdan:1974:CC

[Ham74] M. A. Hamdan. On the continuity correction. *Technometrics*, 16(4):631–632, November 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267619`. See errata [Ano75f].

Hammood:1975:BRB

[Ham75] Abdul W. Hammood. Book review: *Finite Mathematics with Business Applications* by J. G. Kemeny; A. Schleifer; J. L. Snell; G. L. Thompson. *Technometrics*, 17(2):276–277, May 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268369`.

Hannan:1973:BRB

[Han73] E. J. Hannan. Book review: *Principles of Econometrics* by Henri Theil. *Technometrics*, 15(1):195–196, February 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266838`.

Hanumara:1975:EIM

[Han75] R. Choudary Hanumara. Estimating imprecisions of measuring instruments. *Technometrics*, 17(3):299–302, August 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268064`.

Harris:1970:BRB

[Har70] Bernard Harris. Book review: *A Graduate Course in Probability* by Howard G. Tucker. *Technometrics*, 12(1):180, February 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267373`.

Harter:1971:MPP

[Har71] H. Leon Harter. More percentage points of the Pearson Type III distribution. *Technometrics*, 13(1):203–204, February 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267089`.

Hartley:1972:BRB

[Har72] H. O. Hartley. Book review: *Selected Tables in Mathematical Statistics, Volume I* by H. L. Harter; D. B. Owen. *Technometrics*, 14(3):803, August 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267307`.

Harter:1973:LRT

[Har73a] H. Leon Harter. [Likelihood Ratio Test for Discrimination between Two Models with Unknown Location and Scale Parameters]: Discussion no. 2. *Technometrics*, 15(1):29–31, February 1973. CODEN

TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266822`. See [DAH73].

Harville:1973:FPL

[Har73b] David A. Harville. Fitting partially linear models by weighted least squares. *Technometrics*, 15(3):509–515, August 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266856`.

Harville:1974:NOA

[Har74] David A. Harville. Nearly optimal allocation of experimental units using observed covariate values. *Technometrics*, 16(4):589–599, November 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267612`.

Harris:1975:BRB

[Har75] Bernard Harris. Book review: *Random Data: Analysis and Measurement Procedures* by Julius S. Bendat; Allan G. Piersol. *Technometrics*, 17(2):271, May 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268362`.

Hare:1977:BRB

[Har77] Lynne B. Hare. Book review: *Elementary Statistical Concepts* by Ronald E. Walpole. *Technometrics*, 19(2):218, May 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268636`.

Hare:1979:DME

[Har79] Lynne B. Hare. Designs for mixture experiments involving process variables. *Technometrics*, 21(2):159–173, May 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268513`.

Hassanein:1972:SEP

[Has72] Khatab M. Hassanein. Simultaneous estimation of the parameters of the extreme value distribution by sample quantiles. *Technometrics*, 14(1):63–70, February 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266918`.

Hawkins:1972:NMS

[Haw72] Richard H. Hawkins. A note on multiple solutions to the mixed distribution problem. *Technometrics*, 14(4):973–976, November 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267147`.

Hawkins:1975:RBR

[Haw75] Douglas M. Hawkins. Relations between ridge regression and eigenanalysis of the augmented correlation matrix. *Technometrics*, 17 (4):477–480, November 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268435`.

Hawkins:1978:LE

[Haw78] Douglas Hawkins. Letter to the Editor. *Technometrics*, 20(2):218, May 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268730`.

Hayes:1973:BRB

[Hay73] Robert M. Hayes. Book review: *The Evaluation of Information Services and Products* by Donald W. King; Edward C. Bryant. *Technometrics*, 15(4):940–941, November 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267408`.

Hewett:1971:ISM

[HB71] John E. Hewett and William G. Bulgren. Inequalities for some multivariate f-distributions with applications. *Technometrics*, 13(2):397–402, May 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266800`.

Hemmerle:1978:ECG

[HB78] W. J. Hemmerle and T. F. Brantle. Explicit and constrained generalized ridge estimation. *Technometrics*, 20(2):109–120, May 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268701`.

Hager:1971:REG

[HBA71] Harold W. Hager, Lee J. Bain, and Charles E. Antle. Reliability estimation for the generalized gamma distribution and robustness of the Weibull model. *Technometrics*, 13(3):547–557, August 1971.

CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267167`.

Haynes:1970:WTL

[HD70] Tyler Haynes and Edward A. Davis. Waiting-time for a large gap in an alternating renewal process. *Technometrics*, 12(3):697–699, August 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267215`.

Hearne:1978:BRB

[Hea78] F. Terry Hearne. Book review: *BMDP-77 Biomedical Computer Programs, P Series* by W. J. Dixon; M. B. Brown. *Technometrics*, 20(3): 320, August 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268144`.

Hedayat:1971:STM

[Hed71] A. Hedayat. A set of three mutually orthogonal Latin squares of order 15. *Technometrics*, 13(3):696–698, August 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267183`.

Heil:1976:BRB

[Hei76] Peter F. Heil. Book review: *Survival Distributions: Reliability Applications in the Biomedical Sciences* by Alan J. Gross; Virginia A. Clark. *Technometrics*, 18(4):501, November 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268667`.

Heil:1978:BRB

[Hei78] Peter F. Heil. Book review: *Probability and Statistical Inference* by Robert V. Hogg; Elliot A. Tanis. *Technometrics*, 20(4):503, November 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267656`.

Heil:1979:BRB

[Hei79] Peter F. Heil. Book review: *Introduction to Probability and Statistics* by Narayan C. Giri. *Technometrics*, 21(1):135, February 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268593`.

Helms:1971:BRBa

[Hel71a] Ronald W. Helms. Book review: *Approximations to the Poisson, Binomial, and Hypergeometric Distribution Functions* by W. Molenaar.

Technometrics, 13(1):214, February 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267096`.

Helms:1971:BRBb

[Hel71b] Ronald W. Helms. Book review: *Artificial Intelligence* by Bernard Meltzer. *Technometrics*, 13(2):451–452, May 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266810`.

Helms:1974:AEV

[Hel74] Ronald W. Helms. The average estimated variance criterion for the selection-of-variables problem in general linear models. *Technometrics*, 16(2):261–273, May 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267949`.

Hemmerle:1975:ESG

[Hem75] William J. Hemmerle. An explicit solution for generalized ridge regression. *Technometrics*, 17(3):309–314, August 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268066`.

Herbach:1970:EAE

[Her70] L. H. Herbach. An exact asymptotically efficient confidence bound for reliability in the case of the Gumbel distribution. *Technometrics*, 12(3):700–701, August 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267216`.

Haseman:1973:ANI

[HG73] J. K. Haseman and D. W. Gaylor. An algorithm for non-iterative estimation of multiple missing values for crossed classifications. *Technometrics*, 15(3):631–636, August 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266869`.

Hunter:1978:BAE

[HG78] A. J. Hunter and H. J. Griffiths. Bayesian approach to estimation of insect population size. *Technometrics*, 20(3):231–234, August 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268130`.

Hemmerle:1973:CML

[HH73] W. J. Hemmerle and H. O. Hartley. Computing maximum likelihood estimates for the mixed A. O. V. model using the W transformation. *Technometrics*, 15(4):819–831, November 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267392`.

Hill:1974:DES

[HH74] William J. Hill and William G. Hunter. Design of experiments for subsets of parameters. *Technometrics*, 16(3):425–434, August 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267673`.

Habbema:1977:SVD

[HH77] J. D. F. Habbema and J. Hermans. Selection of variables in discriminant analysis by F-statistic and error rate. *Technometrics*, 19(4):487–493, November 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267890`.

Hill:1974:BRB

[Hil74] Bruce M. Hill. Book review: *Bayesian Inference in Statistical Analysis* by George E. P. Box; George C. Tiao. *Technometrics*, 16(3):478–479, August 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267683`.

Hill:1978:RED

[Hil78] Peter D. H. Hill. A review of experimental design procedures for regression model discrimination. *Technometrics*, 20(1):15–21, February 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268155`.

Hines:1977:CSW

[Hin77a] W. G. S. Hines. A comparison of some weighted averages. *Technometrics*, 19(3):313–318, August 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267701`.

Hinkley:1977:JUS

[Hin77b] David V. Hinkley. Jackknifing in unbalanced situations. *Technometrics*, 19(3):285–292, August 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267698`.

Holms:1973:LE

[HJ73] Arthur G. Holms and Eric E. Johnson. Letters to the Editor. *Technometrics*, 15(4):947, November 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267413`.

Hegemann:1976:ATW

[HJ76] Victor Hegemann and Dallas E. Johnson. On analyzing two-way AoV data with interaction. *Technometrics*, 18(3):273–281, August 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268736`.

Hill:1978:TAR

[HJF78] R. Carter Hill, George G. Judge, and Thomas B. Fomby. On testing the adequacy of a regression model. *Technometrics*, 20(4):491–494, November 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267650`.

Hoerl:1970:RRA

[HK70a] Arthur E. Hoerl and Robert W. Kennard. Ridge regression: Applications to nonorthogonal problems. *Technometrics*, 12(1):69–82, February 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267352`. See [Ano70f].

Hoerl:1970:RRB

[HK70b] Arthur E. Hoerl and Robert W. Kennard. Ridge regression: Biased estimation for nonorthogonal problems. *Technometrics*, 12(1):55–67, February 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267351`.

Hoerl:1975:NPG

[HK75] Arthur E. Hoerl and Robert W. Kennard. A note on a power generalization of ridge regression. *Technometrics*, 17(2):269, May 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268361`.

Hoerl:1977:LEC

[HK77] Arthur E. Hoerl and Robert W. Kennard. Letter to the editor: [Comments on: "Simulation and extension of a minimum mean squared error estimator in comparison with Stein's" (Technometrics **18** (1976), no. 4, 491–496) by H. D. Vinod]. *Technometrics*, 19(1):105, February 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268272`.

Hemmerle:1976:IAT

[HL76] W. J. Hemmerle and J. A. Lorens. Improved algorithm for the W-transform in variance component estimation. *Technometrics*, 18(2):207–211, May 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267524`.

Helms:1971:DIP

[HM71] Ronald W. Helms and Scott E. Michaels. Discussion of invited papers. *Technometrics*, 13(3):477–481, August 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267162`.

Hebble:1972:RRS

[HM72] T. L. Hebble and T. J. Mitchell. “repairing” response surface designs. *Technometrics*, 14(3):767–779, August 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267304`.

Hinich:1973:FNM

[HM73] M. J. Hinich and H. Montes. Fitting a nonstationary model of ionospheric motions. *Technometrics*, 15(4):759–767, November 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267386`.

Hald:1976:AFC

[HM76a] Anders Hald and Uffe Møller. The ASN function for curtailed single sampling by attributes. *Technometrics*, 18(3):307–312, August 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268740`.

Hewett:1976:SAS

[HM76b] John E. Hewett and M. L. Moeschberger. Some approximate simultaneous prediction intervals for reliability analysis. *Technometrics*, 18(2):227–229, May 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267527`.

Hettmansperger:1977:RAB

[HM77] Thomas P. Hettmansperger and Joseph W. McKean. A robust alternative based on ranks to least squares in analyzing linear models. *Technometrics*, 19(3):275–284, August 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267697`.

Hahn:1970:PSC

[HN70] Gerald J. Hahn and Wayne Nelson. A problem in the statistical comparison of measuring devices. *Technometrics*, 12(1):95–102, February 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267354`.

Hocking:1972:CSS

[Hoc72] R. R. Hocking. Criteria for selection of a subset regression: Which one should be used? *Technometrics*, 14(4):967–970, November 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267145`.

Halfon:1977:LE

[HOC$^+$77] Efraim Halfon, R. L. Obenchain, R. Dennis Cook, D. G. Kabe, Richard L. Scheaffer, G. K. Shukla, and William C. Guenther. Letters to the Editor. *Technometrics*, 19(3):348–351, August 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267717`.

Hogg:1974:BRB

[Hog74] Robert V. Hogg. Book review: *Probability and Statistics* by Julius R. Blum; Judah I. Rosenblatt. *Technometrics*, 16(2):326, May 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267958`.

Hoke:1974:ESO

[Hok74] Albert T. Hoke. Economical second-order designs based on irregular fractions of the 3^n factorial. *Technometrics*, 16(3):375–384, August 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267667`.

Holland:1973:BRB

[Hol73] Paul W. Holland. Book review: *Introduction to Bayesian Inference and Decision* by Robert L. Winkler. *Technometrics*, 15(4):938–939,

November 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267406`.

Holland:1975:SRD

[Hol75] Burt S. Holland. Some results on the discretization of continuous probability distributions. *Technometrics*, 17(3):333–339, August 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268070`.

Hooke:1979:DSM

[Hoo79] Robert Hooke. Discussion of: "A Simple Method for Regression Analysis with Censored Data". *Technometrics*, 21(4):433–434, November 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268281`. See [SH79].

Howe:1977:BRB

[How77] William G. Howe. Book review: *Probability and Statistics* by M. H. DeGroot. *Technometrics*, 19(2):218, May 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268635`.

Herman:1971:MLE

[HP71] R. J. Herman and Rusi K. N. Patell. Maximum likelihood estimation for multi-risk model. *Technometrics*, 13(2):385–396, May 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266799`.

Hall:1973:OSP

[HP73] I. J. Hall and R. R. Prairie. One-sided prediction intervals to contain at least m out of k future observations. *Technometrics*, 15(4):897–914, November 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267399`.

Hader:1978:SRC

[HP78] R. J. Hader and Sung H. Park. Slope-rotatable central composite designs. *Technometrics*, 20(4):413–417, November 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267641`.

Hogg:1975:ADF

[HR75] Robert V. Hogg and Ronald H. Randles. Adaptive distribution-free regression methods and their applications. *Technometrics*, 17

(4):399–407, November 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268426`.

Holms:1971:DED

[HS71] Arthur G. Holms and Steven M. Sidik. Design of experiments as "doubly telescoping" sequences of blocks with application to a nuclear reactor experiment. *Technometrics*, 13(3):559–574, August 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267168`.

Hocking:1972:OIM

[HS72] R. R. Hocking and W. B. Smith. Optimum incomplete multinormal samples. *Technometrics*, 14(2):299–307, May 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267422`.

Heller:1973:RSO

[HS73] Nelson B. Heller and Glenn E. Staats. Response surface optimization when experimental factors are subject to costs and constraints. *Technometrics*, 15(1):113–123, February 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266829`.

Hocking:1976:CBE

[HSL76] R. R. Hocking, F. M. Speed, and M. J. Lynn. A class of biased estimators in linear regression. *Technometrics*, 18(4):425–437, November 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268658`.

Hannan:1974:EET

[HT74] E. J. Hannan and P. J. Thomson. Estimating echo times. *Technometrics*, 16(1):77–84, February 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267495`.

Huber:1978:BRB

[Hub78] John Huber. Book review: *Introduction to the Use of Computer Packages for Statistical Analyses* by Richard W. Moore. *Technometrics*, 20(4):504, November 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267659`.

Hultquist:1973:BRB

[Hul73] Robert Hultquist. Book review: *Linear Models* by S. R. Searle. *Technometrics*, 15(2):419, May 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267001`.

Hunt:1970:BRB

[Hun70] Jerry G. Hunt. Book review: *Stochastic Theory of a Risk Business* by Hilary L. Seal. *Technometrics*, 12(1):176–178, February 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267371`.

Hunter:1974:BRB

[Hun74] Jeffrey J. Hunter. Book review: *Problems in Complex Variable Theory* by Jan G. Krzyz. *Technometrics*, 16(3):481–482, August 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267687`.

Haile:1975:CFD

[HW75] Alemayehu Haile and J. T. Webster. A comparison of four designs for estimating the variances of random effects in a two-way classification. *Technometrics*, 17(4):495–500, November 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268438`.

Iman:1979:URT

[IC79] Ronald L. Iman and W. J. Conover. The use of the rank transform in regression. *Technometrics*, 21(4):499–509, November 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268289`. See corrigendum [Ano84].

Iglewicz:1973:AME

[Igl73] Boris Iglewicz. An alternative measure of the efficiency of sequential testing procedures. *Technometrics*, 15(3):571–574, August 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266863`.

Iglewicz:1970:CAP

[IM70] Boris Iglewicz and Raymond H. Myers. Comparisons of approximations to the percentage points of the sample coefficient of variation. *Technometrics*, 12(1):166–169, February 1970. CODEN TCMTA2.

ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267363`.

Inglis:1975:BRB

[Ing75] James Inglis. Book review: *Theoretical Statistics* by D. R. Cox; D. V. Hinkley. *Technometrics*, 17(4):513, November 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268442`.

Inglis:1978:BRBa

[Ing78a] James Inglis. Book review: *A Mathematical Theory of Evidence* by Glenn Shafer. *Technometrics*, 20(1):106, February 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268172`.

Inglis:1978:BRBb

[Ing78b] James Inglis. Book review: *Sufficient Statistics: Selected Contributions* by Vasant S. Hazurbazar; Anant M. Kshirsagar. *Technometrics*, 20(1):106, February 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268173`.

Izenman:1977:SDR

[IR77] Alan J. Izenman and Yosef Rinott. Sequential designs for replacements in exponential life tests. *Technometrics*, 19(4):455–459, November 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267885`.

Ingram:1976:CEA

[IS76] C. R. Ingram and R. L. Scheaffer. On consistent estimation of age replacement intervals. *Technometrics*, 18(2):213–219, May 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267525`.

J:1975:BRBg

[J.75a] J. E. J. Book review: *A Survey of Statistical Design and Linear Models* by J. N. Srivastava. *Technometrics*, 17(4):514–515, November 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268446`.

J:1975:BRBd

[J.75b] J. E. J. Book review: *Applied Statistics* by R. P. Gupta. *Technometrics*, 17(3):389–390, August 1975. CODEN TCMTA2. ISSN

0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268090`.

J:1975:BRBb

[J.75c] J. E. J. Book review: *Multivariate Analysis, a Selected and Abstracted Bibliography 1957–1972* by Kocherlakota Subrahmaniam; Kathleen Subrahmaniam. *Technometrics*, 17(3):386, August 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268084`.

J:1975:BRBa

[J.75d] J. E. J. Book review: *Point Estimation in the Linear Regression Model* by Mario Faliva. *Technometrics*, 17(3):385–386, August 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268083`.

J:1975:BRBf

[J75e] J. E. J. Book review: *Progress in Statistics* by J. Gani; K. Sakradi; I. Vincze. *Technometrics*, 17(3):391–392, August 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268092`. See erratum [Ano76f].

J:1975:BRBh

[J.75f] J. E. J. Book review: *Reliability and Biometry, Statistical Analysis of Lifelength* by F. Proschan; R. J. Serfling. *Technometrics*, 17(4):515–516, November 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268447`.

J:1975:BRBc

[J.75g] J. E. J. Book review: *Selected Tables in Mathematical Statistics, Vol. II* by Institute of Mathematical Statistics; H. L. Harter; D. B. Owen. *Technometrics*, 17(3):386, August 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268085`.

J:1975:BRBe

[J.75h] J. E. J. Book review: *Studies in Bayesian Econometrics and Statistics (In Honor of Leonard J. Savage)* by S. E. Fienberg; A. Zellner. *Technometrics*, 17(3):390–391, August 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268091`.

J:1976:BRBg

[J.76a] J. E. J. Book review: *Contributions to Applied Statistics* by W. J. Ziegler. *Technometrics*, 18(3):363, August 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268750`.

J:1976:BRBb

[J.76b] J. E. J. Book review: *Developments in Field Experiment Design and Analysis* by V. J. Bofinger; J. L. Wheeler. *Technometrics*, 18(1):122, February 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267929`.

J:1976:BRBa

[J.76c] J. E. J. Book review: *Elementary Statistics* by G. A. F. Seber. *Technometrics*, 18(1):120–121, February 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267926`.

J:1976:BRBd

[J.76d] J. E. J. Book review: *Multivariate Statistical Methods: Among-Groups Covariation* by W. R. Atchley; E. H. Bryant. *Technometrics*, 18(2):241, May 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267535`.

J:1976:BRBe

[J.76e] J. E. J. Book review: *Multivariate Statistical Methods: Within-Groups Covariation* by E. H. Bryant; W. R. Atchley. *Technometrics*, 18(2):241–242, May 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267536`.

J:1976:BRBf

[J.76f] J. E. J. Book review: *Probability, Statistics and Time: A Collection of Essays* by M. S. Bartlett. *Technometrics*, 18(3):362, August 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268749`.

J:1976:BRBc

[J.76g] J. E. J. Book review: *Sample Size Choice; Charts for Experiments with Linear Models* by R. E. Odeh; M. Fox. *Technometrics*, 18(2):240, May 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267531`.

J:1976:BRBi

[J.76h] J. E. J. Book review: *Selected Tables in Mathematical Statistics, Vol. 3* by The Institute of Mathematical Statistics; H. L. Harter; D. B. Owen. *Technometrics*, 18(4):502–503, November 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268671`.

J:1976:BRBh

[J.76i] J. E. J. Book review: *The Delphi Method: Techniques and Applications* by H. A. Linstone; M. Turoff. *Technometrics*, 18(3):363–364, August 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268751`.

J:1977:BRBn

[J.77a] J. E. J. Book review: *Advances in Operations Research* by Marc Roubens. *Technometrics*, 19(4):519–520, November 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267904`.

J:1977:BRBa

[J.77b] J. E. J. Book review: *An Annotated Bibliography on Methods for Non-Linear Least Squares Computations Including Test Problems* by John C. Nash. *Technometrics*, 19(1):102–103, February 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268265`.

J:1977:BRBf

[J.77c] J. E. J. Book review: *Econometrics* by Peter Schmidt. *Technometrics*, 19(2):219, May 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268638`.

J:1977:BRBb

[J.77d] J. E. J. Book review: *Index to Statistics and Probability: Citation Index* by John W. Tukey. *Technometrics*, 19(1):103, February 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268267`.

J:1977:BRBd

[J.77e] J. E. J. Book review: *Index to Statistics and Probability: Locations and Authors* by I. C. Ross; J. W. Tukey. *Technometrics*, 19(1):104,

February 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268269`.

J:1977:BRBc

[J.77f] J. E. J. Book review: *Index to Statistics and Probability: Permuted Titles* by I. C. Ross; J. W. Tukey. *Technometrics*, 19(1):104, February 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268268`.

J:1977:BRBi

[J.77g] J. E. J. Book review: *Multiple Hypergeometric Functions and Applications* by Harold Exton. *Technometrics*, 19(3):347, August 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267715`.

J:1977:BRBm

[J.77h] J. E. J. Book review: *Multivariate Analysis IV* by P. R. Krishnaiah. *Technometrics*, 19(4):518–519, November 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267903`.

J:1977:BRBk

[J.77i] J. E. J. Book review: *Optimal Strategies in Sports* by Shaul P. Ladany; Robert E. Machol. *Technometrics*, 19(4):517–518, November 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267901`.

J:1977:BRBh

[J.77j] J. E. J. Book review: *Reliability and Fault Tree Analysis* by R. E. Barlow; J. B. Fussell; N. D. Singpurwalla. *Technometrics*, 19(3):346–347, August 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267714`.

J:1977:BRBl

[J.77k] J. E. J. Book review: *Selected Tables in Mathematical Statistics, Volume 4* by Institute of Mathematical Statistics; D. B. Owen; R. E. Odeh. *Technometrics*, 19(4):518, November 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267902`.

J:1977:BRBe

[J.77l] J. E. J. Book review: *Studies in Probability and Statistics: Papers in Honour of Edwin J. G. Pitman* by E. J. Williams. *Techno-*

metrics, 19(1):104, February 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268270`.

J:1977:BRBj

[J.77m] J. E. J. Book review: *The Analysis of Survey Data* by C. A. O'Muircheartaigh; C. Payne. *Technometrics*, 19(4):517, November 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267900`.

J:1977:BRBg

[J.77n] J. E. J. Book review: *Theory and Applications of Reliability* by C. P. Tsokos; I. N. Shimi. *Technometrics*, 19(3):345–346, August 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267713`.

J:1977:RBSa

[J.77o] J. E. J. Review: *Index to Statistics and Probability: Citation Index*, by John W. Tukey. *Technometrics*, 19(1):103, February 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268267`.

J:1977:RBSc

[J.77p] J. E. J. Review: *Index to Statistics and Probability: Location and Authors*, by I. C. Ross and J. W. Tukey. *Technometrics*, 19(1):104, February 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268269`.

J:1977:RBSb

[J.77q] J. E. J. Review: *Index to Statistics and Probability: Permuted Titles*, by I. C. Ross and J. W. Tukey. *Technometrics*, 19(1):104, February 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268268`.

J:1978:BRBp

[J.78a] J. E. J. Book review: *Applications of Statistics* by P. R. Krishnaiah. *Technometrics*, 20(3):322–323, August 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268148`.

J:1978:BRBo

[J.78b] J. E. J. Book review: *Conflicting Objectives in Decisions* by D. E. Bell; R. L. Keeney; H. Raiffa. *Technometrics*, 20(3):322, August 1978.

CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268147`.

J:1978:BRBn

[J.78c] J. E. J. Book review: *Contributions to Survey Sampling and Applied Statistics* by H. A. David. *Technometrics*, 20(3):321–322, August 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268146`.

J:1978:BRBh

[J.78d] J. E. J. Book review: *Interactive Data Analysis* by D. R. McNeil. *Technometrics*, 20(2):212, May 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268720`.

J:1978:BRBe

[J.78e] J. E. J. Book review: *Management Science in Sports* by R. E. Machol; S. P. Ladany; D. G. Morrison. *Technometrics*, 20(1):106, February 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268175`.

J:1978:BRBf

[J.78f] J. E. J. Book review: *Methods for Statistical Data Analysis of Multivariate Observations* by R. Gnanadesikan. *Technometrics*, 20(2):210–211, May 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268717`.

J:1978:BRBg

[J.78g] J. E. J. Book review: *MINITAB: Student Handbook* by T. A. Ryan; B. L. Joiner; B. F. Ryan. *Technometrics*, 20(2):211–212, May 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268719`.

J:1978:BRBb

[J.78h] J. E. J. Book review: *Multiple Criteria Decision Making* by M. K. Starr; M. Zeleny. *Technometrics*, 20(1):105, February 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268169`.

J:1978:BRBk

[J.78i] J. E. J. Book review: *New Developments in the Applications of Bayesian Methods* by A. Aykaç; C. Brumat. *Technomet-*

rics, 20(2):214–215, May 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268726`.

J:1978:BRBm

[J.78j] J. E. J. Book review: *Nuclear Systems Reliability Engineering and Risk Assessment* by J. B. Fussell; G. R. Burdick. *Technometrics*, 20(3):321, August 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268145`.

J:1978:BRBd

[J.78k] J. E. J. Book review: *On the History of Statistics and Probability* by D. B. Owen. *Technometrics*, 20(1):106, February 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268174`.

J:1978:BRBc

[J.78l] J. E. J. Book review: *Pocket Book of Statistical Tables* by R. E. Odeh; D. B. Owen; Z. W. Birnbaum; L. Fisher. *Technometrics*, 20(1):105, February 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268170`.

J:1978:BRBl

[J.78m] J. E. J. Book review: *Recent Developments in Statistics* by J. R. Barra; F. Brodeau; G. Romier; B. van Cutsem. *Technometrics*, 20(2):215–217, May 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268728`.

J:1978:BRBa

[J.78n] J. E. J. Book review: *Sampling Techniques* by W. G. Cochran. *Technometrics*, 20(1):104, February 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268167`.

J:1978:BRBq

[J.78o] J. E. J. Book review: *Selected Tables in Mathematical Statistics, Vol. 5* by Institute of Mathematical Statistics; D. B. Owen; R. E. Odeh. *Technometrics*, 20(3):323, August 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268149`.

J:1978:BRBi

[J.78p] J. E. J. Book review: *Statistical Tables for Science, Engineering, Management and Business Studies* by J. Murdoch; S. A. Baines. *Technometrics*, 20(2):214, May 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268724`.

J:1978:BRBj

[J.78q] J. E. J. Book review: *Tables of Random Times* by I. E. Hill; P. A. Hill. *Technometrics*, 20(2):214, May 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268725`.

J:1979:BRBq

[J.79a] J. E. J. Book review: *A Sampler on Sampling* by Bill Williams. *Technometrics*, 21(4):583–584, November 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268302`.

J:1979:BRBm

[J.79b] J. E. J. Book review: *Algorithmic Methods in Probability* by Marcel F. Neuts. *Technometrics*, 21(3):392, August 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267775`.

J:1979:BRBg

[J.79c] J. E. J. Book review: *Analyzing Qualitative/Categorical Data* by Leo A. Goodman. *Technometrics*, 21(2):272, May 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268530`.

J:1979:BRBo

[J.79d] J. E. J. Book review: *Applied Optimal Control* by A. Bensoussan; P. R. Kleindorfer; C. S. Tapiero. *Technometrics*, 21(3):393, August 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267777`.

J:1979:BRBe

[J.79e] J. E. J. Book review: *Applied Time Series Analysis* by D. F. Findley. *Technometrics*, 21(1):136, February 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268596`.

J:1979:BRBt

[J.79f] J. E. J. Book review: *Developments in Statistics, Volume 2* by P. R. Krishnaiah. *Technometrics*, 21(4):585, November 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268306`.

J:1979:BRBd

[J.79g] J. E. J. Book review: *Developments in Statistics, Volume I* by P. R. Krishnaiah. *Technometrics*, 21(1):136, February 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268595`.

J:1979:BRBu

[J.79h] J. E. J. Book review: *Energy and Health* by N. E. Breslow; A. S. Whittemore. *Technometrics*, 21(4):585, November 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268307`.

J:1979:BRBb

[J.79i] J. E. J. Book review: *Graphical Techniques for Multivariate Data* by Brian Everitt. *Technometrics*, 21(1):134, February 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268591`.

J:1979:BRBf

[J.79j] J. E. J. Book review: *Handbook of Hypergeometric Integrals* by Harold Exton. *Technometrics*, 21(1):136, February 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268597`.

J:1979:BRBj

[J.79k] J. E. J. Book review: *International Encyclopedia of Statistics* by William H. Kruskal; Judith M. Tanur. *Technometrics*, 21(3):388–389, August 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267768`.

J:1979:BRBh

[J.79l] J. E. J. Book review: *Maps and Statistics* by Peter Lewis. *Technometrics*, 21(2):273, May 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268532`.

J:1979:BRBv

[J.79m] J. E. J. Book review: *Modelling and Simulation Practice* by M. Cross; R. D. Gibson; M. J. O'Carroll; T. S. Wilkinson. *Technometrics*, 21(4):586, November 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268308`.

J:1979:BRBp

[J.79n] J. E. J. Book review: *Operational Research '78* by K. B. Haley. *Technometrics*, 21(3):393–394, August 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267778`.

J:1979:BRBk

[J.79o] J. E. J. Book review: *Problems and Solutions in Theoretical Statistics* by D. R. Cox; D. V. Hinkley. *Technometrics*, 21(3):390, August 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267770`.

J:1979:BRBc

[J.79p] J. E. J. Book review: *R. A. Fisher, the Life of a Scientist* by Joan Fisher Box. *Technometrics*, 21(1):135, February 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268594`.

J:1979:BRBa

[J.79q] J. E. J. Book review: *Statistical Methods for Digital Computers, Volume III* by K. Enslein; A. Ralston; H. S. Wilf. *Technometrics*, 21(1):133–134, February 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268590`.

J:1979:BRBi

[J.79r] J. E. J. Book review: *Statistics* by R. F. Hirsch. *Technometrics*, 21 (2):274, May 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268534`.

J:1979:BRBr

[J.79s] J. E. J. Book review: *Statistics for Technology* by Christopher Chatfield. *Technometrics*, 21(4):584–585, November 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268304`.

J:1979:BRBl

[J.79t] J. E. J. Book review: *Survey Sampling and Measurement* by N. K. Namboodiri. *Technometrics*, 21(3):391–392, August 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267774`.

J:1979:BRBs

[J.79u] J. E. J. Book review: *Tables of the F- and Related Distributions with Algorithms* by K. V. Mardia; P. J. Zemroch. *Technometrics*, 21(4):585, November 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268305`.

J:1979:BRBn

[J.79v] J. E. J. Book review: *The H-Function with Applications in Statistics and Other Disciplines* by A. M. Mathai; R. K. Saxena. *Technometrics*, 21(3):392–393, August 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267776`.

Jackson:1980:BRBc

[Jac80] J. Edward Jackson. Book review: *Three Aspects of Policy and Policymaking: Knowledge, Data and Institutions* by Karl Brunner; Allan H. Meltzer. *Technometrics*, 22(1):134, February 1980. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268404`. See corrigenda [Ano80a].

Jaech:1970:CTM

[Jae70] John L. Jaech. Comparing two methods of obtaining a confidence interval for the ratio of Poisson parameters. *Technometrics*, 12(2):383–387, May 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267242`.

Jaech:1974:DSP

[Jae74] John L. Jaech. Determination of system performance by the generation of conditional system moments. *Technometrics*, 16(4):627–629, November 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267618`.

Jaech:1976:LST

[Jae76] John L. Jaech. Large sample tests for Grubbs' estimators of instrument precision with more than two instruments. *Technomet-*

rics, 18(2):127–133, May 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267516`.

Johnson:1974:ESC

[JB74] Richard A. Johnson and Michael Bagshaw. The effect of serial correlation on the performance of CUSUM tests. *Technometrics*, 16(1):103–112, February 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267498`.

Jennrich:1976:FSL

[JB76] Robert I. Jennrich and Peter B. Bright. Fitting systems of linear differential equations using computer generated exact derivatives. *Technometrics*, 18(4):385–392, November 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268653`. See discussion [Wig76].

Joiner:1976:DEW

[JC76] Brian L. Joiner and Cathy Campbell. Designing experiments when run order is important. *Technometrics*, 18(3):249–259, August 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268734`.

John:1978:TTO

[JD78] J. A. John and N. R. Draper. On testing for two outliers or one outlier in two-way tables. *Technometrics*, 20(1):69–78, February 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268162`.

Johnson:1974:LE

[JEBE74] Arthur F. Johnson, A. W. F. Edwards, Lee J. Bain, and Max Engelhardt. Letters to the Editor. *Technometrics*, 16(4):641–642, November 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267629`.

Jerome:1970:BRB

[Jer70] Joseph Jerome. Book review: *An Introduction to the Approximation of Functions* by Theodore J. Rivlin. *Technometrics*, 12(2):425–426, May 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267251`.

Jackson:1973:RAC

[JH73a] J. Edward Jackson and F. Terry Hearne. Relationships among coefficients of vectors used in principal components. *Technometrics*, 15(3):601–610, August 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266866`.

Johnson:1973:BRBa

[JH73b] William D. Johnson and Wolfgang Habermann. Book review: *Statistische Methoden Ein Soforthelfer* by Luther Sachs. *Technometrics*, 15(1):202, February 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266845`.

Jackson:1979:HPC

[JH79] J. Edward Jackson and F. Terry Hearne. Hotelling's T_M^2 for principal components: What about absolute values? *Technometrics*, 21(2):253–255, May 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268524`.

Johnson:1971:NWL

[JK71] William D. Johnson and Gary G. Koch. A note on the weighted least squares analysis of the ries-Smith contingency table data. *Technometrics*, 13(2):438–447, May 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266806`.

Johnson:1974:APM

[JK74] Charles A. Johnson and Jerome H. Klotz. The atom probe and Markov chain statistics of clustering. *Technometrics*, 16(4):483–493, November 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267599`.

Johnson:1979:BSS

[JL79] Mark E. Johnson and Victor W. Lowe, Jr. Bounds on the sample skewness and kurtosis. *Technometrics*, 21(3):377–378, August 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267763`.

Jackson:1979:CPR

[JM79] J. Edward Jackson and Govind S. Mudholkar. Control procedures for residuals associated with principal component analysis. *Tech-*

nometrics, 21(3):341–349, August 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267757`.

Johnson:1978:EPO

[JMM78] Dallas E. Johnson, Stephen A. McGuire, and George A. Milliken. Estimating σ^2 in the presence of outliers. *Technometrics*, 20(4):441–455, November 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267645`.

Johansen:1970:APR

[Joh70a] S. Johansen. Asymptotic properties of the restricted Bayesian double sampling plan. *Technometrics*, 12(3):647–667, August 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267210`.

John:1970:IPOb

[Joh70b] S. John. On identifying the population of origin of each observation in a mixture of observations from two gamma populations. *Technometrics*, 12(3):565–568, August 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267203`.

John:1970:IPOa

[Joh70c] S. John. On identifying the population of origin of each observation in a mixture of observations from two normal populations. *Technometrics*, 12(3):553–563, August 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267202`.

Johnson:1971:LCD

[Joh71a] Arthur F. Johnson. Linear combinations in designing experiments. *Technometrics*, 13(3):575–587, August 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267169`.

Johnson:1971:BRB

[Joh71b] William D. Johnson. Book review: *Introductory Probability and Statistical Applications* by Paul L. Meyer. *Technometrics*, 13(1):212–213, February 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267093`.

John:1973:BDV

[Joh73a] Peter W. M. John. A balanced design for 18 varieties. *Technometrics*, 15(3):641–642, August 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266871`.

Johnson:1973:EEA

[Joh73b] Eric E. Johnson. Empirical equations for approximating tabular F values. *Technometrics*, 15(2):379–384, May 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266996`.

Johnson:1973:BRBb

[Joh73c] William D. Johnson. Book review: *Nonparametric Statistical Inference* by Jean D. Gibbons. *Technometrics*, 15(2):421, May 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267003`.

Johansson:1975:BRB

[Joh75] J. K. Johansson. Book review: *Basic Statistics with Business Applications* by Richard C. Clelland; John S. deCani; Francis E. Brown. *Technometrics*, 17(3):384–385, August 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268081`.

John:1978:NBD

[Joh78] Peter W. M. John. A new balanced design for eighteen varieties. *Technometrics*, 20(2):155–158, May 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268707`.

John:1979:MPF

[Joh79] Peter W. M. John. Missing points in 2^n and 2^{n-k} factorial designs. *Technometrics*, 21(2):225–228, May 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268519`.

Joiner:1977:ECF

[Joi77] Brian L. Joiner. Evaluation of cryogenic flow meters: An example in non-standard experimental design and analysis. *Technometrics*, 19(4):353–379, November 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267876`.

Jones:1971:CIL

[Jon71] C. F. Jones. A confidence interval for the lognormal hazard. *Technometrics*, 13(4):885–888, November 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266965`.

Jones:1973:BRB

[Jon73] Robert C. Jones. Book review: *Basic Statistics for Business and Economics* by Paul G. Hoel; Raymond J. Jessen. *Technometrics*, 15(1):199–200, February 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266842`.

Jones:1976:ADO

[Jon76a] Byron Jones. An algorithm for deriving optimal block designs. *Technometrics*, 18(4):451–458, November 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268661`.

Jones:1976:BRB

[Jon76b] Thomas A. Jones. Book review: *Geomathematics: Mathematical Background and Geo-Science Applications* by F. P. Agterberg. *Technometrics*, 18(2):242–243, May 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267537`.

Joshi:1972:EEM

[Jos72] Prakash C. Joshi. Efficient estimation of the mean of an exponential distribution when an outlier is present. *Technometrics*, 14(1):137–143, February 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266925`.

Jayne:1972:PEF

[JR72] Lance W. Jayne and Edward W. Ross, Jr. Probability of equipment failure when tolerances are incorrect. *Technometrics*, 14(4):899–909, November 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267138`.

Jennrich:1976:NRR

[JS76] R. I. Jennrich and P. F. Sampson. Newton–Raphson and related algorithms for maximum likelihood variance component estimation. *Technometrics*, 18(1):11–17, February 1976. CODEN TCMTA2. ISSN

0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267911`.

Johnson:1975:LEN

[JTS75] Norman L. Johnson, H. Tong, and W. Spendley. Letter to the editor on: "A note on the estimation of Pr$\{Y < X\}$ in the exponential case" (Technometrics **16** (1974), 625) by H. Tong. *Technometrics*, 17(3):393–394, August 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268093`. With a reply by Tong.

K:1971:BRBa

[K.71a] G. G. K. Book review: *An Author and Permuted Title Index to Selected Statistical Journals* by Brian L. Joiner; N. F. Laubscher; Eleanor S. Brown; Bert Levy. *Technometrics*, 13(2):452–453, May 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266812`.

K:1971:BRBc

[K.71b] G. G. K. Book review: *Engineering Mathematics Handbook* by Jan J. Tuma. *Technometrics*, 13(3):709, August 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267189`.

K:1971:BRBd

[K.71c] G. G. K. Book review: *Nonparametric Techniques in Statistical Inference* by Madan Lai Puri. *Technometrics*, 13(3):709–710, August 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267190`.

K:1971:BRBb

[K.71d] G. G. K. Book review: *Random Counts in Models and Structures (Volume 1)* by G. P. Patil. *Technometrics*, 13(2):453–454, May 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266813`.

K:1971:BRBe

[K.71e] G. G. K. Book review: *Statistical Computation* by Roy C. Milton; John A. Nelder. *Technometrics*, 13(3):710–711, August 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267191`.

K:1973:BRBe

[K.73a] G. G. K. Book review: *Analysis and Simulation of Biochemical Systems, Volume 25* by H. C. Hemker; B. Hess. *Technometrics*, 15(4):944–945, November 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267412`.

K:1973:BRBb

[K.73b] G. G. K. Book review: *Collected Papers of R. A. Fisher, Volume I* by J. H. Bennett; R. A. Fisher. *Technometrics*, 15(2):426–427, May 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267011`.

K:1973:BRBc

[K.73c] G. G. K. Book review: *Selected Readings in Economic Theory from Econometrica* by Kenneth J. Arrow. *Technometrics*, 15(3):654–655, August 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266880`.

K:1973:BRBa

[K.73d] G. G. K. Book review: *Statistical Papers in Honor of George W. Snedecor* by T. A. Bancroft. *Technometrics*, 15(2):424–425, May 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267009`.

K:1973:BRBd

[K.73e] G. G. K. Book review: *Statistics and Probability in Civil Engineering* by Peter Lumb. *Technometrics*, 15(4):942–943, November 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267410`.

K:1974:BRBc

[K.74a] G. G. K. Book review: *Inventory Control and Water Storage* by A. Prekopa. *Technometrics*, 16(3):482, August 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267688`.

K:1974:BRBd

[K.74b] G. G. K. Book review: *Mathematics and Statistics: Essays in Honour of Harald Bergstrom* by Peter Jagers; Lennart Rade. *Technometrics*, 16(3):482, August 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267689`.

K:1974:BRBa

[K.74c] G. G. K. Book review: *Multivariate Statistical Inference* by D. G. Kabe; R. P. Gupta. *Technometrics*, 16(2):328, May 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267963`.

K:1974:BRBe

[K.74d] G. G. K. Book review: *Symmetric Functions in Statistics* by Derrick S. Tracy. *Technometrics*, 16(4):637, November 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267628`.

K:1974:BRBb

[K.74e] G. G. K. Book review: *Third Conference Advisory Group of Forest Statisticians*. *Technometrics*, 16(2):328–329, May 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267964`.

Kendell:1971:EPL

[KA71] P. J. Kendell and R. L. Anderson. An estimation problem in life-testing. *Technometrics*, 13(2):289–301, May 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266791`.

Kabe:1974:BRB

[Kab74] D. G. Kabe. Book review: *Quality Control and Reliability* by Norbert L. Enrick. *Technometrics*, 16(1):139–140, February 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267508`.

Kalotay:1971:SSL

[Kal71] A. J. Kalotay. Structural solution to the linear calibration problem. *Technometrics*, 13(4):761–769, November 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266953`.

Kalbfleisch:1975:BRB

[Kal75] J. D. Kalbfleisch. Book review: *Statistical Inference under Order Restrictions* by R. E. Barlow; D. J. Bartholomew; J. M. Bremner; H. D. Brunk. *Technometrics*, 17(1):139–140, February 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268017`.

Kaminsky:1972:CIE

[Kam72] Kenneth S. Kaminsky. Confidence intervals for the exponential scale parameter using optimally selected order statistics. *Technometrics*, 14(2):371–383, May 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267428`.

Kaminsky:1973:CAC

[Kam73] Kenneth S. Kaminsky. Comparison of approximate confidence intervals for the exponential scale parameter from sample quantiles. *Technometrics*, 15(3):483–487, August 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266853`.

Kaminsky:1974:CIT

[Kam74] Kenneth S. Kaminsky. Confidence intervals and tests for two exponential scale parameters based on order statistics in compressed samples. *Technometrics*, 16(2):251–254, May 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267947`.

Kaminsky:1977:CPI

[Kam77] Kenneth S. Kaminsky. Comparison of prediction intervals for failure times when life is exponential. *Technometrics*, 19(1):83–86, February 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268259`.

Kao:1972:ESC

[Kao72] Edward P. C. Kao. Economic screening of a continuously manufactured product. *Technometrics*, 14(3):653–661, August 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267293`.

Kappenman:1972:NSG

[Kap72] Russell F. Kappenman. A note on selection of the greatest exceedance probability. *Technometrics*, 14(1):219–222, February 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266933`.

Kappenman:1975:CCI

[Kap75] Russell F. Kappenman. Conditional confidence intervals for double exponential distribution parameters. *Technometrics*, 17(2):233–235,

May 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268356`.

Klimko:1975:UBP

[KARR75] Lawrence A. Klimko, Charles E. Antle, Alfred W. Rademaker, and Howard E. Rockette. Upper bounds for the power of invariant tests for the exponential distribution with Weibull alternatives. *Technometrics*, 17(3):357–360, August 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268074`.

Koziol:1975:PPA

[KB75] James A. Koziol and David P. Byar. Percentage points of the asymptotic distributions of one and two sample K–S statistics for truncated or censored data. *Technometrics*, 17(4):507–510, November 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268440`.

Krutchkoff:1972:LE

[KBW72] Richard G. Krutchkoff, A. R. Burgess, and E. B. Wilson. Letters to the Editor. *Technometrics*, 14(1):241–242, February 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266942`.

Keesing:1975:BRB

[Kee75] Donald B. Keesing. Book review: *Economic Growth, Development, and Foreign Trade: A Study in Pure Theory* by Pranab K. Bardhan. *Technometrics*, 17(2):276, May 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268368`.

Kennard:1971:NS

[Ken71] Robert W. Kennard. A note on the C_p statistic. *Technometrics*, 13(4):899–900, November 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266968`. See erratum [Ano73i].

Kettenring:1975:BRB

[Ket75] J. R. Kettenring. Book review: *Cluster Analysis* by Brian Everitt. *Technometrics*, 17(2):275, May 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268366`.

Keviczky:1975:DEI

[Kev75] L. Keviczky. “Design of experiments” for the identification of linear dynamic systems. *Technometrics*, 17(3):303–308, August 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268065`.

Khatri:1974:BRB

[Kha74] C. G. Khatri. Book review: *Multivariate Analysis* by Anant M. Kshirsagar. *Technometrics*, 16(1):138–139, February 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267507`.

Kinory:1978:BRB

[Kin78] Shimshon Kinory. Book review: *Statistical Analysis for Decision Making* by Morris Hamburg. *Technometrics*, 20(1):104–105, February 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268168`.

Kinory:1979:BRBa

[Kin79a] Shimshon Kinory. Book review: *Statistics* by David Freedman; Robert Pisani; Roger Purves. *Technometrics*, 21(2):273–274, May 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268533`.

Kinory:1979:BRBb

[Kin79b] Shimshon Kinory. Book reviews: *How to Use (And Misuse) Statistics* by Gregory A. Kimble; *Business Statistics* by Paul R. Winn; Ross H. Johnson. *Technometrics*, 21(3):391, August 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267773`.

Kitagawa:1979:UAD

[Kit79] Genshiro Kitagawa. On the use of AIC for the detection of outliers. *Technometrics*, 21(2):193–199, May 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268516`. See corrigenda [Kit81].

Kitagawa:1981:CUA

[Kit81] Genshiro Kitagawa. Corrigenda: “On the use of AIC for the detection of outliers” [*Technometrics* **21** (1979), no. 2, 193–199; MR 80f:62026]. *Technometrics*, 23(3):320–321, August 1981. CODEN

TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267810`. See [Kit79].

Kao:1979:SPC

[KKM79] Peichuen Kao, Edward P. C. Kao, and Jack M. Mogg. A simple procedure for computing performance characteristics of truncated sequential tests with exponential lifetimes. *Technometrics*, 21(2):229–232, May 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268520`.

Kelley:1976:EEE

[KKS76] Gary D. Kelley, Judy A. Kelley, and W. R. Schucany. Efficient estimation of $P(Y < X)$ in the exponential case. *Technometrics*, 18(3):359–360, August 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268746`.

Kleijnen:1975:SDP

[Kle75] Jack P. C. Kleijnen. Screening designs for poly-factor experimentation. *Technometrics*, 17(4):487–493, November 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268437`.

Kleiner:1977:BRB

[Kle77] Beat Kleiner. Book review: *Time Series Analysis: Forecasting and Control* by G. E. P. Box; G. J. Jenkins. *Technometrics*, 19(3):343–344, August 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267710`.

Khuri:1979:MRA

[KM79] A. I. Khuri and Raymond H. Myers. Modified ridge analysis. *Technometrics*, 21(4):467–473, November 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268285`.

Kubicek:1971:QR

[KME71] M. Kubicek, M. Marek, and E. Eckert. Quasilinearized regression. *Technometrics*, 13(3):601–608, August 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267171`.

Kaminsky:1974:PIE

[KN74] Kenneth S. Kaminsky and Paul I. Nelson. Prediction intervals for the exponential distribution using subsets of the data. *Technomet-*

rics, 16(1):57–59, February 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267492`.

Knox:1971:BRB

[Kno71] Hugh Knox. Book review: *Markets, Prices, and Interregional Trade* by Raymond G. Bressler,; Richard King. *Technometrics*, 13(1):211–212, February 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267092`.

Kase:1977:GAD

[KO77] Shigeo Kase and Hiroshi Ohta. GERT analysis of the Dodge–Romig sampling inspection plan. *Technometrics*, 19(3):249–257, August 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267694`.

Kowalski:1970:PSR

[Kow70] Charles J. Kowalski. The performance of some rough tests for bivariate normality before and after coordinate transformations to normality. *Technometrics*, 12(3):517–544, August 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267200`.

Kowalski:1971:OAF

[Kow71] Charles J. Kowalski. The OC and ASN functions of some SPRT's for the correlation coefficient. *Technometrics*, 13(4):833–841, November 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266958`.

Koyama:1978:MSR

[Koy78] Takeshi Koyama. Modified switching rules for sampling schemes such as MIL-STD-105D. *Technometrics*, 20(1):95–102, February 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268165`.

Koyama:1979:SCU

[Koy79] Takeshi Koyama. Switching characteristics under MIL-STD-105D. *Technometrics*, 21(1):9–19, February 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268576`.

Kumar:1971:TCT

[KP71] S. Kumar and H. I. Patel. A test for the comparison of two exponential distributions. *Technometrics*, 13(1):183–189, February 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267085`. See errata [Ano71g].

Kraemer:1979:CAN

[KP79] Helena Chmura Kraemer and Minja Paik. A central t approximation to the noncentral t distribution. *Technometrics*, 21(3):357–360, August 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267759`.

Kraemer:1976:BRB

[Kra76] Helena Chmura Kraemer. Book review: *Asymptotic Theory of Rank Tests for Independence* by F. H. Ruymgaart. *Technometrics*, 18(1):122, February 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267928`.

Krutchkoff:1970:LE

[Kru70] Richard G. Krutchkoff. Letters to the Editor. *Technometrics*, 12(2):433–434, May 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267253`.

Krzanowski:1977:PFL

[Krz77] W. J. Krzanowski. The performance of Fisher's linear discriminant function under non-optimal conditions. *Technometrics*, 19(2):191–200, May 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268629`.

Krzanowski:1979:SEP

[Krz79] W. J. Krzanowski. Some exact percentage points of a statistic useful in analysis of variance and principal component analysis. *Technometrics*, 21(2):261–263, May 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268526`.

Kale:1971:EEL

[KS71] B. K. Kale and S. K. Sinha. Estimation of expected life in the presence of an outlier observation. *Technometrics*, 13(4):755–759, November 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266952`.

Kupper:1971:BRB

[Kup71] Lawrence L. Kupper. Book review: *Probability, Statistics, and Decision for Civil Engineers* by Jack R. Benjamin; C. Allin Cornell. *Technometrics*, 13(1):211, February 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267091`.

Kussmaul:1979:ACI

[Kus79] Keith Kussmaul. An approximate confidence interval for the mean of the dependent variable in a random one-way classification with covariates. *Technometrics*, 21(1):111–117, February 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268587`.

LaBrecque:1977:GFT

[LaB77] John LaBrecque. Goodness-of-fit tests based on nonlinearity in probability plots. *Technometrics*, 19(3):293–306, August 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267699`.

Lachenbruch:1971:BRBb

[Lac71a] P. A. Lachenbruch. Book review: *Data Representation* by R. S. Anderssen; M. R. Osborne. *Technometrics*, 13(4):925, November 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266978`.

Lachenbruch:1971:BRBa

[Lac71b] P. A. Lachenbruch. Book review: *Statistics: Probability Inference and Decision, Volume 1* by W. L. Hays; R. L. Winkler. *Technometrics*, 13(4):920, November 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266974`.

Lachenbruch:1972:BRBb

[Lac72a] Peter A. Lachenbruch. Book review: *Mathematical Statistics* by John Freund. *Technometrics*, 14(3):807, August 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267312`.

Lachenbruch:1972:BRBa

[Lac72b] Peter A. Lachenbruch. Book review: *Statistical Methods in Medical Research* by P. Armitage. *Technometrics*, 14(1):235, February 1972.

CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266938`.

Lachenbruch:1974:BRB

[Lac74a] Peter A. Lachenbruch. Book review: *Statistics by Example* by F. Mosteller; W. H. Kruskal; R. F. Link; R. S. Pieters; G. R. Rising. *Technometrics*, 16(2):326, May 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267959`.

Lachenbruch:1974:DAW

[Lac74b] Peter A. Lachenbruch. Discriminant analysis when the initial samples are misclassified II: Non-random misclassification models. *Technometrics*, 16(3):419–424, August 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267672`.

Lachenbruch:1979:NIM

[Lac79] Peter A. Lachenbruch. Note on initial misclassification effects on the quadratic discriminant function. *Technometrics*, 21(1):129–132, February 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268589`.

Ladany:1977:DSS

[Lad77] Shaul P. Ladany. Derivation of single-stage attribute sampling plans with one of the p's larger than 0.5. *Technometrics*, 19(1):99–100, February 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268262`.

LaMotte:1978:BLE

[LaM78] Lynn Roy LaMotte. Bayes linear estimators. *Technometrics*, 20(3):281–290, August 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268137`.

Land:1972:EAC

[Lan72] Charles E. Land. An evaluation of approximate confidence interval estimation methods for lognormal means. *Technometrics*, 14(1):145–158, February 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266926`.

Land:1973:BRB

[Lan73] Charles E. Land. Book review: *Probability and Mathematical Statistics: An Introduction* by Eugene Lukacs. *Technometrics*, 15 (4):941–942, November 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267409`.

Landis:1975:BRB

[Lan75] J. Richard Landis. Book review: *Introductory Statistical Analysis* by T. W. Anderson; S. L. Sclove. *Technometrics*, 17(1):143, February 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268022`.

Lawless:1971:PPC

[Law71] J. F. Lawless. A prediction problem concerning samples from the exponential distribution, with application in life testing. *Technometrics*, 13(4):725–730, November 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266949`.

Lawless:1973:ESL

[Law73] J. F. Lawless. On the estimation of Safe life when the underlying life distribution is Weibull. *Technometrics*, 15(4):857–865, November 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267395`.

Lawless:1975:CTB

[Law75a] J. F. Lawless. Construction of tolerance bounds for the extreme-value and Weibull distributions. *Technometrics*, 17(2):255–261, May 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268359`.

Lawrence:1975:BRB

[Law75b] Clive J. Lawrence. Book review: *Robust Estimates of Location: Survey and Advances* by D. F. Andrews; P. J. Bickel; F. R. Hampel; P. J. Huber; W. H. Rogers; J. W. Tukey. *Technometrics*, 17(1):138–139, February 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268015`.

Lawton:1976:NE

[Law76] William H. Lawton. New Editor. *Technometrics*, 18(4):367, November 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268650`.

Lawless:1977:PIT

[Law77a] J. F. Lawless. Prediction intervals for the two parameter exponential distribution. *Technometrics*, 19(4):469–472, November 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267887`.

Lawless:1977:DAO

[Law77b] Jerald F. Lawless. Discussion of: “Asymptotically Optimum Over-Stress Tests to Estimate the Survival Probability at a Condition with a Low Expected Failure Probability”. *Technometrics*, 19(4):401–404, November 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267878`. See [MH77].

Lawless:1978:CIE

[Law78] J. F. Lawless. Confidence interval estimation for the Weibull and extreme value distributions. *Technometrics*, 20(4):355–364, November 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267633`. See discussion [Eas78].

Leslie:1970:DQA

[LC70] R. T. Leslie and D. Culpin. Distribution of quasimidranges and associated mixtures. *Technometrics*, 12(2):311–325, May 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267236`.

Lorden:1973:DFR

[LE73] G. Lorden and I. Eisenberger. Detection of failure rate increases. *Technometrics*, 15(1):167–175, February 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266833`.

Lee:1979:LE

[Lee79] Martin Lee. Letter to the Editor. *Technometrics*, 21(2):275, May 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268536`.

Lehnen:1971:BRB

[Leh71] Robert G. Lehnen. Book review: *Mathematics in the Behavioral and Social Sciences* by John W. Bishir; Donald W. Drewes. *Technometrics*, 13(1):213, February 1971. CODEN TCMTA2. ISSN 0040-

1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267094`.

Lemon:1974:PDM

[Lem74] Glen H. Lemon. A problem in the distribution of maximum flaw length after inspection. *Technometrics*, 16(4):577–583, November 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267610`.

Lemon:1975:MLE

[Lem75] Glen H. Lemon. Maximum likelihood estimation for the three parameter Weibull distribution based on censored samples. *Technometrics*, 17(2):247–254, May 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268358`.

Leone:1970:QTH

[Leo70] F. C. Leone. Query 1: [testing the hypothesis whether the two methods of testing used on the same set of batches are in agreement or not]. *Technometrics*, 12(2):417–418, May 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267248`.

Leonard:1975:BAL

[Leo75] Tom Leonard. A Bayesian approach to the linear model with unequal variances. *Technometrics*, 17(1):95–102, February 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268006`.

Levy:1970:CIE

[Lev70] Paul S. Levy. Combining independent estimators: An empirical sampling study. *Technometrics*, 12(1):162–165, February 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267362`.

Lever:1979:BRB

[Lev79] W. E. Lever. Book review: *Material Accountability Theory, Verification, Applications* by Rudolf Avenhaus. *Technometrics*, 21 (1):134–135, February 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268592`.

Lewis:1979:RAN

[LF79] T. Lewis and N. R. J. Fieller. A recursive algorithm for null distributions for outliers: I. Gamma samples. *Technometrics*, 21(3):371–376, August 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267762`.

LaMotte:1970:CES

[LH70] L. R. LaMotte and R. R. Hocking. Computational efficiency in the selection of regression variables. *Technometrics*, 12(1):83–93, February 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267353`.

Lauer:1974:PCT

[LH74] G. N. Lauer and C. P. Han. Power of Cochran's test in the Behrens-Fisher problem. *Technometrics*, 16(4):545–549, November 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267606`.

Lee:1977:SML

[LH77] Austin F. S. Lee and Sylva M. Heghinian. A shift of the mean level in a sequence of independent normal random variables—a Bayesian approach. *Technometrics*, 19(4):503–506, November 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267892`.

Likes:1974:POO

[Lik74] J. Likeš. Prediction of s th ordered observation for the two-parameter exponential distribution. *Technometrics*, 16(2):241–244, May 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267945`.

Lin:1974:NTE

[Lin74] Chi-Yuan Lin. Numerical techniques for evaluating sample information. *Technometrics*, 16(3):447–454, August 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267676`.

Links:1975:BRB

[Lin75] Graham Links. Book review: *Linear and Integer Programming* by S. Zionts. *Technometrics*, 17(3):386–387, August 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268086`.

Lindstrom:1979:MSM

[Lin79] F. T. Lindstrom. A modified 3-spline method for evaluating the Euler digamma function. *Technometrics*, 21(3):307–311, August 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267752`.

Lee:1978:SRI

[LL78] Larry Lee and S. Keith Lee. Some results on inference for the Weibull process. *Technometrics*, 20(1):41–45, February 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268160`.

Larsen:1972:UPR

[LM72] Wayne A. Larsen and Susan J. McCleary. The use of partial residual plots in regression analysis. *Technometrics*, 14(3):781–790, August 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267305`.

Leone:1961:FND

[LNN61] F. C. Leone, L. S. Nelson, and R. B. Nottingham. The folded normal distribution. *Technometrics*, 3(4):543–550, November 1961. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266560`. See corrigenda [Ano80b].

Li:1979:TSS

[LO79] Loretta Li and Donald B. Owen. Two-sided screening procedures in the bivariate case. *Technometrics*, 21(1):79–85, February 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268583`.

Low:1970:AMC

[Low70] Leone Low. An application of majorization to comparison of variances. *Technometrics*, 12(1):141–145, February 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267358`.

Lowerre:1974:MSE

[Low74] James M. Lowerre. On the mean square error of parameter estimates for some biased estimators. *Technometrics*, 16(3):461–464, August 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267678`.

Low:1976:SPV

[Low76] Leone Y. Low. Some properties of variance component estimators in the two-way classification. *Technometrics*, 18(1):39–46, February 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267914`.

Levenbach:1976:FTT

[LR76] Hans Levenbach and Blake E. Reuter. Forecasting trending time series with relative growth rate models. *Technometrics*, 18(3):261–272, August 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268735`.

Littell:1978:CRL

[LR78] Ramon C. Littell and P. V. Rao. Confidence regions for location and scale parameters based on the Kolmogorov-Smirnov goodness of fit statistic. *Technometrics*, 20(1):23–27, February 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268156`.

Lawton:1971:ELP

[LS71a] William H. Lawton and Edward A. Sylvestre. Elimination of linear parameters in nonlinear regression. *Technometrics*, 13(3):461–467, August 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267160`.

Lawton:1971:SMC

[LS71b] William H. Lawton and Edward A. Sylvestre. Self modeling curve resolution. *Technometrics*, 13(3):617–633, August 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267173`.

Lawton:1972:SMN

[LSM72] W. H. Lawton, E. A. Sylvestre, and M. S. Maggio. Self modeling nonlinear regression. *Technometrics*, 14(3):513–532, August 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267281`.

Layard:1976:LE

[LSP76] M. W. J. Layard, David S. Salsburg, and P. Prescott. Letters to the Editor. *Technometrics*, 18(1):124–125, February 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267932`.

Lawton:1979:SCM

[LSYF79] W. H. Lawton, E. A. Sylvestre, and B. J. Young-Ferraro. Statistical comparison of multiple analytic procedures: Application to clinical chemistry. *Technometrics*, 21(4):397–409, November 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268278`. See discussion [FH79].

Lucas:1973:MVM

[Luc73] James M. Lucas. A modified “v” mask control scheme. *Technometrics*, 15(4):833–847, November 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267393`.

Lucas:1974:OCD

[Luc74] James M. Lucas. Optimum composite designs. *Technometrics*, 16(4):561–567, November 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267608`.

Lucas:1976:WRS

[Luc76] James M. Lucas. Which response surface design is best: A performance comparison of several types of quadratic response surface designs in symmetric regions. *Technometrics*, 18(4):411–417, November 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268656`.

Lucas:1978:DOF

[Luc78] James M. Lucas. Discussion of: “D-Optimal Fractions of Three-Level Factorial Designs”. *Technometrics*, 20(4):381–382, November 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267636`. See [MB78a].

Lukacs:1973:BRB

[Luk73] Eugene Lukacs. Book review: *Preservation of Infinite Divisibility under Mixing* by F. W. Steutel. *Technometrics*, 15(3):650–651, August 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266875`.

Lund:1975:TAT

[Lun75] Richard E. Lund. Tables for an approximate test for outliers in linear models. *Technometrics*, 17(4):473–476, November 1975. CODEN

TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268434`.

Lutz:1973:BRB

[Lut73] Donald S. Lutz. Book review: *Paradoxes of Rationality: Theory of Metagames and Political Behavior* by Nigel Howard. *Technometrics*, 15(3):652, August 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266876`.

Lawton:1973:FNP

[LvNN73] William H. Lawton, John van Ness, and Judith Nelson. [Formulation of a Nonlinear Predictor]: Discussion no. 1. *Technometrics*, 15(1):13–17, February 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266820`. See [NV73b].

Luers:1971:PSL

[LW71] James K. Luers and Robert H. Wenning. Polynomial smoothing: Linear vs cubic. *Technometrics*, 13(3):589–600, August 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267170`.

Lynch:1978:BRB

[Lyn78] John K. Lynch. Book review: *Applications of Statistics to Industrial Experimentation* by C. Daniel. *Technometrics*, 20(2):209–210, May 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268716`.

Muse:1978:CDE

[MA78] H. D. Muse and R. L. Anderson. Comparison of designs to estimate variance components in a two-way classification model. *Technometrics*, 20(2):159–166, May 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268708`. See corrigenda [Ano79e].

MacGregor:1976:OCS

[Mac76] John F. MacGregor. Optimal choice of the sampling interval for discrete process control. *Technometrics*, 18(2):151–160, May 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267518`. See erratum [Ano77h].

Mallows:1973:SC

[Mal73] C. L. Mallows. Some comments on C_P. *Technometrics*, 15 (4):661–675, November 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267380`.

Mallows:1974:FPS

[Mal74] C. L. Mallows. [The Fitting of Power Series, Meaning Polynomials, Illustrated on Band-Spectroscopic Data]: Discussion no. 1. *Technometrics*, 16(2):187–188, May 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267937`. See [BT74].

Mann:1970:EEC

[Man70a] Nancy R. Mann. Estimators and exact confidence bounds for Weibull parameters based on a few ordered observations. *Technometrics*, 12(2):345–361, May 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267239`.

Mantel:1970:WSP

[Man70b] Nathan Mantel. Why stepdown procedures in variable selection. *Technometrics*, 12(3):621–625, August 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267207`.

Mandel:1971:NAV

[Man71a] John Mandel. A new analysis of variance model for non-additive data. *Technometrics*, 13(1):1–18, February 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267072`.

Mann:1971:BLI

[Man71b] Nancy R. Mann. Best linear invariant estimation for Weibull parameters under progressive censoring. *Technometrics*, 13(3):521–533, August 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267165`.

Mann:1971:BRB

[Man71c] W. Robert Mann. Book review: *Green's Functions; Introductory Theory with Applications* by G. F. Roach. *Technometrics*, 13(3):708, August 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267187`.

Mantel:1971:MVS

[Man71d] Nathan Mantel. More on variable selection and an alternative approach. *Technometrics*, 13(2):455–457, May 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266815`.

Mann:1972:DSL

[Man72] Nancy R. Mann. Design of over-stress life-test experiments when failure times have the two-parameter Weibull distribution. *Technometrics*, 14(2):437–451, May 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267434`.

Manson:1973:BRB

[Man73] A. R. Manson. Book review: *Response Surface Methodology* by Raymond H. Myers. *Technometrics*, 15(4):936–938, November 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267405`.

Mantel:1975:PPE

[Man75] Nathan Mantel. Poisson parameter estimation with arbitrary factors of proportionality and arbitrary points of left truncation. *Technometrics*, 17(2):173–176, May 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268348`.

Marquardt:1970:GIR

[Mar70] Donald W. Marquardt. Generalized inverses, ridge regression, biased linear estimation, and nonlinear estimation. *Technometrics*, 12(3):591–612, August 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267205`.

Marcus:1973:SMM

[Mar73] Allan H. Marcus. A stochastic model of microscale air pollution from highway traffic. *Technometrics*, 15(2):353–363, May 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266994`. See erratum [Ano73j].

Marquardt:1974:FPS

[Mar74] Donald W. Marquardt. [The Fitting of Power Series, Meaning Polynomials, Illustrated on Band-Spectroscopic Data]: Discussion no. 2.

Technometrics, 16(2):189–192, May 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267938`. See [BT74].

Marcus:1975:BRB

[Mar75] Allan H. Marcus. Book review: *Systems Analysis and Design Using Network Techniques* by Gary E. Whitehouse. *Technometrics*, 17(2):274–275, May 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268365`.

Margolin:1976:DAF

[Mar76] Barry H. Margolin. Design and analysis of factorial experiments via interactive computing in APL. *Technometrics*, 18(2):135–150, May 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267517`.

Matz:1978:MLP

[Mat78] A. W. Matz. Maximum likelihood parameter estimation for the quartic exponential distribution. *Technometrics*, 20(4):475–484, November 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267648`.

Marcus:1974:SSP

[MB74] Richard Marcus and Saul Blumenthal. A sequential screening procedure. *Technometrics*, 16(2):229–234, May 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267943`.

Mitchell:1978:OFTa

[MB78a] T. J. Mitchell and C. K. Bayne. D-optimal fractions of three-level factorial designs. *Technometrics*, 20(4):369–380, November 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267635`. See discussion [Luc78].

Mitchell:1978:OFTb

[MB78b] T. J. Mitchell and C. K. Bayne. [D-Optimal Fractions of Three-Level Factorial Designs]: Response. *Technometrics*, 20(4):383, November 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267637`.

McKay:1979:CTM

[MBC79] M. D. McKay, R. J. Beckman, and W. J. Conover. A comparison of three methods for selecting values of input variables in the analysis of output from a computer code. *Technometrics*, 21(2):239–245, May 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268522`.

Maynard:1972:APT

[MC72] J. M. Maynard and B. Chow. An approximate Pitman-type "close" estimator for the negative binomial parameter p. *Technometrics*, 14(1):77–88, February 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266920`.

Myers:1973:RST

[MC73] Raymond H. Myers and Walter H. Carter, Jr. Response surface techniques for dual response systems. *Technometrics*, 15(2):301–317, May 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266990`.

McClave:1972:BRB

[McC72] James T. McClave. Book review: *Introduction to Statistics: A Fresh Approach* by G. Noether. *Technometrics*, 14(3):805–806, August 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267310`.

McCabe:1975:CVS

[McC75a] George P. McCabe, Jr. Computations for variable selection in discriminant analysis. *Technometrics*, 17(1):103–109, February 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268007`.

McClave:1975:SA

[McC75b] James McClave. Subset autoregression. *Technometrics*, 17(2):213–220, May 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268353`.

McCabe:1978:ERC

[McC78a] George P. McCabe, Jr. Evaluation of regression coefficient estimates using α-acceptability. *Technometrics*, 20(2):131–139, May 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268704`.

McClave:1978:BRB

[McC78b] James T. McClave. Book review: *Introduction to Statistical Time Series* by Wayne A. Fuller. *Technometrics*, 20(2):211, May 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268718`.

McDonald:1975:DRA

[McD75] Gary C. McDonald. Discussion of: "Ridge Analysis Following a Preliminary Test of the Shrunken Hypothesis". *Technometrics*, 17 (4):443–445, November 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268430`. See [Obe75].

McDonald:1976:DVB

[McD76] Gary C. McDonald. The distribution of a variate based on independent ranges from a uniform population. *Technometrics*, 18(3):343–349, August 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268744`.

McDonald:1979:NSP

[McD79] Gary C. McDonald. Nonparametric selection procedures applied to state traffic fatality rates. *Technometrics*, 21(4):515–523, November 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268291`. See corrigendum [Ano80c].

McKay:1976:SPD

[McK76] Ronald J. McKay. Simultaneous procedures in discriminant analysis involving two groups. *Technometrics*, 18(1):47–53, February 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267915`.

McKay:1979:AVS

[McK79] R. J. McKay. The adequacy of variable subsets in multivariate regression. *Technometrics*, 21(4):475–479, November 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268286`.

McLachlan:1972:ARD

[McL72] G. J. McLachlan. Asymptotic results for discriminant analysis when the initial samples are misclassified. *Technometrics*, 14(2):415–422,

May 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267432`.

McLachlan:1974:EEM

[McL74a] G. J. McLachlan. Estimation of the errors of misclassification on the criterion of asymptotic mean square error. *Technometrics*, 16(2):255–260, May 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267948`.

McLachlan:1974:RTA

[McL74b] G. J. McLachlan. The relationship in terms of asymptotic mean square error between the separate problems of estimating each of the three types of error rate of the linear discriminant function. *Technometrics*, 16(4):569–575, November 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267609`.

Mudholkar:1976:SAN

[MCL76] Govind S. Mudholkar, Yogendra P. Chaubey, and Ching-Chuong Lin. Some approximations for the noncentral-f distribution. *Technometrics*, 18(3):351–358, August 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268745`.

McMillan:1971:TOTb

[McM71] R. G. McMillan. Tests for one or two outliers in normal samples with unknown variance. *Technometrics*, 13(1):87–100, February 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267077`. See correction [MM73].

Maxim:1975:OAT

[MCM75] L. Daniel Maxim, Daniel E. Cullen, and John G. Mardo. Optimal acceptance test plans with grouping. *Technometrics*, 17(3):315–320, August 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268067`.

McMillan:1971:TOTa

[MD71] R. G. McMillan and H. A. David. Tests for one of two outliers in normal samples with known variance. *Technometrics*, 13(1):75–85, February 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267076`.

McDonald:1977:NUT

[MDM77] Lyman L. McDonald, Bruce M. Davis, and George A. Milliken. A nonrandomized unconditional test for comparing two proportions in 2×2 contigency tables. *Technometrics*, 19(2):145–157, May 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268624`.

Merten:1972:BRB

[Mer72] Alan G. Merten. Book review: *Computer Simulation Experiments with Models of Economic Systems* by Thomas H. Naylor. *Technometrics*, 14(2):504–505, May 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267443`.

Mergenthaler:1977:BRB

[Mer77] Mitchell J. Mergenthaler. Book review: *Introduction to Statistics: A Nonparametric Approach* by Gottfried E. Noether. *Technometrics*, 19(3):342–343, August 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267708`.

Mergenthaler:1979:BRB

[Mer79] Mitchell J. Mergenthaler. Book review: *Nonparametrics: Statistical Methods Based on Ranks* by E. L. Lehmann. *Technometrics*, 21(2):272–273, May 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268531`.

Mann:1973:TOW

[MF73] Nancy R. Mann and Kenneth W. Fertig. Tables for obtaining Weibull confidence bounds and tolerance bounds based on best linear invariant estimates of parameters of the extreme-value distribution. *Technometrics*, 15(1):87–101, February 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266827`.

Mann:1975:GFT

[MF75a] Nancy R. Mann and Kenneth W. Fertig. A goodness-of-fit test for the two parameter vs. three parameter Weibull; confidence bounds for threshold. *Technometrics*, 17(2):237–245, May 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268357`.

Mann:1975:SEP

[MF75b] Nancy R. Mann and Kenneth W. Fertig. Simplified efficient point and interval estimators for Weibull parameters. *Technometrics*, 17(3):361–368, August 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268075`.

Mann:1977:EUQ

[MF77] Nancy R. Mann and Kenneth W. Fertig. Efficient unbiased quantile estimators for moderate-size complete samples from extreme-value and Weibull distributions; confidence bounds and tolerance and prediction intervals. *Technometrics*, 19(1):87–93, February 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268260`.

Mann:1974:AOC

[MG74] Nancy R. Mann and Frank E. Grubbs. Approximately optimum confidence bounds for system reliability based on component test data. *Technometrics*, 16(3):335–347, August 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267663`.

McGilchrist:1972:NSS

[MH72] C. A. McGilchrist and S. H. Huxham. A note on some simple time series estimates. *Technometrics*, 14(1):223–227, February 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266934`.

Meeker:1977:AOS

[MH77] William Q. Meeker, Jr. and Gerald J. Hahn. Asymptotically optimum over-stress tests to estimate the survival probability at a condition with a low expected failure probability. *Technometrics*, 19(4):381–399, November 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267877`. See discussion [Law77b].

Meeker:1978:CAT

[MH78] William Q. Meeker, Jr. and Gerald J. Hahn. A comparison of accelerated test plans to estimate the survival probability at a design stress. *Technometrics*, 20(3):245–247, August 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268132`.

Maxim:1977:EDS

[MHC77] L. Daniel Maxim, Arlo D. Hendrickson, and Daniel E. Cullen. Experimental design for sensitivity testing: The Weibull model. *Technometrics*, 19(4):405–412, November 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267879`. See discussion [Ant77].

Moussa-Hamouda:1974:BEC

[MHL74] Effat Moussa-Hamouda and Fred C. Leone. The *O*-blue estimators for complete and censored samples in linear regression. *Technometrics*, 16(3):441–446, August 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267675`.

Moussa-Hamouda:1977:EOL

[MHL77a] Effat Moussa-Hamouda and Fred C. Leone. Efficiency of ordinary least squares estimators from trimmed and Winsorized samples in linear regression. *Technometrics*, 19(3):265–273, August 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267696`.

Moussa-Hamouda:1977:REA

[MHL77b] Effat Moussa-Hamouda and Fred C. Leone. The robustness of efficiency of adjusted trimmed estimators in linear regression. *Technometrics*, 19(1):19–34, February 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268250`.

Mielke:1974:SRT

[Mie74] Paul W. Mielke, Jr. Squared rank test appropriate to weather modification cross-over design. *Technometrics*, 16(1):13–16, February 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267486`.

Mihram:1975:BRB

[Mih75] G. Arthur Mihram. Book review: *Concepts and Methods in Discrete Event Digital Simulation* by George S. Fishman. *Technometrics*, 17(2):272–274, May 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268364`. See corrigenda [Mih77].

Mihram:1977:CBR

[Mih77] G. Arthur Mihram. Corrigenda: Book Review: *Concepts and Methods in Discrete Event Digital Simulation* by George S. Fishman. *Technometrics*, 19(2):222, May 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268644`. See [Mih75].

Miller:1972:BRB

[Mil72a] M. Clinton Miller III. Book review: *Introductory Statistics and Probability* by David W. Blakeslee; William G. Chinn. *Technometrics*, 14(1):236, February 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266939`.

Milton:1972:CEM

[Mil72b] Roy C. Milton. Computer evaluation of the multivariate normal integral. *Technometrics*, 14(4):881–889, November 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267136`.

Mitchell:1974:ACO

[Mit74a] Toby J. Mitchell. An algorithm for the construction of "D-optimal" experimental designs. *Technometrics*, 16(2):203–210, May 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267940`.

Mitchell:1974:CCO

[Mit74b] Toby J. Mitchell. Computer construction of "D-optimal" first-order designs. *Technometrics*, 16(2):211–220, May 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267941`.

Martinelle:1970:CRL

[MK70] Sten Martinelle and R. G. Krutchkoff. On the choice of regression in linear calibration. Comments on a paper by R. G. Krutchkoff. *Technometrics*, 12(1):157–161, February 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267361`.

Myers:1975:GRS

[ML75] Raymond H. Myers and Steve J. Lahoda. A generalization of the response surface mean square error criterion with a specific application to the scope. *Technometrics*, 17(4):481–486, November 1975.

CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268436`.

Moran:1973:TOT

[MM73] M. A. Moran and R. G. McMillan. Tests for one or two outliers in normal samples with unknown variance: A correction. *Technometrics*, 15(3):637–640, August 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266870`. See [McM71].

Meeker:1977:WVC

[MN77] William Q. Meeker, Jr. and Wayne Nelson. Weibull variances and confidence limits by maximum likelihood for singly censored data. *Technometrics*, 19(4):473–476, November 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267888`.

Moeschberger:1972:BRB

[Moe72] M. L. Moeschberger. Book review: *Basic Probability Theory* by Robert B. Ash. *Technometrics*, 14(4):983, November 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267154`.

Moeschberger:1974:LTU

[Moe74] M. L. Moeschberger. Life tests under dependent competing causes of failure. *Technometrics*, 16(1):39–47, February 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267490`.

Miller:1972:LE

[MP72] Alan J. Miller and S. A. Patil. Letters to the Editor. *Technometrics*, 14(2):507–508, May 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267444`.

Meeter:1970:CTM

[MPB70] Duane Meeter, Walter Pirie, and William Blot. A comparison of two model-discrimination criteria. *Technometrics*, 12(3):457–470, August 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267196`.

McLean:1979:SMM

[MPBD79] D. D. McLean, D. J. Pritchard, D. W. Bacon, and J. Downie. Singularities in multiresponse modelling. *Technometrics*, 21(3):291–298, August 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267750`.

Moberg:1978:AME

[MRR78] Thomas F. Moberg, John S. Ramberg, and Ronald H. Randles. An adaptive m-estimator and its application to a selection problem. *Technometrics*, 20(3):255–263, August 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268134`.

McDonald:1973:IRE

[MS73] Gary C. McDonald and Richard C. Schwing. Instabilities of regression estimates relating air pollution to mortality. *Technometrics*, 15(3):463–481, August 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266852`.

Marquardt:1974:TSM

[MS74] Donald W. Marquardt and Ronald D. Snee. Test statistics for mixture models. *Technometrics*, 16(4):533–537, November 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267604`.

Michael:1979:NAT

[MS79] John R. Michael and William R. Schucany. A new approach to testing goodness of fit for censored samples. *Technometrics*, 21(4):435–441, November 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268282`.

Morgan:1972:CRS

[MT72] J. A. Morgan and J. F. Tatar. Calculation of the residual sum of squares for all possible regressions. *Technometrics*, 14(2):317–325, May 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267424`.

Muller:1970:CID

[Mul70] Mervin E. Muller. Computers as an instrument for data analysis. *Technometrics*, 12(2):259–293, May 1970. CODEN TCMTA2. ISSN

0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267233`.

Mayer:1973:BEL

[MW73] Lawrence S. Mayer and Thomas A. Willke. On biased estimation in linear models. *Technometrics*, 15(3):497–508, August 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266855`.

McGilchrist:1975:NDF

[MW75a] C. A. McGilchrist and K. D. Woodyer. Note on a distribution-free CUSUM technique. *Technometrics*, 17(3):321–325, August 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268068`.

Minder:1975:LAL

[MW75b] Ch. E. Minder and J. B. Whitney. A likelihood analysis of the linear calibration problem. *Technometrics*, 17(4):463–471, November 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268433`.

Martz:1978:BMD

[MW78] H. F. Martz, Jr. and M. S. Waterman. A Bayesian model for determining the optimal test stress for a single test unit. *Technometrics*, 20(2):179–185, May 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268711`.

Myers:1974:BRB

[Mye74] Raymond H. Myers. Book review: *Elementary Applied Statistics* by Marvin Lentner. *Technometrics*, 16(1):137, February 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267504`.

Nadas:1970:EDR

[Nád70a] Arthur Nádas. On estimating the distribution of a random vector when only the smallest coordinate is observable. *Technometrics*, 12(4):923–924, November 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267338`.

Nadas:1970:PHF

[Nád70b] Arthur Nádas. On proportional hazard functions. *Technometrics*, 12(2):413–416, May 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267247`.

Nadas:1971:DIM

[Nád71] Arthur Nádas. The distribution of the identified minimum of a normal pair determines the distribution of the pair. *Technometrics*, 13(1):201–202, February 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267088`.

Nadas:1973:BTZ

[Nád73] Arthur Nádas. Best tests for zero drift based on first passage times in Brownian motion. *Technometrics*, 15(1):125–132, February 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266830`.

Naik:1974:TME

[Nai74] Umesh D. Naik. On tests of main effects and interactions in higher-way layouts in the analysis of variance random effects model. *Technometrics*, 16(1):17–25, February 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267487`.

Naszodi:1978:EBC

[Nas78] László J. Naszódi. Elimination of the bias in the course of calibration. *Technometrics*, 20(2):201–205, May 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268714`.

Naylor:1972:BRB

[Nay72] Thomas H. Naylor. Book review: *Computer Simulation of Competitive Market Response* by Arnold E. Amstutz. *Technometrics*, 14(3):803–804, August 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267308`.

Neave:1970:EFR

[Nea70] Henry R. Neave. Extending the frequency range of spectrum estimates by the use of two data recorders. *Technometrics*, 12

(4):877–890, November 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267332`.

Nelson:1972:SLT

[Nel72a] Wayne Nelson. A short life test for comparing a sample with previous accelerated test results. *Technometrics*, 14(1):175–185, February 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266929`.

Nelson:1972:TAH

[Nel72b] Wayne Nelson. Theory and applications of hazard plotting for censored failure data. *Technometrics*, 14(4):945–966, November 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267144`.

Nelson:1973:ARC

[Nel73] Wayne Nelson. Analysis of residuals from censored data. *Technometrics*, 15(4):697–715, November 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267382`.

Nelson:1974:BRB

[Nel74] Judith Zeh Nelson. Book review: *Digital Time Series Analysis* by Robert K. Otnes; Loren Enochson. *Technometrics*, 16(3):479–480, August 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267684`.

Nelson:1975:SRG

[Nel75] David L. Nelson. Some remarks on generalizations of the negative binomial and Poisson distributions. *Technometrics*, 17(1):135–136, February 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268013`.

Ng:1976:NBT

[Ng76] Vee Ming Ng. A note on the best test for discrimination between exponentiality and uniformity. *Technometrics*, 18(2):237–238, May 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267529`.

Nalimov:1970:PUC

[NGM70] V. V. Nalimov, T. I. Golikova, and N. G. Mikeshina. On practical use of the concept of D-optimality. *Technometrics*, 12(4):799–812,

November 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267326`.

Nelson:1972:LER

[NH72] Wayne Nelson and Gerald J. Hahn. Linear estimation of a regression relationship from censored data. Part I: Simple methods and their application. *Technometrics*, 14(2):247–269, May 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267418`. See discussion [Zel72].

Nelson:1973:LER

[NH73] Wayne Nelson and Gerald J. Hahn. Linear estimation of a regression relationship from censored data: Part II best linear unbiased estimation and theory. *Technometrics*, 15(1):133–150, February 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266831`.

Nelson:1976:TOC

[NK76] Wayne Nelson and Thomas J. Kielpinski. Theory for optimum censored accelerated life tests for normal and lognormal life distributions. *Technometrics*, 18(1):105–114, February 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267923`.

Narula:1975:SSC

[NL75] Subhash C. Narula and Franz S. Li. Sample size calculations in exponential life testing. *Technometrics*, 17(2):229–231, May 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268355`.

Nelson:1978:TOA

[NM78] Wayne Nelson and William Q. Meeker. Theory for optimum accelerated censored life tests for Weibull and extreme value distributions. *Technometrics*, 20(2):171–177, May 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268710`.

Nelson:1979:ILN

[NS79] Wayne Nelson and Josef Schmee. Inference for (log) normal life distributions from small singly censored samples and BLUEs. *Technometrics*, 21(1):43–54, February 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268579`.

Nelson:1973:CNP

[NV73a] Judith Zeh Nelson and John W. Van Ness. Choosing a nonlinear predictor. *Technometrics*, 15(2):219–231, May 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266983`.

Nelson:1973:FNP

[NV73b] Judith Zeh Nelson and John W. Van Ness. Formulation of a nonlinear predictor. *Technometrics*, 15(1):1–12, February 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266819`. See discussion [LvNN73].

Narula:1977:PLR

[NW77] Subhash C. Narula and John F. Wellington. Prediction, linear regression and the minimum sum of relative errors. *Technometrics*, 19(2):185–190, May 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268628`. See corrigenda [Ano80b].

Narula:1979:SVL

[NW79] Subhash C. Narula and John F. Wellington. Selection of variables in linear regression using the minimum sum of weighted absolute errors criterion. *Technometrics*, 21(3):299–306, August 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267751`. See corrigenda [Ano80b].

OBrien:1973:PSI

[O'B73] Peter C. O'Brien. A procedure for the sequential interval estimation of the shape parameter of the gamma distribution. *Technometrics*, 15(3):563–569, August 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266862`.

Owen:1976:SMI

[OB76] D. B. Owen and J. W. Boddie. A screening method for increasing acceptable product with some parameters unknown. *Technometrics*, 18(2):195–199, May 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267522`.

Obenchain:1975:RAF

[Obe75] R. L. Obenchain. Ridge analysis following a preliminary test of the shrunken hypothesis. *Technometrics*, 17(4):431–441, November

1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268429`. See discussion [McD75].

Obenchain:1977:CTC

[Obe77] R. L. Obenchain. Classical F-tests and confidence regions for ridge regression. *Technometrics*, 19(4):429–439, November 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267882`.

Odeh:1971:JST

[Ode71] Robert E. Odeh. On Jonckheere's k-sample test against ordered alternatives. *Technometrics*, 13(4):912–918, November 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266972`.

Odoroff:1977:BRB

[Odo77] Charles L. Odoroff. Book review: *Discrete Multivariate Analyses: Theory and Practice* by Yvonne M. M. Bishop; Stephen E. Fienberg; Paul W. Holland; Richard J. Light; Frederick Mosteller. *Technometrics*, 19(1):101–102, February 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268263`. See addendum and corrigendum [Ano77a].

Odoroff:1978:BRB

[Odo78] Charles L. Odoroff. Book review: *The Analysis of Contingency Tables* by B. A. Everitt. *Technometrics*, 20(3):319, August 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268142`. See corrigenda [Ano79f].

OFallon:1973:BRB

[O'F73] W. M. O'Fallon. Book review: *Multivariate Data Analysis* by W. W. Cooley; P. R. Lohnes. *Technometrics*, 15(3):648–650, August 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266874`.

Oxspring:1977:DIM

[OL77] H. H. Oxspring and L. R. LaMotte. The design of incomplete multinomial samples: The nested case. *Technometrics*, 19(1):59–63, February 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268255`.

Owen:1977:SBN

[OlHS77] D. B. Owen and Yueh ling Hsiao Su. Screening based on normal variables. *Technometrics*, 19(1):65–68, February 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268256`.

Ott:1972:DES

[OM72] L. Ott and W. Mendenhall. Designs for estimating the slope of a second order linear model. *Technometrics*, 14(2):341–353, May 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267426`.

Olsson:1975:NMS

[ON75] Donald M. Olsson and Lloyd S. Nelson. The Nelder–Mead simplex procedure for function minimization. *Technometrics*, 17(1):45–51, February 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267998`.

Pape:1972:CS

[Pap72] Elinor S. Pape. A combination of F-statistics. *Technometrics*, 14(1):89–99, February 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266921`.

Park:1970:RCB

[Par70] Se-Hark Park. Regression and correlation in a bivariate distribution with different marginal densities. *Technometrics*, 12(3):687–691, August 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267212`.

Parzen:1972:IAT

[Par72] Emanual Parzen. [The Inverse Autocorrelations of a Time Series and Their Applications]: Discussion no. 2. *Technometrics*, 14(2):295–298, May 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267421`. See [Cle72b].

Park:1978:EDF

[Par78a] Sung H. Park. Experimental designs for fitting segmented polynomial regression models. *Technometrics*, 20(2):151–154, May 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268706`.

Park:1978:SCA

[Par78b] Sung H. Park. Selecting contrasts among parameters in Scheffé's mixture models: Screening components and model reduction. *Technometrics*, 20(3):273–279, August 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268136`.

Passi:1979:LME

[Pas79] Ranjit M. Passi. Linear model estimation with extraneous estimates of a parameter subset, with an application to aircraft tracking. *Technometrics*, 21(4):511–514, November 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268290`.

Patel:1973:QCM

[Pat73] H. I. Patel. Quality control methods for multivariate binomial and Poisson distributions. *Technometrics*, 15(1):103–112, February 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266828`.

Patel:1976:CIU

[Pat76a] Jagdish K. Patel. Confidence intervals using censored data. *Technometrics*, 18(2):221–225, May 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267526`.

Patel:1976:EPT

[Pat76b] Y. C. Patel. Estimation of the parameters of the triple and quadruple stuttering-Poisson distributions. *Technometrics*, 18(1):67–73, February 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267918`.

Pritchard:1977:AHE

[PB77] D. J. Pritchard and D. W. Bacon. Accounting for heteroscedasticity in experimental design. *Technometrics*, 19(2):109–115, May 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268620`.

Pasternack:1976:GSL

[PBT76] B. S. Pasternack, D. E. Bohning, and J. Thomas. Group-sequential leak-testing of sealed radium sources. *Technometrics*, 18(1):59–66,

February 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267917`.

Pritchard:1977:FCH

[PDB77] D. J. Pritchard, J. Downie, and D. W. Bacon. Further consideration of heteroscedasticity in fitting kinetic models. *Technometrics*, 19(3):227–236, August 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267692`.

Pepper:1973:CIN

[Pep73] M. P. G. Pepper. A calibration of instruments with non-random errors. *Technometrics*, 15(3):587–599, August 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266865`.

Pierce:1973:FFB

[Pie73] Donald A. Pierce. Fiducial, frequency, and Bayesian inference on reliability for the two parameter negative exponential distribution. *Technometrics*, 15(2):249–253, May 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266985`.

Patil:1976:TPZ

[PK76] S. A. Patil and J. L. Kovner. On the test and power of zero drift on first passage times in Brownian motion. *Technometrics*, 18(3):341–342, August 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268743`.

Patil:1979:POT

[PK79] S. A. Patil and J. L. Kovner. On the power of an optimum test for the mean of the inverse Gaussian distribution. *Technometrics*, 21(3):379–381, August 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267764`.

Preece:1971:IPM

[Pre71] D. A. Preece. Iterative procedures for missing values in experiments. *Technometrics*, 13(4):743–753, November 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266951`.

Prescott:1975:ATO

[Pre75] P. Prescott. An approximate test for outliers in linear models. *Technometrics*, 17(1):129–132, February 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268011`.

Preston:1977:BRB

[Pre77] D. B. Preston. Book review: *The Analysis of Time Series: Theory and Practice* by C. Chatfield. *Technometrics*, 19(3):343, August 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267709`.

Pfanzagl:1970:ESS

[PS70] J. Pfanzagl and W. Schüler. The efficiency of sequential sampling plans based on prior distributions and costs. *Technometrics*, 12(2):299–310, May 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267235`.

Pettitt:1977:KSG

[PS77] A. N. Pettitt and M. A. Stephens. The Kolmogorov–Smirnov goodness-of-fit statistic with discrete and grouped data. *Technometrics*, 19(2):205–210, May 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268631`.

Pope:1972:USS

[PW72] P. T. Pope and J. T. Webster. The use of an F-statistic in stepwise regression procedures. *Technometrics*, 14(2):327–340, May 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267425`.

Pandit:1977:MAC

[PW77] S. M. Pandit and S. M. Wu. Modeling and analysis of closed-loop systems from operating data. *Technometrics*, 19(4):477–485, November 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267889`.

Quade:1971:BRB

[Qua71] Dana Quade. Book review: *Readings in Statistics* by Audrey Haber; Richard P. Runyon; Pietro Badia. *Technometrics*, 13(2):451, May 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266809`.

Quade:1974:BRBb

[Qua74a] Dana Quade. Book review: *The Statistics Cum Index*, by James L. Dolby and John W. Tukey. *Technometrics*, 16(4):634, November 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267621`.

Quade:1974:BRBa

[Qua74b] Dana Quade. Book review: *The Statistics Cum Index* by James L. Dolby; John W. Tukey. *Technometrics*, 16(4):634, November 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267621`.

Quade:1975:BRB

[Qua75] Dana Quade. Book review: *Sturdy Statistics: Nonparametrics and Order Statistics* by Frederick Mosteller; Robert E. K. Rourke. *Technometrics*, 17(1):140–141, February 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268019`.

Rahim:1976:PTE

[Rah76] M. A. Rahim. Pre-test estimation of simple linear regression model using prior knowledge of one of the parameters. *Technometrics*, 18(4):439–445, November 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268659`.

Ramsey:1973:BRB

[Ram73] James Ramsey. Book review: *Probability and Statistical Analysis* by E. P. Hickman; J. G. Hilton. *Technometrics*, 15(2):422–423, May 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267005`.

Randolph:1970:BRBa

[Ran70a] Paul H. Randolph. Book review: *Linear Programming: Methods and Applications* by Saul I. Gass. *Technometrics*, 12(1):174, February 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267367`.

Randolph:1970:BRBc

[Ran70b] Paul H. Randolph. Book review: *Optimal Statistical Decisions* by Morris H. de Groot. *Technometrics*, 12(3):712–713, August 1970.

CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267221`.

Randolph:1970:BRBb

[Ran70c] Paul H. Randolph. Book review: *Spectral Analysis and Its Applications* by Gwilym M. Jenkins; Donald G. Watts. *Technometrics*, 12(1):174–175, February 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267368`.

Ray:1970:IFT

[Ray70] W. D. Ray. The inverse of a finite Toeplitz matrix. *Technometrics*, 12(1):153–156, February 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267360`.

Rayment:1972:IPM

[Ray72] P. R. Rayment. The identification problem for a mixture of observations from two normal populations. *Technometrics*, 14(4):911–918, November 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267139`.

Read:1971:RBS

[Rea71] R. R. Read. A remark on the Barlow–Scheuer reliability growth estimation scheme. *Technometrics*, 13(1):199–200, February 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267087`. See [BS71].

Regier:1976:SSP

[Reg76] Mary H. Regier. Simplified selection procedures for multivariate normal populations. *Technometrics*, 18(4):483–489, November 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268664`.

Relles:1970:VRT

[Rel70] Daniel A. Relles. Variance reduction techniques for Monte Carlo sampling from Student distributions. *Technometrics*, 12(3):499–515, August 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267199`.

Reynolds:1975:AAR

[Rey75] Marion R. Reynolds, Jr. Approximations to the average run length in cumulative sum control charts. *Technometrics*, 17(1):65–71, February 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268002`.

Robinson:1978:ARL

[RH78] P. B. Robinson and T. Y. Ho. Average run lengths of geometric moving average charts by numerical methods. *Technometrics*, 20(1):85–93, February 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268164`.

Riffenburgh:1971:RTT

[Rif71] Robert H. Riffenburgh. Regime testimation in a time sequence. *Technometrics*, 13(4):795–809, November 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266955`.

Rizvi:1971:SSP

[Riz71] M. Haseeb Rizvi. Some selection problems involving folded normal distribution. *Technometrics*, 13(2):355–369, May 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266797`.

Ralston:1978:DDF

[RJ78] Mary L. Ralston and Robert I. Jennrich. Dud, a derivative-free algorithm for nonlinear least squares. *Technometrics*, 20(1):7–14, February 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268154`.

Rogers:1970:BRBc

[Rog70a] G. S. Rogers. Book review: *Parametric Estimation* by M. T. Wasan. *Technometrics*, 12(3):713–714, August 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267223`.

Rogers:1970:BRBb

[Rog70b] G. S. Rogers. Book review: *Probability and Random Processes for Engineers and Scientists* by A. Bruce Clarke; Ralph L. Disney. *Technometrics*, 12(3):712, August 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267220`.

Rogers:1970:BRBd

[Rog70c] Gerald S. Rogers. Book review: *Foundations of Probability* by Alfred Renyi. *Technometrics*, 12(4):932, November 1970. CODEN

TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267342`.

Rogers:1970:BRBa

[Rog70d] Gerald S. Rogers. Book review: *The Structure of Probability Theory with Applications* by Aram J. Thomasion. *Technometrics*, 12(1):178–179, February 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267372`.

Ronde:1972:BRB

[Ron72] C. A. Ronde. Book review: *Review of Estimation in Linear Models* by T. O. Lewis; P. L. Odell. *Technometrics*, 14(3):804–805, August 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267309`.

Ronning:1977:SSG

[Ron77] Gerd Ronning. A simple scheme for generating multivariate gamma distributions with non-negative covariance matrix. *Technometrics*, 19(2):179–183, May 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268627`.

Roquemore:1976:HDQ

[Roq76] K. G. Roquemore. Hybrid designs for quadratic response surfaces. *Technometrics*, 18(4):419–423, November 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268657`. See errata [Ano77f].

Rosner:1975:BRB

[Ros75a] Bernard Rosner. Book review: *An Introduction to Medical Statistics* by H. O. Lancaster. *Technometrics*, 17(2):275–276, May 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268367`.

Rosner:1975:DMO

[Ros75b] Bernard Rosner. On the detection of many outliers. *Technometrics*, 17(2):221–227, May 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268354`.

Rossi:1975:AWA

[Ros75c] J. A. Dei Rossi. An application of Welch's approximate t-solution of the Behrens–Fisher problem to confidence intervals. *Technomet-*

rics, 17(1):57–60, February 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268000`.

Rosner:1977:PPR

[Ros77] Bernard Rosner. Percentage points for the RST many outlier procedure. *Technometrics*, 19(3):307–312, August 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267700`.

Rousu:1973:WSK

[Rou73] Dwight N. Rousu. Weibull skewness and kurtosis as a function of the shape parameter. *Technometrics*, 15(4):927–930, November 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267402`.

Ran:1976:ARD

[RR76] Arne Ran and Stig I. Rosenlund. Age replacement with discounting for a continuous maintenance cost model. *Technometrics*, 18 (4):459–465, November 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268662`.

Randles:1973:APS

[RRH73] Ronald H. Randles, John S. Ramberg, and Robert V. Hogg. An adaptive procedure for selecting the population with largest location parameter. *Technometrics*, 15(4):769–778, November 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267387`.

Raghunandanan:1971:SEP

[RS71] K. Raghunandanan and R. Srinivasan. Simplified estimation of parameters in a double exponential distribution. *Technometrics*, 13(3):689–691, August 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267181`.

Rao:1972:ENN

[RSO72] J. N. K. Rao, K. Subrahmaniam, and D. B. Owen. Effect of nonnormality on tolerance limits which control percentages in both tails of normal distribution. *Technometrics*, 14(3):571–575, August 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267285`.

Ramberg:1979:PDU

[RTDM79] John S. Ramberg, Pandu R. Tadikamalla, Edward J. Dudewicz, and Edward F. Mykytka. A probability distribution and its uses in fitting data. *Technometrics*, 21(2):201–214, May 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268517`.

Rubin:1976:CRW

[Rub76] Donald B. Rubin. Comparing regressions when some predictor values are missing. *Technometrics*, 18(2):201–205, May 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267523`.

Rustagi:1973:BRB

[Rus73] J. S. Rustagi. Book review: *Statistical Functions* by Buddy L. Myers; Norbert L. Enrick. *Technometrics*, 15(2):423, May 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267006`.

Schafer:1979:EWQ

[SA79] R. E. Schafer and J. E. Angus. Estimation of Weibull quantiles with minimum error in the distribution function. *Technometrics*, 21(3):367–370, August 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267761`.

Sackrowitz:1972:AML

[Sac72] Harold Sackrowitz. Alternative multi-level continuous sampling plans. *Technometrics*, 14(3):645–652, August 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267292`.

Sacker:1975:BRB

[Sac75] Robert J. Sacker. Book review: *Ordinary Differential Equations* by V. I. Arnold. *Technometrics*, 17(3):388–389, August 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268088`.

Sachs:1976:IMN

[Sac76] William H. Sachs. Implicit multifunctional nonlinear regression analysis. *Technometrics*, 18(2):161–173, May 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267519`.

Salsburg:1975:BRB

[Sal75a] David S. Salsburg. Book review: *The Generalized Jackknife Statistic* by Henry L. Gray; William R. Schucany. *Technometrics*, 17(3):383–384, August 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268080`.

Salsburg:1975:EDV

[Sal75b] David S. Salsburg. Estimating differences in variance when comparing two methods of assay. *Technometrics*, 17(3):381–382, August 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268078`.

Samuels:1973:BRB

[Sam73] S. M. Samuels. Book review: *An Introduction to Probability Theory and Its Applications* by William Feller. *Technometrics*, 15(2):420–421, May 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267002`.

Samuels:1978:EST

[Sam78] S. M. Samuels. The exact solution to the two-stage group-testing problem. *Technometrics*, 20(4):497–500, November 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267652`.

Sanathanan:1972:MEM

[San72] Lalitha Sanathanan. Models and estimation methods in visual scanning experiments. *Technometrics*, 14(4):813–829, November 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267131`.

Sanathanan:1973:CSM

[San73] Lalitha Sanathanan. A comparison of some models in visual scanning experiments. *Technometrics*, 15(1):67–78, February 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266825`.

Saperstein:1973:OSW

[Sap73] B. Saperstein. On the occurrence of n successes within N Bernoulli trials. *Technometrics*, 15(4):809–818, November 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267391`.

Sarkar:1971:ELC

[Sar71] Tapas K. Sarkar. An exact lower confidence bound for the reliability of a series system where each component has an exponential time to failure distribution. *Technometrics*, 13(3):535–546, August 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267166`.

Saunders:1973:SAS

[Sau73] Sam C. Saunders. The statistical analysis of stellar X-ray sources. *Technometrics*, 15(2):341–351, May 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266993`.

Saw:1970:LE

[Saw70] John G. Saw. Letter to the Editor. *Technometrics*, 12(4):937, November 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267344`.

Saxena:1972:BRB

[Sax72] K. M. Lal Saxena. Book review: *Introduction to Statistical Theory* by P. G. Hoel; S. C. Port; C. J. Stone. *Technometrics*, 14(4):980–981, November 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267152`.

Shenton:1972:FRM

[SB72a] L. R. Shenton and K. O. Bowman. Further remarks on maximum likelihood estimators for the gamma distribution. *Technometrics*, 14(3):725–733, August 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267300`.

Swindel:1972:REI

[SB72b] Benee F. Swindel and David R. Bower. Rounding errors in the independent variables in a general linear model. *Technometrics*, 14(1):215–218, February 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266932`.

Schucany:1979:LE

[SBV79] William R. Schucany, John E. Boyer, Jr., and H. D. Vinod. Letters to the Editor. *Technometrics*, 21(1):138, February 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268599`.

Srivastava:1971:BOF

[SC71] J. N. Srivastava and D. V. Chopra. Balanced optimal 2^m fractional factorial designs of resolution V, $m \leq 6$. *Technometrics*, 13(2):257–269, May 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266788`.

Scheffe:1970:NSV

[Sch70] Henry Scheffé. A note on separation of variables. *Technometrics*, 12(2):388–393, May 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267243`.

Scheaffer:1971:THM

[Sch71a] R. L. Scheaffer. A test for the homogeneity of a mixture. *Technometrics*, 13(2):325–331, May 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266794`.

Scheaffer:1971:OAR

[Sch71b] Richard L. Scheaffer. Optimum age replacement policies with an increasing cost factor. *Technometrics*, 13(1):139–144, February 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267081`.

Scheaffer:1972:SBS

[Sch72] R. L. Scheaffer. Size-biased sampling. *Technometrics*, 14(3):635–644, August 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267291`.

Schafer:1974:CBM

[Sch74a] Dick Schafer. Confidence bands for the minimum fatigue life. *Technometrics*, 16(1):113–123, February 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267499`.

Schafer:1974:BRB

[Sch74b] Ray E. Schafer. Book review: *A First Course in Probability and Statistics* by Henrick J. Malik; Kenneth Mullen. *Technometrics*, 16(3):481, August 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267686`.

Schlossmacher:1975:BRB

[Sch75] Edward Schlossmacher. Book review: *Modeling and Simulation in Chemical Engineering* by Rodger G. E. Franks. *Technometrics*, 17(1):139, February 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268016`.

Scheaffer:1976:CCM

[Sch76] Richard L. Scheaffer. On the computation of certain minimum variance unbiased estimators. *Technometrics*, 18(4):497–499, November 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268666`.

Sclove:1972:VV

[Scl72] Stanley L. Sclove. (Y vs. X) or ($\log Y$ vs. X)? *Technometrics*, 14(2):391–403, May 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267430`.

Smith:1976:DME

[SCSB76] M. R. Smith, S. Cohn-Sfetcu, and H. A. Buckmaster. Decomposition of multicomponent exponential decays by spectral analytic techniques. *Technometrics*, 18(4):467–482, November 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268663`.

StJohn:1975:ORD

[SD75] R. C. St. John and N. R. Draper. D-optimality for regression designs: A review. *Technometrics*, 17(1):15–23, February 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267995`.

Suich:1977:REA

[SD77] Ronald Suich and George C. Derringer. Is the regression equation adequate?: One criterion. *Technometrics*, 19(2):213–216, May 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268633`.

Steffens:1973:SSR

[SdV73] F. E. Steffens and Rosalie de Villiers. Sample sizes required for two-sided comparisons of two treatments with a control. *Technometrics*, 15(4):915–921, November 1973. CODEN TCMTA2. ISSN

0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267400`.

Seeger:1970:MEV

[See70] Paul Seeger. A method of estimating variance components in unbalanced designs. *Technometrics*, 12(2):207–218, May 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267229`.

Seegrist:1973:LSA

[See73] Donald W. Seegrist. Least squares analysis of experimental design models by augmenting the data with side conditions. *Technometrics*, 15(3):643–645, August 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266872`.

Sen:1970:BRB

[Sen70] A. R. Sen. Book review: *Sampling Theory* by Des Raj. *Technometrics*, 12(2):423–425, May 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267250`.

Sen:1974:BRB

[Sen74] P. K. Sen. Book review: *Monotone Transformations and Limit Laws* by A. A. Balkema. *Technometrics*, 16(4):635, November 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267623`.

Sen:1975:BRB

[Sen75] P. K. Sen. Book review: *Characterization Problems in Mathematical Statistics* by A. M. Kagan; Yu. V. Linnik; C. R. Rao; B. Ramachandran. *Technometrics*, 17(3):385, August 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268082`.

Serfling:1973:BRB

[Ser73] R. J. Serfling. Book review: *Brownian Motion and Diffusion* by David Freedman. *Technometrics*, 15(3):653–654, August 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266879`.

Sarhan:1971:ETE

[SG71] A. E. Sarhan and B. G. Greenberg. The effect of the two extremes in estimating the best linear unbiased estimates (BLUE) of the parameters of the exponential distribution. *Technometrics*, 13(1):113–125, February 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267079`.

Schmee:1979:SMR

[SH79] Josef Schmee and Gerald J. Hahn. A simple method for regression analysis with censored data. *Technometrics*, 21(4):417–432, November 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268280`. See discussion [Hoo79].

Shah:1971:BRB

[Sha71] B. V. Shah. Book review: *Integer and Nonlinear Programming* by J. Abadie. *Technometrics*, 13(4):921–922, November 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266976`.

Shaked:1978:ALT

[Sha78] Moshe Shaked. Accelerated life testing for a class of linear hazard rate type distributions. *Technometrics*, 20(4):457–466, November 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267646`.

Shahani:1979:WWT

[Sha79] A. K. Shahani. Wald–Wolfowitz type sampling plans for continuous production. *Technometrics*, 21(1):21–31, February 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268577`.

Shumway:1971:DSS

[Shu71] Robert H. Shumway. On detecting a signal in N stationarily correlated noise series. *Technometrics*, 13(3):499–519, August 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267164`.

Shukla:1972:PC

[Shu72] G. K. Shukla. On the problem of calibration. *Technometrics*, 14(3):547–553, August 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267283`.

Suich:1970:TST

[SI70] Ronald Suich and Boris Iglewicz. A truncated sequential t-test. *Technometrics*, 12(4):789–798, November 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267325`.

Siddiqui:1975:BRB

[Sid75] M. M. Siddiqui. Book review: *A Guide to Probability Theory and Application* by Cyrus Derman; Leon J. Gleser; Ingram Olkin. *Technometrics*, 17(1):140, February 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268018`.

Sielken:1975:BRB

[Sie75] Robert L. Sielken, Jr. Book review: *Practical Linear Programming with Computer Applications* by Michael O. Locks. *Technometrics*, 17(4):514, November 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268445`.

Simons:1973:BRB

[Sim73] Gordon D. Simons. Book review: *Great Expectations: Theory of Optimal Stopping* by Y. S. Chow; Herbert Robbins; David Siegmund. *Technometrics*, 15(3):652–653, August 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266877`.

Simon:1976:BRB

[Sim76] Gary Simon. Book review: *Basic Concepts in Information Theory and Statistics: Axiomatic Foundations and Applications* by A. M. Mathai; P. N. Rathie. *Technometrics*, 18(4):502, November 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268669`.

Simon:1979:BRB

[Sim79] Gary A. Simon. Book review: *The Analysis of Cross-Tabulated Data* by Graham J. G. Upton. *Technometrics*, 21(4):581–582, November 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268299`.

Singpurwalla:1971:IAL

[Sin71] N. D. Singpurwalla. Inference from accelerated life tests when observations are obtained from censored samples. *Technometrics*, 13(1):161–170, February 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267083`.

Singpurwalla:1972:EVL

[Sin72] N. D. Singpurwalla. Extreme values from a lognormal law with applications to air pollution problems. *Technometrics*, 14(3):703–711, August 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267298`.

Singpurwalla:1973:IAL

[Sin73] Nozer D. Singpurwalla. Inference from accelerated life tests using Arrhenius type re-parameterizations. *Technometrics*, 15(2):289–299, May 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266989`.

Schmitz:1979:OCC

[SLK79] Karl H. Schmitz, Leonard R. Lamberson, and Kailash C. Kapur. Operating characteristic curves for minimum life hypothesis testing for the exponential distribution. *Technometrics*, 21(4):539–547, November 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268294`.

Sylvestre:1974:CRU

[SLM74] E. A. Sylvestre, W. H. Lawton, and M. S. Maggio. Curve resolution using a postulated chemical reaction. *Technometrics*, 16(3):353–368, August 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267665`.

Snee:1974:EVD

[SM74] Ronald D. Snee and Donald W. Marquardt. Extreme vertices designs for linear mixture models. *Technometrics*, 16(3):399–408, August 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267670`.

Snee:1976:SCD

[SM76] Ronald D. Snee and Donald W. Marquardt. Screening concepts and designs for experiments with mixtures. *Technometrics*, 18(1):19–29, February 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267912`.

Sprevak:1979:LE

[SM79] D. Sprevak and D. Meegan. Letter to the Editor. *Technometrics*, 21(3):395, August 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267780`.

Smith:1970:BRB

[Smi70a] Harry Smith, Jr. Book review: *Discrete Distributions* by N. L. Johnson; Samuel Kotz. *Technometrics*, 12(3):713, August 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267222`.

Smith:1970:NE

[Smi70b] Harry Smith, Jr. New Editor. *Technometrics*, 12(4):iii, November 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267318`.

Smith:1976:LE

[Smi76] Patricia L. Smith. Letter to the Editor: "On the distribution of the studentized bivariate range" (Technometrics **17** (1975), no 4, 501–505) by J. E. Gentle, R. L. Kodell and Smith. *Technometrics*, 18(3):365, August 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268754`.

Smith:1977:BRB

[Smi77] Donald R. Smith. Book review: *Statistical Theory of Reliability and Life Testing-Probability Models* by Richard E. Barlow; Frank Proschan. *Technometrics*, 19(2):220, May 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268641`.

Saxena:1977:REM

[SN77] S. K. Saxena and A. K. Nigam. Restricted exploration of mixtures by symmetric-simplex design. *Technometrics*, 19(1):47–52, February 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268253`.

Snell:1970:BRB

[Sne70] James L. Snell. Book review: *Convergence of Probability Measures* by P. Billingsley. *Technometrics*, 12(1):171–172, February 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267364`.

Snee:1971:NUR

[Sne71] Ronald D. Snee. A note on the use of residuals for examining the assumptions of covariance analysis. *Technometrics*, 13(2):430–437, May 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266805`.

Snee:1972:BRB

[Sne72a] Ronald D. Snee. Book review: *Fitting Equations to Data* by C. Daniel; F. S. Wood. *Technometrics*, 14(2):501–502, May 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267439`.

Snee:1972:ARC

[Sne72b] Ronald D. Snee. On the analysis of response curve data. *Technometrics*, 14(1):47–62, February 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266917`.

Snee:1973:TAM

[Sne73] Ronald D. Snee. Techniques for the analysis of mixture data. *Technometrics*, 15(3):517–528, August 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266857`.

Snee:1974:BRB

[Sne74] Ronald D. Snee. Book review: *Biometrika Tables for Statisticians, Volume 2* by E. S. Pearson; H. O. Hartley. *Technometrics*, 16(3):480–481, August 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267685`.

Snee:1975:DUG

[Sne75a] Ronald D. Snee. Discussion of: “The Use of Gradients to Aid in the Interpretation of Mixture Response Surfaces”. *Technometrics*, 17(4):425–430, November 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268428`. See [CO75].

Snee:1975:EDQ

[Sne75b] Ronald D. Snee. Experimental designs for quadratic models in constrained mixture spaces. *Technometrics*, 17(2):149–159, May

1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268345`. See erratum [Ano76e].

Snee:1976:BRB

[Sne76] Ronald D. Snee. Book review: *Analysis of Variance in Complex Experimental Designs* by Harold R. Lindman; W. H. Freeman. *Technometrics*, 18(3):361–362, August 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268747`.

Snee:1977:VRM

[Sne77] Ronald D. Snee. Validation of regression models: Methods and examples. *Technometrics*, 19(4):415–428, November 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267881`.

Simpson:1975:BAM

[SOE75] Joanne Simpson, Anthony Olsen, and Jane C. Eden. A Bayesian analysis of a multiplicative treatment effect in weather modification. *Technometrics*, 17(2):161–166, May 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268346`.

Somerville:1970:TCP

[Som70] Paul N. Somerville. A technique for the computation of percentage points of a statistic. *Technometrics*, 12(2):373–382, May 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267241`.

Sorum:1971:ECP

[Sor71] M. J. Sorum. Estimating the conditional probability of misclassification. *Technometrics*, 13(2):333–343, May 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266795`.

Sorum:1972:EEO

[Sor72a] M. Sorum. Estimating the expected and the optimal probabilities of misclassification. *Technometrics*, 14(4):935–943, November 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267143`.

Sorum:1972:TPM

[Sor72b] M. Sorum. Three probabilities of misclassification. *Technometrics*, 14(2):309–316, May 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267423`.

Sorum:1973:EEP

[Sor73] M. Sorum. Estimating the expected probability of misclassification for a rule based on the linear discriminant function: Univariate normal case. *Technometrics*, 15(2):329–339, May 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266992`.

Shah:1972:SFA

[SP72] D. K. Shah and A. G. Phatak. A simplified form of the ASN for a curtailed sampling plan. *Technometrics*, 14(4):925–929, November 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267141`.

Shah:1974:MLE

[SP74] D. K. Shah and A. G. Phatak. The maximum likelihood estimate of the fraction defective under curtailed multiple sampling plans. *Technometrics*, 16(2):311–315, May 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267953`.

Shah:1977:MLE

[SP77] D. K. Shah and A. G. Phatak. The maximum likelihood estimation under curtailed three class attributes plans. *Technometrics*, 19(2):159–166, May 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268625`.

Specht:1971:SEP

[Spe71] Donald F. Specht. Series estimation of a probability density function. *Technometrics*, 13(2):409–424, May 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266802`.

Sprott:1972:BRB

[Spr72] D. A. Sprott. Book review: *Finite Mathematics with Applications* by A. W. Goodman; J. S. Ratti. *Technometrics*, 14(2):503–504, May

1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267442`.

Sprevak:1976:SPE

[Spr76] D. Sprevak. Statistical properties of estimates of linear models. *Technometrics*, 18(3):283–289, August 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268737`.

Sprott:1978:BRB

[Spr78] D. A. Sprott. Book review: *Urn Models and Their Application: An Approach to Modern Discrete Probability Theory* by Norman L. Johnson; Samuel Kotz. *Technometrics*, 20(4):501, November 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267653`. See corrigenda [Ano79f].

Sprott:1979:BRB

[Spr79] D. A. Sprott. Book review: *Random Allocations* by V. F. Kolchin; B. A. Sevast'yanov; V. P. Chistyakov. *Technometrics*, 21(4):584, November 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268303`.

Schafer:1975:SCR

[SR75] Ray E. Schafer and Herbert C. Rutemiller. Some characteristics of a ranking procedure for population parameters based on chi-square statistics. *Technometrics*, 17(3):327–331, August 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268069`. See note [Bis78].

Scott:1971:NSP

[SS71a] Alastair J. Scott and Michael J. Symons. A note on shortest prediction intervals for log-linear regression. *Technometrics*, 13(4):889–894, November 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266966`.

Smith:1971:IMP

[SS71b] F. Beckley Smith, Jr. and David F. Shanno. An improved Marquardt procedure for nonlinear regressions. *Technometrics*, 13(1):63–74, February 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267075`.

Seshadri:1974:ETZ

[SS74] V. Seshadri and J. J. Shuster. Exact tests for zero drift based on first passage times in Brownian motion. *Technometrics*, 16(1):133–134, February 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267502`.

Sen:1975:SOS

[SS75] Ashish Sen and Muni S. Srivastava. Some one-sided tests for change in level. *Technometrics*, 17(1):61–64, February 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268001`.

Schafer:1976:PCT

[SS76] Ray E. Schafer and T. S. Sheffield. On procedures for comparing two Weibull populations. *Technometrics*, 18(2):231–235, May 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267528`.

Swallow:1978:MVQ

[SS78] William H. Swallow and S. R. Searle. Minimum variance quadratic unbiased estimation (MIVQUE) of variance components. *Technometrics*, 20(3):265–272, August 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268135`.

Schafer:1972:SPR

[ST72] R. E. Schafer and Roy Takenaga. A sequential probability ratio test for availability. *Technometrics*, 14(1):123–135, February 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266924`.

Schmidt:1973:DPC

[ST73] J. W. Schmidt and R. E. Taylor. A dual purpose cost based quality control system. *Technometrics*, 15(1):151–166, February 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266832`.

Stapleton:1970:BRB

[Sta70] James Stapleton. Book review: *Introduction to Probability Theory and Statistical Inference* by Harold J. Larson. *Technometrics*, 12(1):175–176, February 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267369`.

Starks:1979:IST

[Sta79] Thomas H. Starks. An improved sign test for experiments in which neutral responses are possible. *Technometrics*, 21(4):525–530, November 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268292`.

Stewart:1970:NWA

[Ste70] Kirkland B. Stewart. A new weighted average. *Technometrics*, 12(2):247–258, May 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267232`.

Stefansky:1972:ROF

[Ste72a] Wilhelmine Stefansky. Rejecting outliers in factorial designs. *Technometrics*, 14(2):469–479, May 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267436`.

Stewart:1972:SWA

[Ste72b] Kirkland B. Stewart. Situations in which the arithmetic and geometric moving averages are inefficient estimators. *Technometrics*, 14(3):619–633, August 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267290`.

Steinberg:1975:BRB

[Ste75] Joseph Steinberg. Book review: *Statistical Theory of Sample Survey Design and Analysis* by H. S. Konijn. *Technometrics*, 17(3):383, August 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268079`.

Stephens:1978:TEO

[Ste78] M. A. Stephens. On the W test for exponentiality with origin known. *Technometrics*, 20(1):33–35, February 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268158`.

Stone:1976:BRB

[Sto76] Ricardo R. Stone. Book review: *Quantitative Analysis Methods for Substantive Analysts* by H. F. DeFrancesco. *Technometrics*, 18(2):240, May 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267532`.

Strauss:1975:BRB

[Str75] Monty J. Strauss. Book review: *A Short Course in Differential Equations* by Earl D. Rainville; Phillip E. Bedient. *Technometrics*, 17(2): 278, May 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268371`.

Stoline:1979:TSM

[SU79] Michael R. Stoline and Hans K. Ury. Tables of the Studentized maximum modulus distribution and an application to multiple comparisons among means. *Technometrics*, 21(1):87–93, February 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268584`.

Shapiro:1972:AVT

[SW72] S. S. Shapiro and M. B. Wilk. An analysis of variance test for the exponential distribution (complete samples). *Technometrics*, 14(2):355–370, May 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267427`.

Srinivasan:1975:CBW

[SW75] R. Srinivasan and R. M. Wharton. Confidence bands for the Weibull distribution. *Technometrics*, 17(3):375–380, August 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268077`.

Stralkowski:1970:CIE

[SWD70] C. M. Stralkowski, S. M. Wu, and R. E. DeVor. Charts for the interpretation and estimation of the second order autoregressive model. *Technometrics*, 12(3):669–685, August 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267211`.

Stralkowski:1974:CIE

[SWD74] C. Michael Stralkowski, S. M. Wu, and R. E. DeVor. Charts for the interpretation and estimation of the second order moving average and mixed first order autoregressive-moving average models. *Technometrics*, 16(2):275–285, May 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267950`.

Symons:1971:BRB

[Sym71] M. J. Symons. Book review: *An Introduction to Probability, Decision, and Inference* by Irving H. LaValle. *Technometrics*, 13(2):450,

May 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266808`.

Syski:1975:BRB

[Sys75] R. Syski. Book review: *Dynamic Programming and Markov Potential Theory* by A. Hordijk. *Technometrics*, 17(4):514, November 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268444`.

Syski:1976:BRB

[Sys76] R. Syski. Book review: *Markov Chains* by D. Revuz. *Technometrics*, 18(4):501, November 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268668`.

Syski:1978:BRB

[Sys78] R. Syski. Book review: *Innovation Processes* by Y. A. Rozanov. *Technometrics*, 20(4):503–504, November 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267658`.

Tiao:1971:ENN

[TA71] George C. Tiao and M. M. Ali. Effect of non-normality on inferences about variance components. *Technometrics*, 13(3):635–650, August 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267174`.

Thompson:1975:CDE

[TA75] William O. Thompson and Richard L. Anderson. A comparison of designs and estimators for the two-stage nested random model. *Technometrics*, 17(1):37–44, February 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267997`.

Takagi:1972:DUS

[Tak72] Kinji Takagi. On designing unknown-sigma sampling plans based on a wide class of non-normal distributions. *Technometrics*, 14(3):669–678, August 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267295`.

Taneja:1970:BRB

[Tan70] V. S. Taneja. Book review: *Game Theory* by Guillermo Owen. *Technometrics*, 12(1):176, February 1970. CODEN TCMTA2. ISSN 0040-

1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267370`.

Tarone:1976:SCE

[Tar76] Robert E. Tarone. Simultaneous confidence ellipsoids in the general linear model. *Technometrics*, 18(1):85–87, February 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267920`.

Tietjen:1975:DMC

[TB75] Gary L. Tietjen and Richard J. Beckman. On duplicate measurements in the chemical laboratory. *Technometrics*, 17(1):53–56, February 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267999`.

Thoman:1970:MLE

[TBA70] Darrel R. Thoman, Lee J. Bain, and Charles E. Antle. Maximum likelihood estimation, exact confidence intervals for reliability, and tolerance limits in the Weibull distribution. *Technometrics*, 12(2):363–371, May 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267240`.

Trout:1972:TPP

[TC72] J. Richard Trout and Bryant Chow. Table of the percentage points of the trivariate t-distribution with an application to uniform confidence bands. *Technometrics*, 14(4):855–879, November 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267135`.

Trout:1973:UCB

[TC73] J. Richard Trout and Bryant Chow. Uniform confidence bands for a quadratic model. *Technometrics*, 15(3):611–624, August 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266867`.

Thompson:1975:BCL

[TC75a] William E. Thompson and Eugene Y. Chang. Bayes confidence limits for reliability of redundant systems. *Technometrics*, 17(1):89–93, February 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268005`.

Tilquin:1975:BRP

[TC75b] C. Tilquin and R. Cléroux. Block replacement policies with general cost structures. *Technometrics*, 17(3):291–298, August 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268063`.

Tenenbein:1972:DSS

[Ten72] Aaron Tenenbein. A double sampling scheme for estimating from misclassified multinomial data with applications to sampling inspection. *Technometrics*, 14(1):187–202, February 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266930`.

Thompson:1973:SCS

[Tho73] William O. Thompson. Secondary criteria in the selection of minimum bias designs in two variables. *Technometrics*, 15(2):319–328, May 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266991`.

Thompson:1975:NT

[Tho75] R. Thompson. A note on the W transformation. *Technometrics*, 17(4):511–512, November 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268441`.

Tietjen:1979:EST

[TJ79] Gary L. Tietjen and Mark E. Johnson. Exact statistical tolerance limits for sample variances. *Technometrics*, 21(1):107–110, February 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268586`.

Tarter:1972:NTC

[TK72] Michael E. Tarter and Charles J. Kowalski. A new test for and class of transformations to normality. *Technometrics*, 14(3):735–744, August 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267301`.

Tietjen:1972:SGT

[TM72] Gary L. Tietjen and Roger H. Moore. Some Grubbs-type statistics for the detection of several outliers. *Technometrics*, 14(3):583–597, August 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267287`. See [Ano79g].

Tietjen:1973:TSO

[TMB73] G. L. Tietjen, R. H. Moore, and R. J. Beckman. Testing for a single outlier in simple linear regression. *Technometrics*, 15(4):717–721, November 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267383`. See corrigendum [Ano74f].

Tong:1972:BRB

[Ton72] Yung Liang Tong. Book review: *Introduction to the Probability Theory* by P. G. Hoel; S. C. Port; C. J. Stone. *Technometrics*, 14(4):980, November 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267151`.

Tong:1974:NEE

[Ton74] H. Tong. A note on the estimation of Pr$Y < X$ in the exponential case. *Technometrics*, 16(4):625, November 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267617`. See errata [Ton75].

Tong:1975:ENE

[Ton75] H. Tong. Errata: "A Note on the Estimation of Pr$Y < X$ in the Exponential Case" [(*Technometrics* **16** (1974), 625)]. *Technometrics*, 17(3):395, August 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268094`. See [Ton74].

Trout:1979:RII

[TS79] J. Richard Trout and William H. Swallow. Regular and inverse interval estimation of individual observations using uniform confidence bands. *Technometrics*, 21(4):567–574, November 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268297`.

Tsiakals:1978:BRB

[Tsi78] Joseph J. Tsiakals. Book review: *Sampling Inspection and Quality Control* by G. Barrie Wetherill. *Technometrics*, 20(2):212, May 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268721`.

Tukey:1970:SGS

[Tuk70] John W. Tukey. Some graphic and semigraphic displays (abstract). *Technometrics*, 12(1):205, February 1970. CODEN TCMTA2. ISSN

0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267376`.

Tiahrt:1970:MCR

[TW70] Kenneth J. Tiahrt and D. L. Weeks. A method of constrained randomization for 2^n factorials. *Technometrics*, 12(3):471–486, August 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267197`.

Tee:1972:ASD

[TW72a] L. H. Tee and S. M. Wu. An application of stochastic and dynamic models for the control of a papermaking process. *Technometrics*, 14(2):481–496, May 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267437`.

Thomas:1972:LOS

[TW72b] David R. Thomas and Wanda M. Wilson. Linear order statistic estimation for the two-parameter Weibull and extreme-value distributions from Type II progressively censored samples. *Technometrics*, 14(3):679–691, August 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267296`.

Urquhart:1973:BRB

[Urq73] N. Scott Urquhart. Book review: *Generalized Inverse Matrices (With Applications to Statistics)* by R. M. Pringle; A. A. Rayner. *Technometrics*, 15(2):423–424, May 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267007`.

Ury:1972:DFC

[Ury72] Hans K. Ury. On distribution-free confidence bounds for PrY ¡ X. *Technometrics*, 14(3):577–581, August 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267286`.

Ury:1976:CFP

[Ury76] Hans K. Ury. A comparison of four procedures for multiple comparisons among means (pairwise contrasts) for arbitrary sample sizes. *Technometrics*, 18(1):89–97, February 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267921`.

Varde:1970:ERT

[Var70] S. D. Varde. Estimation of reliability of a two exponential component series system. *Technometrics*, 12(4):867–875, November 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267331`.

vanderVaart:1975:BRB

[vdV75] H. R. van der Vaart. Book review: *Mathematics for the Biological Sciences* by Stanley I. Grossman; James E. Turner. *Technometrics*, 17(3):387–388, August 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268087`.

Venetis:1970:IYW

[Ven70] C. Venetis. Intra-year water storage. *Technometrics*, 12(4):741–749, November 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267321`.

Vinod:1976:SEM

[Vin76] H. D. Vinod. Simulation and extension of a minimum mean squared error estimator in comparison with Stein's. *Technometrics*, 18 (4):491–496, November 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268665`.

Vinod:1976:LE

[VK76] H. D. Vinod and R. W. Kennard. Letters to the Editor. *Technometrics*, 18(4):504–505, November 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268673`.

Vance:1979:CMR

[VM79] Lonnie C. Vance and Gary C. McDonald. A class of multiple run sampling plans. *Technometrics*, 21(2):141–146, May 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268511`.

vanNess:1979:EDD

[vN79] John van Ness. On the effects of dimension in discriminant analysis for unequal covariance populations. *Technometrics*, 21(1):119–127, February 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268588`.

vanNess:1976:EDD

[vNS76] John W. van Ness and Cary Simpson. On the effects of dimension in discriminant analysis. *Technometrics*, 18(2):175–187, May 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267520`.

Wang:1971:IMT

[Wan71] Peter C. C. Wang. An inequality on the mean time of faultless operation of a parallel system I. *Technometrics*, 13(4):904–909, November 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266970`.

Watts:1970:QMP

[Wat70a] D. G. Watts. Query 2: [missing Plackett and Burman design with $n = 92$ runs]. *Technometrics*, 12(2):418–419, May 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267249`.

Watts:1970:PTS

[Wat70b] Donald G. Watts. A program for training statistical consultants. *Technometrics*, 12(4):737–740, November 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267320`.

Watson:1973:BRB

[Wat73] G. S. Watson. Book review: *Statistics of Directional Data* by K. V. Mardia. *Technometrics*, 15(4):935–936, November 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267404`.

Waterman:1974:RLS

[Wat74] M. S. Waterman. A restricted least squares problem. *Technometrics*, 16(1):135–136, February 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267503`.

Wilson:1971:MSP

[WB71] Edwin B. Wilson and A. R. Burgess. Multiple sampling plans viewed as finite Markov chains. *Technometrics*, 13(2):371–383, May 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266798`.

Watts:1974:UHT

[WB74] Donald G. Watts and David W. Bacon. Using an hyperbola as a transition model to fit two-regime straight-line data. *Technometrics*, 16(3):369–373, August 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267666`. See errata [Ano75f].

Weisberg:1975:AAV

[WB75] Sanford Weisberg and Christopher Bingham. An approximate analysis of variance test for non-normality suitable for machine calculation. *Technometrics*, 17(1):133–134, February 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268012`.

Weiler:1970:VWM

[WC70] H. Weiler and D. Culpin. On the variance of weighted means. *Technometrics*, 12(4):757–773, November 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267323`.

Wichern:1978:CRE

[WC78] Dean W. Wichern and Gilbert A. Churchill. A comparison of ridge estimators. *Technometrics*, 20(3):301–311, August 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268139`.

Weinman:1973:TET

[WDFH73] David G. Weinman, Gene Dugger, W. E. Franck, and John E. Hewett. On a test for the equality of two exponential distributions. *Technometrics*, 15(1):177–182, February 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266834`.

Webb:1971:SIF

[Web71] Steve R. Webb. Small incomplete factorial experiment designs for two- and three-level factors. *Technometrics*, 13(2):243–256, May 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266787`. See corrigenda [Ano73f].

Webster:1973:BRB

[Web73] J. T. Webster. Book review: *Engineering Statistics* by Albert H. Bowker; Gerald J. Lieberman. *Technometrics*, 15(4):939–940,

November 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267407`.

Wegman:1972:NPD

[Weg72] Edward J. Wegman. Nonparametric probability density estimation: I. A summary of available methods. *Technometrics*, 14(3):533–546, August 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267282`.

Wegman:1974:SRN

[Weg74] Edward J. Wegman. Some results on non stationary first order autoregression. *Technometrics*, 16(2):321–322, May 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267955`.

Wegman:1976:BRB

[Weg76] Edward J. Wegman. Book review: *Time Series Data Analysis and Theory* by David R. Brillinger. *Technometrics*, 18(1):121, February 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267927`.

Weiss:1971:BRB

[Wei71] Lionel Weiss. Book review: *Probability and Statistics* by L. Daniel Massey. *Technometrics*, 13(4):921, November 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266975`.

Westlake:1971:OSV

[Wes71] W. J. Westlake. A one-sided version of the Tukey–Duckworth test. *Technometrics*, 13(4):901–903, November 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266969`.

Weinrich:1978:BSR

[WG78] Martin C. Weinrich and Alan J. Gross. The Barlow–Scheuer reliability growth model from a Bayesian viewpoint. *Technometrics*, 20(3):249–254, August 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268133`.

White:1979:LRR

[WG79] J. W. White and R. F. Gunst. Latent root regression: Large sample analysis. *Technometrics*, 21(4):481–488, November 1979. CODEN

TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268287`. See corrigenda [Ano80b].

Webster:1974:LRR

[WGM74] J. T. Webster, R. F. Gunst, and R. L. Mason. Latent root regression analysis. *Technometrics*, 16(4):513–522, November 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267602`.

Wheeler:1970:VEV

[Whe70] Donald J. Wheeler. The variance of an estimator in variables sampling. *Technometrics*, 12(4):751–755, November 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267322`.

Wheeler:1974:PP

[Whe74] Robert E. Wheeler. Portable power. *Technometrics*, 16(2):193–201, May 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267939`.

Wheeler:1975:VPP

[Whe75] Robert E. Wheeler. The validity of portable power. *Technometrics*, 17(2):177–179, May 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268349`.

Whitehouse:1970:GUT

[Whi70] Gary E. Whitehouse. GERT, a useful technique for analyzing reliability problems. *Technometrics*, 12(1):33–48, February 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267349`.

Wichern:1972:EEE

[Wic72] Dean W. Wichern. The effect of estimation error on a geometric moving average. *Technometrics*, 14(3):745–755, August 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267302`.

Wiggins:1976:DFS

[Wig76] Alvin D. Wiggins. Discussion of: "Fitting Systems of Linear Differential Equations Using Computer Generated Exact Derivatives". *Technometrics*, 18(4):393–399, November 1976. CODEN TCMTA2.

ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268654`. See [JB76].

Williams:1970:BRB

[Wil70] James S. Williams. Book review: *The Structure of Inference* by D. A. S. Fraser. *Technometrics*, 12(3):709–711, August 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267219`. See comment [FW72].

Wilcox:1979:BRB

[Wil79a] Rand R. Wilcox. Book review: *The Statistical Implications of Pre-Test and Stein-Rule Estimators in Econometrics* by George G. Judge; M. E. Bock. *Technometrics*, 21(3):389–390, August 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267769`.

Wilkinson:1979:NE

[Wil79b] John W. Wilkinson. New Editor. *Technometrics*, 21(4):iii, November 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268277`.

Winkler:1971:BRB

[Win71] R. L. Winkler. Book review: *Statistical Analysis for Decision Making* by Morris Hamburg. *Technometrics*, 13(3):705–706, August 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267185`.

Wiorkowski:1970:EPV

[Wio70] John J. Wiorkowski. Estimation of the proportion of the variance explained by regression, when the number of parameters in the model may depend on the sample size. *Technometrics*, 12(4):915–919, November 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267336`. See comment [Cro71].

Wani:1971:PER

[WK71] J. K. Wani and D. G. Kabe. Point estimation of reliability of a system comprised of k elements from the same gamma model. *Technometrics*, 13(4):859–864, November 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266961`.

Woodward:1977:MVU

[WK77] Wayne A. Woodward and Gary D. Kelley. Minimum variance unbiased estimation of $P[Y < X]$ in the normal case. *Technometrics*, 19(1):95–98, February 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268261`.

Wold:1974:SFD

[Wol74] Svante Wold. Spline functions in data analysis. *Technometrics*, 16(1):1–11, February 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267485`.

Wolfe:1977:DFT

[Wol77a] Douglas A. Wolfe. A distribution-free test for related correlation coefficients. *Technometrics*, 19(4):507–509, November 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267893`. See errata [Ano78e].

Wolfe:1977:TST

[Wol77b] Douglas A. Wolfe. Two-stage two-sample median test. *Technometrics*, 19(4):495–501, November 1977. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267891`.

Wold:1978:CVE

[Wol78] Svante Wold. Cross-validatory estimation of the number of components in factor and principal components models. *Technometrics*, 20(4):397–405, November 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267639`.

Wood:1973:UIE

[Woo73] Fred S. Wood. The use of individual effects and residuals in fitting equations to data. *Technometrics*, 15(4):677–695, November 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267381`.

Woolson:1974:BRBb

[Woo74a] Robert F. Woolson. Book review: *Concepts of Statistical Inference* by William C. Guenther. *Technometrics*, 16(4):635–636, November 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267625`.

Woolson:1974:BRBa

[Woo74b] Robert F. Woolson. Book review: *Introduction to Probability and Statistics* by Henry L. Alder; Edward B. Roessler. *Technometrics*, 16(1):142, February 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267513`.

Woods:1975:BRB

[Woo75] Raymond F. Woods. Book review: *Quality Control* by Richard C. Vaughn. *Technometrics*, 17(4):513, November 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268443`.

Woodruff:1975:DEC

[WRLI75] H. B. Woodruff, G. L. Ritter, S. R. Lowry, and T. L. Isenhour. Density estimations and the characterization of binary infrared spectra. *Technometrics*, 17(4):455–462, November 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268432`.

Wu:1973:LE

[Wu73] S. M. Wu. Letter to the Editor. *Technometrics*, 15(1):207–208, February 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266847`.

Willan:1978:MMM

[WW78] Andrew R. Willan and Donald G. Watts. Meaningful multicollinearity measures. *Technometrics*, 20(4):407–412, November 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267640`.

Whitmore:1978:NLT

[WY78] G. A. Whitmore and M. Yalovsky. A normalizing logarithmic transformation for inverse Gaussian random variables. *Technometrics*, 20(2):207–208, May 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268715`.

Yahil:1976:SCB

[YB76] Amos Yahil and Morton B. Brown. On separating clusters from background. *Technometrics*, 18(1):55–58, February 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267916`.

Youngs:1971:SRR

[YC71] Edward A. Youngs and Elliot M. Cramer. Some results relevant to choice of sum and sum-of-product algorithms. *Technometrics*, 13(3):657–665, August 1971. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267176`.

Yochmowitz:1978:STM

[YC78] Michael G. Yochmowitz and Richard G. Cornell. Stepwise tests for multiplicative components of interaction. *Technometrics*, 20(1):79–84, February 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268163`.

Yale:1976:WR

[YF76] Coralee Yale and Alan B. Forsythe. Winsorized regression. *Technometrics*, 18(3):291–300, August 1976. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268738`.

Yuen:1974:PPD

[YM74] Karen K. Yuen and V. K. Murthy. Percentage points of the distribution of the t statistic when the parent is Student's t. *Technometrics*, 16(4):495–497, November 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267600`.

Youden:1972:EV

[You72a] W. J. Youden. Enduring values. *Technometrics*, 14(1):1–11, February 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266913`.

Youden:1972:RE

[You72b] W. J. Youden. Randomization and experimentation. *Technometrics*, 14(1):13–22, February 1972. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266914`.

Yuen:1978:QWS

[Yue78] C. K. Yuen. Quadratic windowing in the segment averaging method for power spectrum computation. *Technometrics*, 20(2):195–200, May 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268713`.

Zirphile:1975:LE

[ZA75] J. Zirphile and Etudes Avancées. Letter to the Editor. *Technometrics*, 17(1):145, February 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268023`.

Zacks:1970:BDS

[Zac70] S. Zacks. Bayesian design of single and double stratified sampling for estimating proportion in finite population. *Technometrics*, 12(1):119–130, February 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267356`.

Zacks:1974:BRB

[Zac74] Shelley Zacks. Book review: *Probability Distributions: An Introduction to Probability Theory with Applications* by Chris P. Tsokos. *Technometrics*, 16(4):634–635, November 1974. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267622`.

Zahn:1975:ESH

[Zah75a] Douglas A. Zahn. An empirical study of the half-normal plot. *Technometrics*, 17(2):201–211, May 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268352`.

Zahn:1975:MRC

[Zah75b] Douglas A. Zahn. Modifications of and revised critical values for the half-normal plot. *Technometrics*, 17(2):189–200, May 1975. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268351`.

Zeigler:1973:ECV

[Zei73] R. K. Zeigler. Estimators of coefficient of variation using k samples. *Technometrics*, 15(2):409–414, May 1973. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1266999`.

Zelen:1972:LER

[Zel72] Marvin Zelen. [Linear Estimation of a Regression Relationship from Censored Data. Part I: Simple Methods and Their Application]: Discussion no. 1. *Technometrics*, 14(2):271–276, May 1972. CODEN

TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267419`. See [NH72].

Ziegel:1978:BRB

[Zie78] Eric R. Ziegel. Book review: *Introduction to Statistics and Probability* by Edward J. Dudewicz. *Technometrics*, 20(2):213–214, May 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268723`.

Zizes:1978:BRB

[Ziz78] P. A. Zizes. Book review: *Manual of Product Assurance Films on Reliability Engineering and Management, Reliability Testing, Maintainability, and Quality Control* by Dimitri Kececioglu. *Technometrics*, 20(1):105, February 1978. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268171`.

Zidek:1979:SEA

[ZNL79] James V. Zidek, Francis P. D. Navin, and Richard Lockhart. Statistics of extremes: An alternate method with application to bridge design codes. *Technometrics*, 21(2):185–191, May 1979. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1268515`.

Zyskind:1970:BRB

[Zys70] George Zyskind. Book review: *Introduction to Matrices with Applications in Statistics* by Franklin A. Graybill. *Technometrics*, 12(4):929–931, November 1970. CODEN TCMTA2. ISSN 0040-1706 (print), 1537-2723 (electronic). URL `http://www.jstor.org/stable/1267341`.